

Cardiac Rhythm Disease Management

Product Performance Report

Important Patient Management Information for Physicians







2011

Second Edition – Issue 65

A Message from the Vice President

Dear Customer,

At Medtronic, product quality and reliability have been and will continue to be a priority. For over 28 years, Medtronic has compiled and produced product performance reports with one primary goal, to provide you with the product information you need to best care for your patients.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continually explore new ways to expand, improve, and learn from our product performance systems and measures.

Our quality goals cannot be reached alone. We welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback comments and any questions.

Your participation and assistance in returning explanted products are also critical. Returned products are tested and evaluated so that we can fully measure the performance of our devices. Please refer to the instructions on the next page for assistance in returning products to the Medtronic CRDM Returned Product Analysis Laboratory.

As we constantly strive to exceed your expectations, we thank you for your dedication to improving and saving the lives of those suffering from cardiac rhythm disorders.

With appreciation and warm regards,

Tim Samsel

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

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For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

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ProductPerformance

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Introduction

All product performance reports are not created equal. For 28 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), cardiac resynchronization therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly, Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted products from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab. For information on how to contact the Lab, refer to the Contact Information page of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see the Contact Information page of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for individual devices and leads in the *population sample*. The population sample for

CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined in the study protocol.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads
- implanted in patients who are lost to follow-up

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles Method for Estimating CRT, ICD, and IPG Device Performance (page 6) and Method for Estimating Lead Performance (page 81).

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with a yellow X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

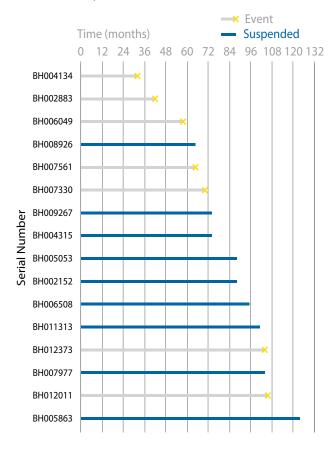


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that seven of the 16 devices suffered events, and nine are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized, as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For the interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices underestimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The Interval Survival Probability (F) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the Proportion with Event (E). This number can be interpreted as the estimated rate at which events do not occur in the time interval.

The Cumulative Survival Probabilities (G) from the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

Table 1 Life Table for Figure 1

	Α	В	C	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Definitions:

A	B	C	D	E	F	G
Number	Number	Number	Effective	Proportion	Interval	Cumulative
Number Entered Number of devices active at the start of the interval	Number Suspended Number of devices removed from service for reasons other than an event	Number of Events Number of units removed from service due to an event	Effective Sample Size Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered.	Proportion with Event Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size.	Interval Survival Probability The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event.	

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the Interval Survival Probability (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.

Cumulative Survival Probability (%) 100 90 80 70 40 30 12 48 60 96 108 0 24 36 72 84 120 132 Time (months) 96 24 48 60 72 84 108 120 0 12 36 132 93.8 87.5 81.3 68.3 68.3 68.3 34.1 34.1 100 100 100 34.1 16 16 15 12.5 0.5 16 16 **Effective Sample Size**

Figure 2 Survival Curve for Data Given in Table 1

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product Performance Report

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using 1-month intervals (for CRT, ICD, and IPG devices) or 3-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.¹

¹ Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics).

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and US returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) is functioning normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Definition of Malfunction

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function, and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion - The condition when:

- (a) a device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) a device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Expanded Malfunction Detail

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component – Findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – Findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery – Findings linked to the battery and its components

Software/Firmware – Findings linked to software or firmware function

Possible Early Battery Depletion – Findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – Findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed evenly within the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first 5 years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more malfunctions or battery depletions. This occurs because, even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates.

Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and **Population Samples Are Defined**

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in Medtronic's Device And Registrant Tracking (DART) system.

The DART system is an important element of Medtronic's Quality System. The DART system is designed to meet or exceed the US FDA's device tracking requirements set forth by the Safe Medical Devices Act. In the United States, over 98% of Medtronic's CRT, ICD, and IPG implants become registered in the DART

continued

Because pacemakers do not cure the patient's underlying health problem, when a pacemaker stops functioning (due to either normal battery replacement or malfunction) it is replaced with a new pacemaker. Therefore, the replacement recorded in the DART system is a good indication that the previous pacemaker experienced either battery depletion or malfunction. The fraction of replaced devices that are subsequently returned can be used to estimate the correction factor for the under reporting of the combination of battery depletion and malfunction.

Note that devices of patients who have expired do not factor into the calculation of the correction. It is possible some proportion of these device experienced battery depletion or malfunction. Since these are not counted into the correction factor based on the return rate of replaced devices, a correction factor based only on the return rate of replaced devices may still underestimate the true rate of battery depletion and malfunction. However, devices that are replaced because the patient is receiving a system upgrade or are removed because the patient no longer needs it (e.g., due to heart transplant) do contribute to the calculation of the correction factor and therefore impart an opposite bias.

Also note that this method of calculating the correction factor cannot distinguish between devices that are removed due to malfunction and those due to normal battery depletion. It might seem intuitive that devices that unexpectedly malfunction should be much more likely to be returned to the manufacturer than a device with ordinary normal battery depletion. But this has not been conclusively demonstrated. Therefore, this method only provides a correction factor reflecting the combination of battery depletion and malfunction.

No adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to non-device related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, Medtronic addresses this underreporting in two ways. Regular updates obtained from the Social Security Administration about deceased persons is used to update Medtronic's DART data about patients who have died but whose deaths had not been reported to Medtronic. In addition, the patient mortality rate derived from our DART system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in DART is significantly different from published rates, an adjustment is applied to correct the difference.

24,000

Effective Sample Size

18,000

13,000

2,400

7289 InSync II Marquis

Product Characteristics

89	inSync II I	viarquis							Product Ch	aracteri	stics	
US Ma	irket Release		Aug-03	Malfund	tions (US)			304	NBD Code			VVED
Regist	tered US Implan	ts	28,000	Therap	y Function N	lot Compromised	d	272	Serial Number	Prefix		PRJ
Estima	ated Active US Ir	mplants	1,500	Ele	ctrical Comp	onent		25	Max Delivered	Energy		30 J
Norm	al Battery Deple	tions (US)	6,538	Sof	ftware/Firmw	are are		1	Estimated Lon	gevity		See page 2
	ories: See page			Pos	ssible Early Ba	attery Depletion		246				
Prema	ature Battery De	pletion Due to l	Battery Short	Therap	y Function C	Compromised		32				
				Bat	tery (9 malfui	nctions related to a	advisory)	10				
				Ele	ctrical Compo	onent		22				
100							1					
90 80 70 60 50 40 30)											
80)											
70)											
60)											
50)											
40												
30					<u> </u>							
20					1							
10					1							
0												
	0	1	2 3		4	5	6	7	8		9	10
	Years Afte	r Implant	E xc	luding Norr	mal Battery	/ Depletion	Ir	ncludii	ng Normal Ba	ttery De	pletion	
		1 yr	2 yr	3 yr	4 yr	at 50 mo						
%		99.9	99.7	98.8	98.0	97.9						
%		99.6	96.7	83.1	23.8	0.4						
/(′ <u> </u>	22.0	20.7	00.1	25.5	- · · ·						

600

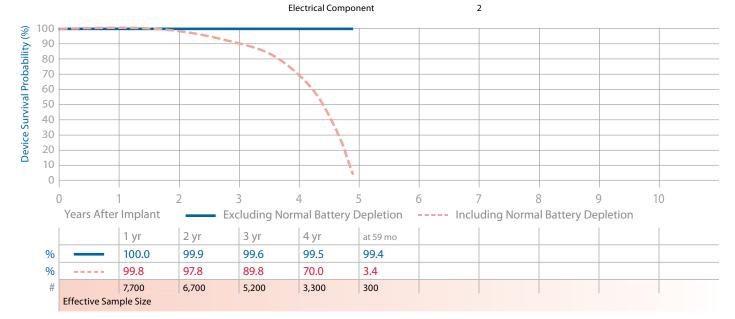


7297 InSync Sentry

US Market Release	Nov-04	Malfunctions (US)	39
Registered US Implants	9,000	Therapy Function Not Compromised	37
Estimated Active US Implants	700	Battery	1
Normal Battery Depletions (US)	2,479	Electrical Component	10
Advisories	None	Software/Firmware	1
		Possible Early Battery Depletion	25
		Therapy Function Compromised	2

Product Characteristics

NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 22



7299 InSync Sentry

US Market Release	Apr-05	Malfun	ctions (US)		162	NBD Code	VVED
Registered US Implants	31,000	Thera	y Function No	ot Compromised	152	Serial Number Prefix	PRK
Estimated Active US Implants	4,700	Ele	ectrical Compo	nent	16	Max Delivered Energy	35 J
Normal Battery Depletions (US)	7,907	So	ftware/Firmwa	re	2	Estimated Longevity	See page 2
Advisories	None	Po	ssible Early Bat	tery Depletion	133		
		Ot	her		1		
		Thera	py Function Co	mpromised	10		
		Ele	ectrical Compo	nent	10		
100							
90 80 70 60 50 40 30 20							
80							
70 60							
50							
40							
30			\				
20			1				
10			1				
0			1				
0 1	2 3		4	5 6	7	8 9	10
Years After Implant	Exclu	ıding Norr	nal Battery [Depletion	Includin	g Normal Battery Depletic	on
1 yr	2 yr	3 yr	4 yr	at 58 mo			
% 100.0	99.9	99.7	99.3	99.1			
% 99.8	97.9	90.2	66.4	1.5			
# 27,000	24,000	19,000	11,000	700			
Effective Sample Size							

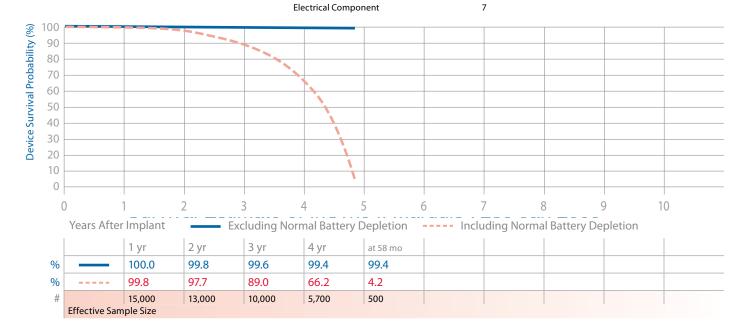


7303 InSync Maximo

	•			
U	S Market Release	Jun-04	Malfunctions (US)	73
R	egistered US Implants	17,000	Therapy Function Not Compromised	66
E	stimated Active US Implants	1,200	Electrical Component	15
N	ormal Battery Depletions (US)	4,713	Software/Firmware	2
Α	dvisories	None	Possible Early Battery Depletion	49
			Therapy Function Compromised	7

Product Characteristics

NBD Code	VVED
Serial Number Prefix	PRL
Max Delivered Energy	35 J
Estimated Longevity	See page 22



7304 InSync Maximo

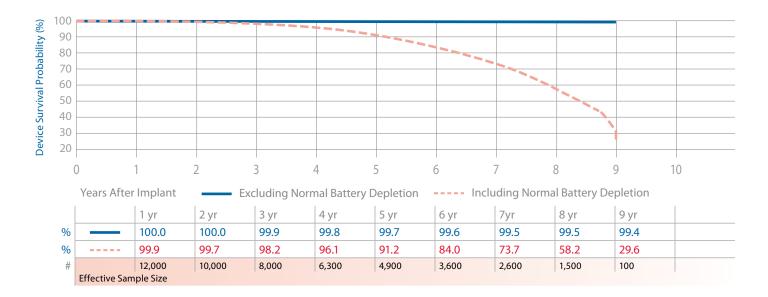
US Market Release	Apr-05	Malfunctions (US)		92	NBD Code	VVED
Registered US Implants	19,000	Therapy Function I	Not Compromised	89	Serial Number Prefix	PRL
Estimated Active US Implants	4,000	Battery		1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	3,975	Electrical Comp	onent	12	Estimated Longevity	See page 22
Advisories	None	Possible Early B	attery Depletion	76		·
		Therapy Function (Compromised	3		
		Electrical Comp	onent	3		
100						
80						
70						
60						
50						
40		\				
30		,				
20		1				
10		<u> </u>				
0		1	<u> </u>			
0 1	2 3	4	5 6	7	8 9	10
Years After Implant	Exclu	ding Normal Battery	Depletion	Includin	g Normal Battery Depleti	on
1 yr	2 yr 3	yr 4 yr	at 58 mo			
% 100.0		9.6 99.2	99.2			
% 99.8		0.9 69.4	4.1			
# 17,000		,000 5,800	400			
Effective Sample Size						



8040 InSync

US Market Release	Aug-01	Malfunctions (US)	32	NBG Code	DDDR
Registered US Implants	15,000	Therapy Function Not Compromised	8	Serial Number Prefix	PIN
Estimated Active US Implants	1,900	Electrical Component	4	Estimated Longevity	See page 2
Normal Battery Depletions (US)	1,103	Possible Early Battery Depletion	3		
Advisories	None	Other	1		
		Therapy Function Compromised	24		

Electrical Interconnect



8042 InSync III

US Market Release Feb-03 Registered US Implants 39,000 **Estimated Active US Implants** 18,000 Normal Battery Depletions (US) 963 Advisories None

Malfunctions (US) 18 **Therapy Function Not Compromised** 10 **Electrical Component** 5



Electrical Component Electrical Interconnect

Product Characteristics

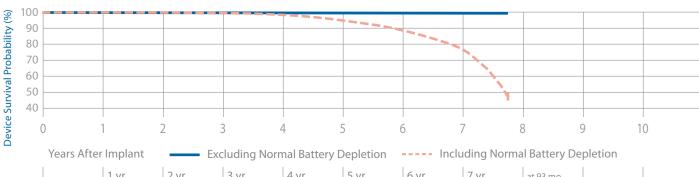
Product Characteristics

24

3

5

3	NBG Code	DDDR
)	Serial Number Prefix	PKF
5	Estimated Longevity	See page 23
2		



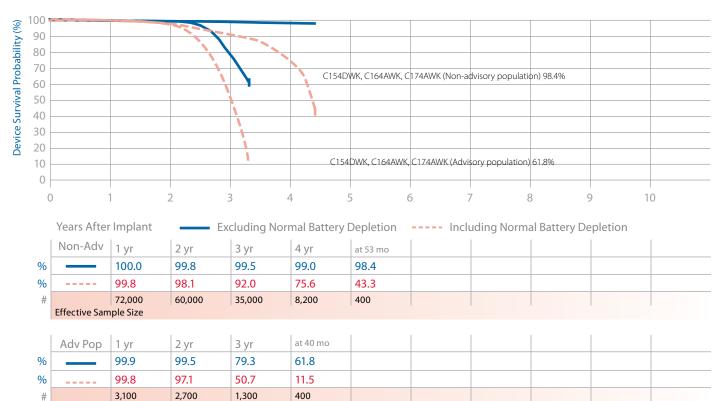
	rears Arter	impiant	EXC	cluding Norr	nai Battery L	Depletion	Incit	ading Norma	al Battery Depletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 93 mo	
%		100.0	100.0	100.0	99.9	99.9	99.9	99.8	99.8	
%		99.9	99.8	99.3	97.6	94.6	88.4	76.0	47.6	
#		31,000	23,000	16,000	12,000	7,600	4,400	2,000	200	
	Effective Sam	ple Size								



C154DWK, C164AWK, C174AWK Concerto

Product Characteristics

	(N)	(A)		(N)	(A)		
US Market Release	May-06	May-06	Malfunctions (US)	429	1,286	NBD Code	DDED
Registered US Implants	81,000	3,500	Therapy Function Not Compromised	398	1,272	Serial Number Prefix	PVU, PVT, PVR
Estimated Active US Implants	49,000	300	Electrical Component	24	1,269	Max Delivered Energy	35 J
Normal Battery Depletions (US)	3,893	222	Electrical Interconnect	1		Estimated Longevity	See page 22
Advisories: See page 148 – 2009			Software/Firmware	1			
Potential Reduced Device Longevity			Possible Early Battery Depletion	369	3		
_			Other	3			
Performance Note: See page 159 – Anomalies in MOSFET Integrated			Therapy Function Compromised	31	14	(N) = Non-advisory populatio	n
Circuit Technology			Electrical Component	29	13	(A) = Advisory population	
			Electrical Interconnect	2	1		



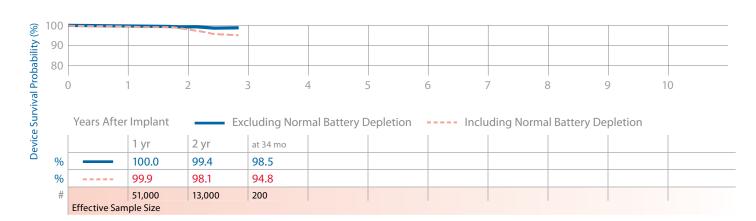
Effective Sample Size



D224TRK Consulta CRT-D

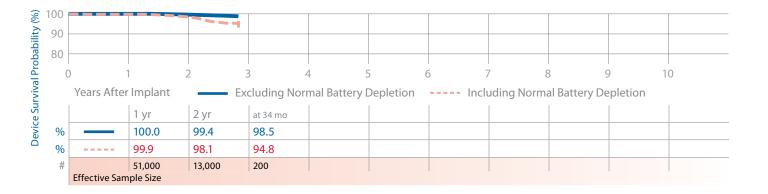
Product Characteristics

US Market Release	Sep-08	Malfunctions (US)	155	NBD Code	DDED
	•				
Registered US Implants	54,000	Therapy Function Not Compromised	150	Serial Number Prefix	PUD
Estimated Active US Implants	46,000	Electrical Component	8	Max Delivered Energy	35 J
Normal Battery Depletions (US)	93	Software/Firmware	1	Estimated Longevity	See page 22
Advisories	None	Possible Early Battery Depletion	141		
		Therapy Function Compromised	5		
		Electrical Component	5		



D274TRK Concerto II CRT-D

US Market Release	Aug-09	Malfunctions (US)	7	NBD Code	DDED
Registered US Implants	27,000	Therapy Function Not Compromised	6	Serial Number Prefix	PZV
Estimated Active US Implants	24,000	Possible Early Battery Depletion	6	Max Delivered Energy	35 J
Normal Battery Depletions (US)	14	Therapy Function Compromised	1	Estimated Longevity	See page 22
Advisories	None	Electrical Component	1		



Sep-08

12,000

9,900

None

39



D284TRK Maximo II CRT-D

US Market Release

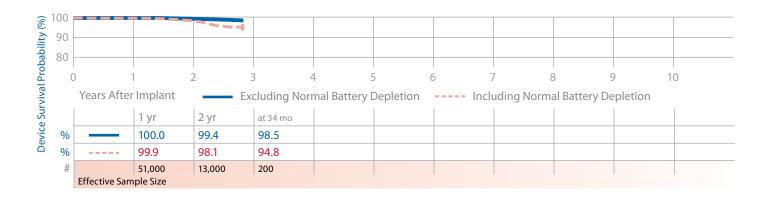
Advisories

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Malfunctions (US)	39	NBD Code	DDED
Therapy Function Not Compromised	39	Serial Number Prefix	PZP
Possible Early Battery Depletion	39	Max Delivered Energy	35 J
Therapy Function Compromised	0	Estimated Longevity	See page 22



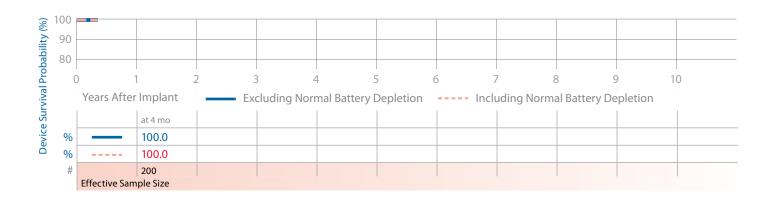
None



Advisories

D314TRG Protecta XT CRT-D

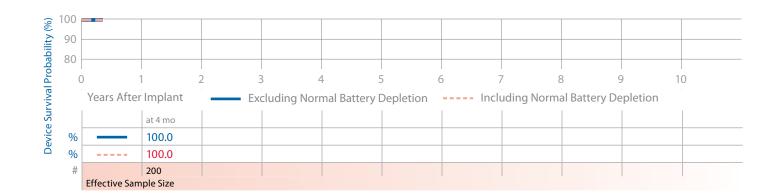
US Market Release	Mar-11	Malfunctions (US)	0	NBD Code	DDED
Registered US Implants	2,300	Therapy Function Not Compromised	0	Serial Number Prefix	PFS
Estimated Active US Implants	2,200	Possible Early Battery Depletion	0	Max Delivered Energy	35J
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 22



D334TRG Protecta CRT-D

Product Characteristics

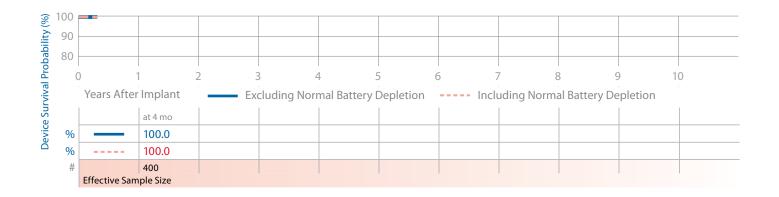
US Market Release	Mar-11	Malfunctions (US)	0	NBD Code	DDED
Registered US Implants	500	Therapy Function Not Compromised	0	Serial Number Prefix	PSO
Estimated Active US Implants	500	Possible Early Battery Depletion	0	Max Delivered Energy	35J
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 22
Advisories	None				



C2TR01 Syncra CRT-P

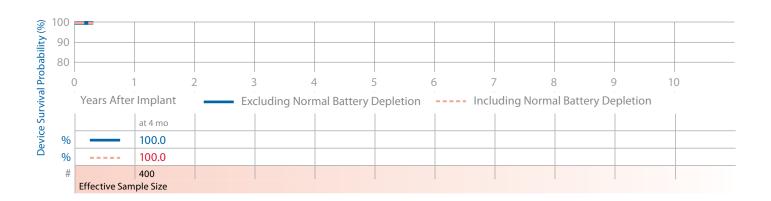
Product Characteristics

US Market Release	Mar-11	Malfunctions (US)	0	NBG Code	OOED
Registered US Implants	1,200	Therapy Function Not Compromised	0	Serial Number Prefix	PZX
Estimated Active US Implants	1,200	Possible Early Battery Depletion	0	Max Delivered Energy	NA
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 23
Advisories	None				



C4TR01 Consulta CRT-P

US Market Release	Mar-11	Malfunctions (US)	0	NBG Code	OAED
Registered US Implants	700	Therapy Function Not Compromised	0	Serial Number Prefix	PVX
Estimated Active US Implants	700	Possible Early Battery Depletion	0	Max Delivered Energy	NA
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 23
Advisories	None				





The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included. **Device Survival Summary** (95% Confidence Interval)

		8 yr 10 yr										
		7 yr										
		6 yr										
		5 yr	97.9 +0.2/-0.3 at 50 mo	0.4 +0.2/-0.2 at 50 mo	99.4 0.2/-0.3 at 59 mo	3.4 +0.9/-0.8 at 59 mo	99.1 +0.1/-0.2 at 58 mo	1.5 +0.4/-0.3 at 58 mo	99.4 +0.1/-0.2 at 58 mo	4.2 +0.7/-0.6 at 58 mo	99.2 +0.2/-0.2 at 58 mo	4.1 +0.9/-0.8 at 58 mo
ty (%)		4 yr	98.0 +0.2/-0.3	23.8 +0.9/-0.9	99.5 0.1/-0.2	70.0 +1.2/-1.3	99.3	66.4	99.4 +0.1/-0.2	66.2 +0.9/-0.9	99.2 +0.1/-0.2	69.4 +0.9/-0.9
robabilit	nt	3 yr	98.8 +0.2/-0.2	83.1 +0.6/-0.6	99.6 0.1/-0.2	89.8 +0.7/-0.8	99.7 +0.1/-0.1	90.2 +0.4/-0.4	99.6 +0.1/-0.1	89.0+0.5/-0.6	99.6 +0.1/-0.1	90.9
Device Survival Probability (%)	Years After Implant	2 yr	99.7 +0.1/-0.1	96.7 0.2/-0.3	99.9	97.8 0.3/-0.4	99.9	97.9 +0.2/-0.2	99.8 +0.1/-0.1	97.7 +0.2/-0.3	99.9 +0.0/-0.1	97.9 +0.2/-0.2
Device 5	Years Af	1 yr	99.9	99.6 +0.1/-0.1	100.0 +0.0/-0.0	99.8 0.1/-0.1	100.0	99.8 +0.0/-0.1	100.0	99.8 +0.1/-0.1	100.0	99.8
,			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
			Š	Š	2	8	Ž	Š	Š	Š	Š	No
Malfunctions (US)	prepy Function mpromised section Not mpromised al	The	32 + 272 = 304 No	$\frac{(9)}{\text{Nor}} + 0 = 9$ (advisory-related subset)	2 + 37 = 39 No	No	10 + 152 = 162 No	NON	7 + 66 = 73	No	3 + 89 = 92	No
Malfunctions (US)	erapy Iction Not npromised	The Cor The Thur Turi	+ 272 = 304	(9) + 0 = 9 (advisory-related subset)	+ 37 = 39	<u>8</u>	+ 152 = 162	No	+ 66 = 73	No	+ 89 = 92	No
Malfunctions (US)	oletions (US) srapy Function mpromised notion Not notion Not mpromised	Action Management of the Manag	32 + 272 = 304	(9) + 0 = 9 (advisory-related subset)	2 + 37 = 39	ON .	10 + 152 = 162	No	7 + 66 = 73	No	3 + 89 = 92	No
Malfunctions (US)	ive US blants mal Battery oletions (US) promised mpromised srapy promised mpromised	Esta Act Imp Moi Del Del The Con The Con	6,538 32 + 272 = 304	(9) + 0 = 9 (advisory-related subset)	2,479 2 + 37 = 39	∞	7,907 10 + 152 = 162	No	4,713	No	3,975 3 + 89 = 92	No
Malfunctions (US)	Implants imated ive US slants smal Battery sletions (US) srepy Function mpromised myromised serpy myromised myromised	Regular Regula	1,500 6,538 32 + 272 = 304	(9) + 0 = 9 (advisory-related subset)	700 2,479 2 + 37 = 39	∞	4,700 $7,907$ $10 + 152 = 162$	No.	1,200 4,713 7 + 66 = 73	No	4,000 3,975 3 + 89 = 92	No
Malfunctions (US)	pistered implants ive US inve US solution VS Inve US solution (US) series in properties in propertie	Regular Regula	28,000 1,500 6,538 32 + 272 = 304		9,000 700 $2,479$ $2 + 37 = 39$	δN	31,000 4,700 7,907 10 + 152 = 162	No.	17,000 1,200 4,713 7 + 66 = 73	No	$19,000 4,000 3,975 \qquad 3 + 89 = 92$	No

	Cardiac Resy	nch	roniza	ition Tl	herapy	, conti	nued				
		10 yr	99.4 +0.2/-0.3 at 9 yr	29.6 +3.4/-3.3 at 9 yr							
		8 yr	99.5	58.2 +1.6/-1.6	99.8 +0.1/-0.3 at 93 mo	47.6 +2.9/-3.0 at 93 mo					
		7 yr	99.5 +0.1/-0.2	73.7 +1.3/-1.3	99.8 +0.1/-0.1	76.0 +1.2/-1.3					
		6 yr	99.6	84.0 +0.9/-1.0	99.9 +0.0/-0.1	88.4 +0.7/-0.7					
		5 yr	99.7 +0.1/-0.2	91.2 +0.7/-0.7	99.9	94.6	98.4 +0.2/-0.2 at 53 mo	43.3 +2.6/-2.6 at 53 mo			
y (%)		4 yr	99.8 +0.1/-0.1	96.1	99.9	97.6 +0.2/-0.3	99.0 +0.1/-0.1	75.6 +0.6/-0.6	61.8 +2.0/-2.1 at 40 mo	11.5 +1.5/-1.4 at 40 mo	
Device Survival Probability (%)	nt .	3 yr	99.9 +0.0/-0.1	98.2 +0.3/-0.3	100.0 +0.0/-0.0	99.3 +0.1/-0.1	99.5 +0.1/-0.1	92.0 +0.2/-0.2	79.3 +1.6/-1.7	50.7 +2.0/-2.0	
urvival P	Years After Implant	2 yr	100.0	99.7 +0.1/-0.1	100.0	99.8 +0.0/-0.1	999.8 +0.0/-0.0	98.1 +0.1/-0.1	99.5 +0.2/-0.4	97.1 +0.6/-0.7	
Device 5	Years Af	1 yr	100.0	99.9	100.0	99.9	100.0	99.8	99.9 +0.1/-0.2	99.8 +0.1/-0.3	
,			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	
	ls	toT	32		18		429		1,286		
Malfunctions (US)	erapy Setion Not Sesimordm	ın∃	II ∞		10 =	i i	398 =		1,272 =		
unctio	ubromisea	רסו	+		+		+		+		
Malfu	erapy oction	The	24		∞		31		14		
,	yaətteri (SU) snoitəld		1,103		963		3,893	MOSFET	222	ed Device	MOSFET
	bətemi SU əvi stnslc	tэА	1,900		18,000		49,000	omalies in	300	ntial Reduce	omalies in
	jistered stnalqml	SO Beg	15,000		39,000		81,000	note on Ar Jy	3,500	. 2009 Poter	note on Ar Jy
	Market ease	SU Sel	Aug-01		Feb-03		May-06	Performance uit Technolog	May-06	e page 148–	Performance uit Technolog
		Family	InSync		InSync III		Concerto	See page 159 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	Concerto	Advisories: See page 148–2009 Potential Reduced Device Longevity	See page 159 – Performance note on Anomalies in MOSFET Integrated Circuit Technology
		Number	8040		8042		C154DWK, C164AWK, C174AWK (Non- advisory		C154DWK, C164AWK, C174AWK (Advisory population)		

Device Survival Summary continued

					E	Malfunct	Malfunctions (US)		E	Device S	Device Survival Probability (%)	obability	(%) /					
:		Narket sase	istered mplants	bətem 2U əv stnal	mal Battery letions (US)	rapy ction npromised	rapy ction Not npromised	Įŧ		Years Aft	Years After Implant	‡						
Model Number	Family	NS N	N21 gea	its∃ itɔA qml	Nor Dep		unℲ	toT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
D224TRK	Consulta CRT-D	Sep-08	54,000	46,000	93	70	+ 150 =	155	Excluding Normal Battery Depletion	100.0	99.4 +0.1/-0.1	98.5 +0.3/-0.3 at 34 mo						
									Including Normal Battery Depletion	99.9	98.1 +0.2/-0.2	94.8 +0.5/-0.6 at 34 mo						
D274TRK	Concerto II CRT-D	Ang-09	27,000	24,000	41	_	9 +	7	Excluding Normal Battery Depletion	100.0	99.4 +0.1/-0.1	98.5 +0.3/-0.3 at 34 mo						
									Including Normal Battery Depletion	99.9	98.1 +0.2/-0.2	94.8 +0.5/-0.6 at 34 mo						
D284TRK	Maximo II CRT-D	Sep-08	12,000	006'6	39	0	+ 39	39	Excluding Normal Battery Depletion	100.0	99.4	98.5 +0.3/-0.3 at 34 mo						
									Including Normal Battery Depletion	99.9	98.1 +0.2/-0.2	94.8 +0.5/-0.6 at 34 mo						
D314TRG	Protecta XT CRT-D	Mar-11	2,300	2,200	0	0	0 +	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
D334TRG	Protecta CRT-D	Mar-11	200	200	0	0	0 +	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
C2TR01	Syncra CRT-P	Mar-11	1,200	1,200	0	0	0 +	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
C4TR01	Consulta CRT-P	Mar-11	700	700	0	0	0 +	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 4 mo								



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					Estimated Longevity					Elective	Replacement	
					**						:RI)***	End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

					Estimated Longevity						mmended	
					اور ادر)**				_		ment (RRT)***	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 10.9	≤ 2.62 V	-	3 month after RRT or > 16-second charge time
D224TRK	Consulta CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D274TRK	Concerto II	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D284TRK	Maximo II CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D314TRG	Protecta XT CRT-D	CRT-D	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT
D334TRG	Protecta CRT-D	CRT-D	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT

^{*} Volume and mass differ by connector style.

^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

		Estimated Lon	gevity		
Model Number	Family	Amplitude Setting	500 Lead Ω	1,000 Lead Ω	Elective Replacement Time Indicators
8040	InSync	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	*
8042	InSync III	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	*
C2TR01	Syncra CRT-P	Low 2.5 V (A, RV) Normal 3.5 V (A, RV) High 5.0 V (A, RV)	8.7 6.0 3.3	10.7 8.2 5.1	*
C4TR01	Consulta CRT-P	Low 2.5 V (A, RV) Normal 3.5 V (A, RV) High 5.0 V (A, RV)	8.7 6.0 3.3	10.7 8.2 5.1	*

 $^{^*}$ Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Dec-02

19,000

6,200

2

2 yr

99.9

99.6

13,000

11,000

Dec-00

17,000

2,900

2,986

9,800

794

7230 Marquis VR **US Market Release**

Battery Short

100

%

%

#

Device Survival Probability (%)

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Advisories: See page 154 – 2005 Potential Premature Battery Depletion Due to

Years After Implant

Effective Sample Size

1 yr

100.0

99.8

17,000

Product Characteristics

)	2	Malfund	ctions (US)		5	7	NBD Cod	e		VVEV		
)	0	Therap	y Function No	t Compromise	d 2	8	Serial Nu	mber Prefix		PKD, P	LW, PLY	
)	0	Ele	ctrical Compor	nent	1	2						
).	4	Ва	ttery (1 malfund	tion related to a	idvisory)	1	Max Deli	vered Energy		30 J		
		So	ftware/Firmwa	re		1	Estimate	d Longevity		See p	age 40	
		Po	ssible Early Batt	tery Depletion	1	3						
		Ot	her			1						
		Therap	y Function Co	mpromised	2	9						
		Bat	tery (19 malfun	ctions related to	advisory) 2	0						
		Ele	ctrical Compon			9						
						-						
												_
								1				_
-	3	,	1	ι 5 - β	 	7	S	} ()	1(1	
						/					J	
C	ludin	g Norn	nal Battery D	epletion	Inclu	uding	g Norma	l Battery De	pletion	1 .		
	3 yr		4 yr	5 yr	6 yr	7 y	r	8 yr	at 99 m	10		
	99.9		99.8	99.7	99.6	99.	5	99.3	99.2			
	99.3		99.0	98.3	93.9	84.	2	70.1	52.2			

4,500

7231Cx GEM III VR

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Performance Note: See page 165-Performance note on ICD Battery

US Market Release

Discharge Behavior

Malfunctions (US) **Therapy Function Not Compromised** Battery **Electrical Component** Possible Early Battery Depletion **Therapy Function Compromised** Battery

8,700

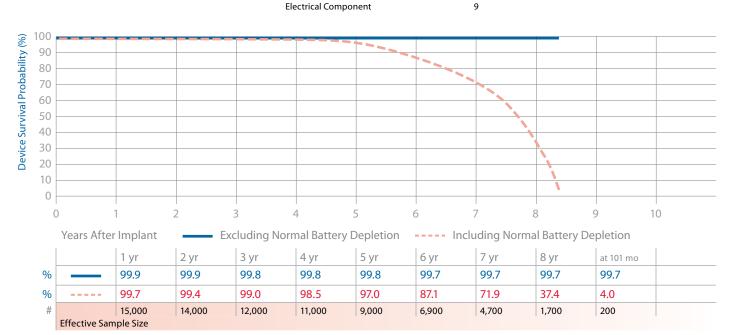
7,400

Product Characteristics

900

37	NBD Code	VVEV
27	Serial Number Prefix	PJL
1	Max Delivered Energy	30 J
22	Estimated Longevity	See page 40
4		
10		
1		
9		

100





7232 Maximo VR

Product Characteristics

2 Maximo V	K							Product Characte	ristics	
JS Market Release		Oct-03	Malfu	nctions (US)			60	NBD Code		VVEV
Registered US Implant	S	44,000	The	apy Function I	Not Compromi	sed	45	Serial Number Prefix		PRN, PVF, PVG
Estimated Active US Im	nplants	23,000	1	Electrical Comp	onent		20	Max Delivered Energy		35 J
Normal Battery Deplet	ions (US)	1,037	ı	Possible Early B	attery Depletio	n	21	Estimated Longevity		See page 40
Advisories: See page	154_ 2005 Po	tential	(Other			4			
remature Battery Dep		territar	Ther	apy Function (Compromised		15			
Battery Short			ı	Electrical Comp	onent		13			
			I	Electrical Interc	onnect		1			
			ı	Possible Early B	attery Depletio	n	1			
100							_			
90						,				
80										
70										
60										
0 1	2	2 3		4	5	6	7	8	9	10
Years After	Implant	Excl	uding No	rmal Battery	Depletion	Ir	ncluding	Normal Battery D	epletion	
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 85 mo		
%	100.0	99.9	99.9	99.9	99.8	99.8	99.8	99.8		
%	99.9	99.8	99.5	99.2	97.8	90.0	74.9	66.5		
#	40,000	35,000	31,000	26,000	19,000	9,200	400	100		

7274 Marquis DR

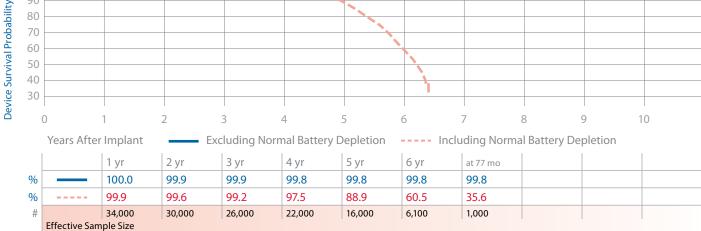
JS Mark	ket Release		M	ar-02 M	Malfunctions (US)			190	NBD Code	VVED
Register	red US Implai	nts	48	3,000	Therapy Function	Not Compromi	sed	83	Serial Number Prefix	PKC
stimate	ed Active US	Implants	4	4,900	Battery (3 malf	unctions related	to advisory)	5	Max Delivered Energy	30 J
lormal	Battery Depl	etions (US)	:	7,545	Electrical Com	ponent		27	Estimated Longevity	See page 4
dvisor	ries: See pag	je 154 – 2005 i	Potential		Possible Early (Battery Depletio	n	51		
rematu	ure Battery D	epletion Due t			Therapy Function	Compromised		107		
attery	SHOLL				Battery (73 mal	functions related	to advisory)	80		
					Electrical Comp	oonent		27		
100 –										
90 -										
80										
70 -										
60 -										
50 -										
40 -										
30 -										
20 -								1		
10 -								1		
0										
0		1	2	3	4	5	6	7	8 9	10
	Years Afte	r Implant		Excluding	Normal Batter	y Depletion	In	cluding	g Normal Battery Depletic	on
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 y	r	
%		99.9	99.9	99.8	99.6	99.4	99.3	99.		
%		99.8	99.5	98.4	96.9	90.5	65.4	5.4		
#		42,000	34,000	26,000	22,000	18,000	10,000	700		



7275 GEM III DR

	Effective Sar	mple Size									
#		18,000	15,000	13,000	10,000	5,500	700	300			
%		99.4	98.8	96.7	90.0	64.8	12.8	0.9			
%		99.9	99.9	99.8	99.8	99.7	99.7	99.7	7		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 73	3 mo		
	Years Afte	er Implant	E	excluding l	Normal Batter	y Depletion	1	ncluding	g Normal Bat	tery Depleti	on
0		I	2	3	4	5	6	/	8	9	10
		1	2	2	4		6	7	0		10
10							١				
20											
30											
40											
50											
60											
70											
80											
90											
100											
					Electrical Inter	•		1			
					Electrical Com	ponent		8			
				Т	herapy Function Battery	Compromised		11 2			
					Other			1			
	nance note or ge Behavior	n ICD Battery			•	Battery Depletion	on	18			
		See page 165	-		Software/Firm	nware		1			
Normal	Battery Depl	etions (US)	4	,359	Electrical Com	ponent		11	Estimated Lon	gevity	See page
Estimat	ted Active US	Implants	1,	,700	Battery			1	Max Delivered	l Energy	30 J
Registe	red US Implai	nts	20,	.000 T	herapy Function	Not Compromi	sed	32	Serial Number	Prefix	PJM
o	ket Release		Nov	/-00 M	alfunctions (US)			43	NBD Code		VVED

/2/	8 Maximo DR				Product Characteristics	
U	IS Market Release	Oct-03	Malfunctions (US)	55	NBD Code	VVED
R	egistered US Implants	38,000	Therapy Function Not Compromised	46	Serial Number Prefix	PRM
E:	stimated Active US Implants	14,000	Electrical Component	19	Max Delivered Energy	35 J
N	Iormal Battery Depletions (US)	4,176	Possible Early Battery Depletion	25	Estimated Longevity	See page 40
	dvisories: See page 154 – 2005 Potential		Other	2		
	remature Battery Depletion Due to attery Short		Therapy Function Compromised	9		
			Electrical Component	8		
			Possible Early Battery Depletion	1		
(%)	100					
obability (%)	90					
abil	80					
g	70					





7288 Intrinsic

Product Characteristics

US Market Rele	250	lere	n-04 Ma	Ifunctions (US)			60	NBD Code		VVED
									D (
Registered US I	•			erapy Function	Not Compromi	sed	53	Serial Numb		PUB
Estimated Activ	·	13,	000	Battery			2	Max Delivere		35 J
Normal Battery	Depletions (US)	3,	,033	Electrical Com	ponent		18	Estimated Lo	ongevity	See page 4
Advisories		N	one	Software/Firm	ware		1			
				Possible Early	Battery Depletic	on	31			
				Other			1			
			Tł	erapy Function	Compromised		7			
100				Electrical Com	ponent		7			
100 90 80 70 60 50 40 30 20					_					
90 80										
70										
60										
50						\\				
40										
30						1				
20						1				
							7			10
0	1	2	3	4	5	6	/	8	9	10
Years	After Implant		xcluding N	lormal Batter	y Depletion	11	ncludin	ig Normal B	attery Deplet	ion
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 7	76 mo		
%	1 00.0	99.9	99.9	99.8	99.8	99.7	99	.7		
%	99.9	99.7	99.2	98.1	89.1	64.9	27.	.9		
#	28,000	26,000	23,000	20,000	15,000	5,100	400			

7290Cx Onyx

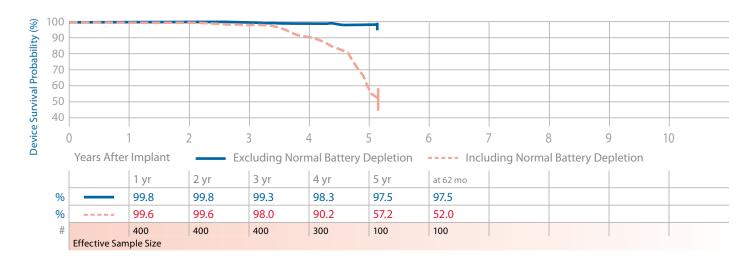
JS Mar	rket Release		Mar	-04	Malfunctions (US)			5	NBD Code		VVEV
Registe	ered US Implan	ts	1,0	000	Therapy Function	n Not Compron	nised	4	Serial Number	Prefix	PRP
Estima	ted Active US I	mplants	•	400	Electrical Con	nponent		3	Max Delivered	Energy	30 J
Norma	l Battery Deple	etions (US)		67	Possible Early	Battery Deplet	ion	1	Estimated Long	See page 40	
Adviso	ries		Ne	one	Therapy Function	n Compromise	d	1			
					Electrical Con	nponent		1			
100											
90											
80											
70											
60											
()	1	2	3	4	5	6	7	8	9	10
90 80 70 60	Years After	r Implant	E	xcludin	g Normal Batte	ry Depletion	1	ncludin	g Normal Bati	tery Depletic	on
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 7	'4 mo		
%		99.9	99.5	99.5	99.4	99.4	99.4	99	.4		
%		99.8	99.1	98.3	96.8	92.1	75.7	69.	.4		
#		900	800	700	600	500	200	100)		
	Effective Sam	nple Size									



D153ATG, D153DRG EnTrust

Product Characteristics

US Market Release	Jun-05	Malfunctions (US)	8	NBD Code	DDED
Registered US Implants	500	Therapy Function Not Compromised	7	Serial Number Prefix	PNR
Estimated Active US Implants	100	Possible Early Battery Depletion	7	Max Delivered Energy	30 J
Normal Battery Depletions (US)	121	Therapy Function Compromised	1	Estimated Longevity	See page 41
Advisories	None	Electrical Component	1		



D154ATG, D154DRG EnTrust

JAAI	G, D 13-11	DING LIII	Tust						Froduct Charact	eristics	
US Mark	et Release		Jun-	05 Ma	Ifunctions (US)			97	NBD Code		DDED
Register	ed US Implan	ts	28,0	00 T	herapy Function	Not Comprom	nised	86	Serial Number Prefix		PNR
Estimate	ed Active US Ir	mplants	16,0	00	Electrical Com	ponent		24	Max Delivered Energ	y	35 J
Normal	Battery Deple	etions (US)	9	75	Electrical Inter	connect		1	Estimated Longevity		See page 4
Advisori	ies		No	ne	Software/Firm	ware		2			
					Possible Early	Battery Depleti	ion	59			
				Т	herapy Function	Compromised	d	11			
					Electrical Com	ponent		11			
90 - 80 -											
90 - 80 - 0	Years After	1 · Implant 1 yr	2 Ex	3 cluding l 3 yr	4 Normal Batter 4 yr	5 y Depletion 5 yr	6 In	7 Icludii 	8 ng Normal Battery [9 Depletion	10
%											
, , , , , , , , , , , , , , , , , , ,		100.0	99.9	99.8	99.7	99.5	99.5				
%		99.9	99.7	99.2	97.7	90.4	76.6				
#	Effective Sam	26,000 pole Size	23,000	21,000	17,000	9,900	600				



D154AWG, D164AWG Virtuoso DR

Product Characteristics

Page	
Part	
Stimated Active US Implants	DDED
Normal Battery Depletions (US) 247 20 Electrical Interconnect 1 0 Estimated Longevity St.	VV, PUL
Possible Early Battery Depletion 49 0 0 0 0 0 0 0 0 0	5 J
Other 1 1 1 Performance Note: See page 159 Anomalies in MOSFET Integrated Circuit Electrical Component 24 11 D154AWG, D164AWG, (Non-acvisory population) 99.7% D154AWG, D164AWG (Advisory population) 566% Pears After Implant Excluding Normal Battery Depletion Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Mon-Adv 1 yr 2 yr 3 yr at 46 mo Mon-Mon-Mon-Mon-Mon-Mon-Mon-Mon-Mon-Mon-	See page 4
Other 1 1 1 Therapy Function Compromised 24 11 Anomalies in MOSFET Integrated Circuit echnology D154AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG (Advisory population) 566% Therapy Function Compromised 24 11 D154AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG (Advisory population) 566% D154AWG, D164AWG (Advisory population) 566% Therapy Function Compromised 24 11 D154AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG (Advisory population) 566% D154AWG, D164AWG (Advisory population) 566% Therapy Function Compromised 24 11 D154AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG (Advisory population) 566% Therapy Function Compromised 24 11 D154AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG, D164AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG,	
Anomalies in MOSFET Integrated Circuit Electrical Component 24 11 100	
Anomalies in MOSFET Integrated Circuit echnology Electrical Component 24 11 D154AWG, D164AWG, (Non-advisory population) 99.7% D154AWG, D164AWG (Advisory population) 56.6% D154AWG, D164AWG (Advisory popu	
DIS4AWG, DI64AWG (Non-advisory population) 99.7% DIS4AWG, DI64AWG (Advisory population) 566% Excluding Normal Battery Depletion Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo 100.0 99.9 99.9 99.8 99.7 100.0 99.9 99.9 99.8 99.7 66,000 58,000 39,000 15,000 200 Effective Sample Size Advisory 1 yr 2 yr 3 yr at 46 mo Machine Battery Depletion Including Normal Battery Depletion Advisory 1 yr 2 yr 3 yr at 46 mo Machine Battery Depletion Including Normal Battery	
DIS4AWG, DI64AWG, (Non-advisory population) 99.7% DI54AWG, DI64AWG (Advisory population) 566% DI54AWG, DI64AWG, DI64AWG, DI64AWG (Advisory population) 566% DI54AWG, DI64AWG, DI64AW	
DIS4AWG, DI64AWG, (Non-advisory population) 99.7% DI54AWG, DI64AWG (Advisory population) 99.7% DI54AWG, DI64AWG (Advisory population) 56.6% DI54AWG, DI64AWG (Advisory population) 56.6% Teach of the population of the populati	
70 60 60 60 60 60 60 60 60 60 60 60 60 60	
60	
50	
DIS4AWG, DI 64AWG (Advisory population) 566% DIS4AWG, DI 64AWG (Advisory population) 566% DIS4AWG, DI 64AWG (Advisory population) 566% Textually a series of the series	
30 20	
20 10 0 1 2 3 4 5 6 7 8 9 10 Years After Implant — Excluding Normal Battery Depletion Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo	
10	
0 1 2 3 4 5 6 7 8 9 10 Years After Implant — Excluding Normal Battery Depletion — Including Normal Battery Depletion % — 100.0 99.9 99.9 99.8 99.7 % — 100.0 99.9 99.4 98.5 96.6 # 66,000 58,000 39,000 15,000 200 Effective Sample Size % — 100.0 99.9 90.6 56.6 # — 99.9 99.6 80.9 7.0	
0 1 2 3 4 5 6 7 8 9 10 Years After Implant Excluding Normal Battery Depletion Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo Including Normal Battery Depletion % 100.0 99.9 99.9 99.8 99.7 Including Normal Battery Depletion % 100.0 99.9 99.8 99.7 Including Normal Battery Depletion % 100.0 99.9 99.8 99.7 Including Normal Battery Depletion % 100.0 99.9 99.8 99.7 Including Normal Battery Depletion % 100.0 99.9 99.4 98.5 96.6 Including Normal Battery Depletion % 100.0 99.9 99.8 99.7 Including Normal Battery Depletion % 100.0 99.9 99.8 99.7 99.7 Including Normal Battery Depletion % Advisory 1 yr 2 yr 3 yr at 46 mo	
Years After Implant Excluding Normal Battery Depletion Including Normal Battery Depletion Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo % 100.0 99.9 99.9 99.8 99.7 % 99.9 99.7 99.4 98.5 96.6 # 66,000 58,000 39,000 15,000 200 Effective Sample Size % Advisory 1 yr 2 yr 3 yr at 46 mo % 100.0 99.9 90.6 56.6 # 99.9 99.6 80.9 7.0	0
Non-Adv 1 yr 2 yr 3 yr 4 yr at 58 mo	
% — 100.0 99.9 99.9 99.8 99.7 99.4 98.5 96.6 # 66,000 58,000 39,000 15,000 200 Effective Sample Size % Advisory 1 yr 2 yr 3 yr at 46 mo	ı
%	
# 66,000 58,000 39,000 15,000 200 Effective Sample Size % Advisory 1 yr 2 yr 3 yr at 46 mo % — 100.0 99.9 90.6 56.6 # 99.9 99.6 80.9 7.0	
% Advisory 1 yr 2 yr 3 yr at 46 mo % 100.0 99.9 90.6 56.6 # 99.9 99.6 80.9 7.0	
% Advisory 1 yr 2 yr 3 yr at 46 mo % 100.0 99.9 90.6 56.6 # 99.9 99.6 80.9 7.0	
% 100.0 99.9 90.6 56.6 # 99.9 99.6 80.9 7.0	
% 100.0 99.9 90.6 56.6 # 99.9 99.6 80.9 7.0	
# 99.9 99.6 80.9 7.0	
777. 777. 667 1.0	
3,800 3,500 2,700 300	

Effective Sample Size



D154VRC EnTrust VR

Product Characteristics

J4VI	ic Lilliu	St VIN							Product	Characte	ristics	
US Mai	rket Release		Jun-(05 Malfu	nctions (US)			58	NBD Code			VVEV
Registe	ered US Implant	ts	14,00	00 Ther	apy Function	Not Comprom	ised	47	Serial Num	ber Prefix		PNT
Estima	ted Active US Ir	nplants	8,60	00 E	attery			2	Max Delive	red Energy		35 J
Norma	l Battery Deple	tions (US)	:	74 E	lectrical Comp	oonent		19	Estimated L	ongevity		See page
Adviso	ories		Nor	ne F	ossible Early B	Battery Depletion	on	25				
				(Other			1				
				Ther	apy Function	Compromised		11				
				E	lectrical Comp	oonent		11				
90 80												
2	0	1	2	3	4	5	6	7	8		9	10
90 80	Years After		1		1	/ Depletion	1	cludin	ıg Normal E	Battery D	epletion	I
, ,		1 yr	2 yr	3 yr	4 yr	5 yr	at 70 mo					
%		99.9	99.9	99.8	99.7	99.4	99.3					
- /0		99.9	99.6	99.3	98.7	97.6	95.6					
#		13,000	12,000	11,000	8,600	4,600	200					
#	Effective Sam		1.2,000	1.1,000	0,000	1,000	200		1		1	

D154VWC, D164VWC Virtuoso VR

4V WC, D10-								
JS Market Release		May-0	06 Mal	Ifunctions (US)		29	NBD Code	VVEV
Registered US Implan	nts	33,00	00 Th	erapy Function	Not Compromised	17	Serial Number Prefix	PUN, PUP
Estimated Active US I	mplants	24,00	0	Electrical Com related to advis	ponent (3 malfunctions cory)	11	Max Delivered Energy	35 J
Normal Battery Deple	etions (US)	4	19	Electrical Inter	connect	1	Estimated Longevity	See page
Advisories: See pag	ge 148- 2009			Possible Early	Battery Depletion	5		
Potential Reduced D		.y	Th	erapy Function	Compromised	12		
Performance Note: Anomalies in MOSFE				Electrical Com	-			
3,								
100 90 80	1	2	3	4	5 6 y Depletion	7	8 9	10 on
100 90 80	1 r Implant	2 Exc	3 cluding N	4 Iormal Batter		7 Includin	8 9 ng Normal Battery Depletic	
100 90 80	1	2	3	4	y Depletion	7 Includin		
100 90 80 0 Years After	1 r Implant	2 Exc	3 cluding N	4 lormal Batter	y Depletion	7 Includin		



D224DRG Secura DR

Product Characteristics

24DNG Secura	DK							Product Character	ISTICS	
US Market Release		Sep-08	Malfund	ctions (US)			15	NBD Code		VVED
Registered US Implants		42,000	Therap	y Function No	t Compromise	ed	9	Serial Number Prefix		PUG
Estimated Active US Impla	ants	38,000) Ele	ectrical Compor	nent		4	Max Delivered Energy		35 J
Normal Battery Depletion	ns (US)	38	B Po	ssible Early Bat	tery Depletion	า	3	Estimated Longevity		See page 4
Advisories		None	e Sc	oftware/Firmwa	re		2			
			Therap	y Function Co	mpromised		6			
			Ele	ectrical Compor	nent		5			
			So	ftware/Firmwa	re		1			
80 0 1	2	3		4	5	6	7	8	9	10
90 80 0 1 Years After Im 100 100 100 100 100 100 100 100 100 10	plant •	Excl		nal Battery D			ludin	g Normal Battery De		
10 m		-	99.9							
½ % 99			99.4							
			500							
Effective Sample										

D224VRC Secura VR

JS Market Release	•	Sep-	08 N	lalfunctions (US)		6	NBD Cod	de		VVEV
Registered US Imp	olants	16,0	00	Therapy Function Not Compromi	sed	4	Serial Nu	ımber Prefix		PUX
Estimated Active	JS Implants	14,0	00	Electrical Component		1	Max Deli	ivered Energy	/	35 J
Normal Battery De	epletions (US)		10	Possible Early Battery Depletic	on	2	Estimate	d Longevity		See page 4
Advisories		No	ne	Software/Firmware		1				
				Therapy Function Compromised		2				
				Electrical Component		1				
				Software/Firmware		1				
90 80	1	2	3	4 5	6	7	8		9	10
					0	/	C	,		10
Years At	fter Implant	1	cluding	Normal Battery Depletion		rcludin		် al Battery ြ		
	1 yr	2 yr	at 34 m	Normal Battery Depletion		ncludin				
%	1 yr	2 yr 99.9	at 34 m	Normal Battery Depletion		rcludin				
%	1 yr	2 yr	at 34 m	Normal Battery Depletion		ncludin				



D274DRG Virtuoso II DR

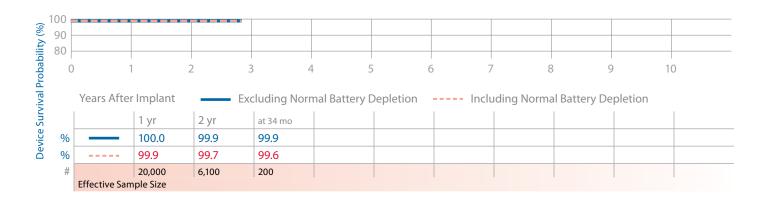
Product Characteristics

US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	VVED
Registered US Implants	19,000	Therapy Function Not Compromised	0	Serial Number Prefix	PZT
Estimated Active US Implants	18,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	2			Estimated Longevity	See page 41
Advisories	None				



D274VRC Virtuoso II VR

US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	VVEV
Registered US Implants	8,000	Therapy Function Not Compromised	0	Serial Number Prefix	PZR
Estimated Active US Implants	7,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	2			Estimated Longevity	See page 41
Advisories	None				

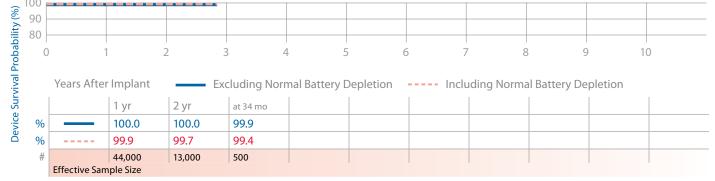




D284DRG Maximo II DR

Product Characteristics

US Market Release	Sep-08	Malfunctions (US)	5	NBD Code	VVED
Registered US Implants	16,000	Therapy Function Not Compromised	2	Serial Number Prefix	PZM
Estimated Active US Implants	14,000	Electrical Component	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	11	Possible Early Battery Depletion	1	Estimated Longevity	See page 4
Advisories	None	Therapy Function Compromised	3		
		Electrical Component	3		
100					



D284VRC Maximo II VR

#

Product Characteristics

US Ma	rket Release		Sep-0)8 Ma	Ifunctions (l	JS)		4	NBD Co	de		V	/VEV
Regist	ered US Implan	ts	10,00	00 TI	nerapy Func	tion Not Com	promised	1	Serial N	umber Prefix		Р	PZN
Estima	ated Active US Ir	mplants	8,70	00	Possible E	arly Battery D	epletion	1	Max Del	livered Energ	у	3	5 J
Norma	al Battery Deple	tions (US)		8 TI	nerapy Func	tion Compror	nised	3	Estimate	ed Longevity		S	See page 41
Adviso	ories		Nor	ne	Electrical (Component		2					
					Software/	Firmware		1					
90 80													
0) 1		2 3	3	4	5	6	7	8	3	9	10	
	Years After		1	1		ttery Deple	tion	- Includ	ing Norma	al Battery I	Depletio	n	
0/	Years After	1 yr	2 yr	at 34 mo		ttery Deple	tion	- Includ	ing Norma	al Battery	Depletio	n	
% %	Years After		1	1		ttery Deple	tion	- Includ	ing Norma	al Battery I	Depletio	n	

20,000

Effective Sample Size

6,100

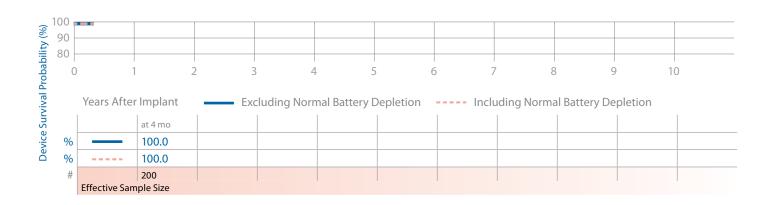
200



D314DRG Protecta XT DR

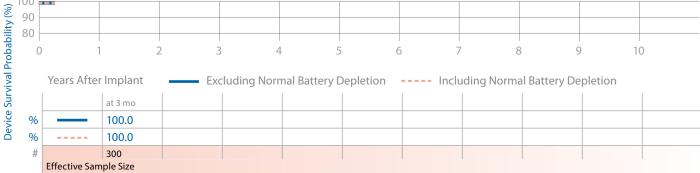
Product Characteristics

US Market Release	Mar-11	Malfunctions (US)		NBD Code	DDED
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PSK
Estimated Active US Implants	2,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0	Electrical Component	0	Estimated Longevity	See page 41
Advisories	None	Software/Firmware	0		



D314VRG Protecta XT VR

٠.	SITVING FIOLECTIA XI VII				Product Characteris	Stics	
	US Market Release	Mar-11	Malfunctions (US)		NBD Code		VVEV
	Registered US Implants	700	Therapy Function Not Compromised	0	Serial Number Prefix		PSA
	Estimated Active US Implants	700	Therapy Function Compromised	0	Max Delivered Energy		35 J
	Normal Battery Depletions (US)	0	Electrical Component	0	Estimated Longevity		See page 41
	Advisories	None	Software/Firmware	0			
(%)	100						





D334DRG Protecta DR

Product Characteristics

US Market Release	Mar-11	Malfunctions (US)		NBD Code	DDED
Registered US Implants	800	Therapy Function Not Compromised	0	Serial Number Prefix	PSP
Estimated Active US Implants	800	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0	Electrical Component	0	Estimated Longevity	See page 41
Advisories	None	Software/Firmware	0		



D334VRG Protecta VR

US Ma	rket Release		Mar-11	Malfunctions (US)				NBD Code		VVEV
Regist	tered US Implant	ts	300	Therapy Function	Not Comprom	ised	0	Serial Number P	refix	PSX
Estima	ated Active US Ir	mplants	300	Therapy Function	Compromised		0	Max Delivered E	nergy	35 J
Norma	al Battery Deple	tions (US)	0	Electrical Com	ponent		0	Estimated Longo	evity	See page 41
Adviso	ories		None	Software/Firm	nware		0			
⊋ 100										
Device Survival Probability (%)										
ab iii 80										
roba	0	1 2	2 3	4	5	6	7	8	9	10
<u>a</u>	\/	Jacobana	E 1 1:	N. ID.	D 1 ::		1 1 1	N ID	D 1 ::	
Σ̈́	Years After	impiant	Excludi	ng Normal Batter	y Depletion		Includin	g Normal Batte	ery Depletio	on
nS a		at 3 mo								
× × × ×		100.0								
å %		100.0								
#		300								
	Effective Sam	ple Size								



Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

Device	Device Survival Summary continued	ummar	y contii	panu	E	Malfun	unctions			E	Device S	Device Survival Probability (%)	obability	(%)					
7		Market esse	jistered Implants	bətem SU əvi stnsle	mal Battery Jetions	erapy Iction Inpromised	rapy oction Not	npromised	ls		Years Aft	Years After Implant	ıt						
Number	Family	NS I	I SN Bəy	its∃ itoA imp			un <u>⊣</u> ∃YF		тот		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
7290Cx	Onyx	Mar-04	1,000	400	29	1	+	II	2	Excluding Normal Battery Depletion	99.9	99.5 +0.3/-0.8	99.5	99.4 +0.4/-0.9	99.4 +0.4/-0.9	99.4 +0.4/-0.9	99.4 +0.4/-0.9 at 74 mo		
										Including Normal Battery Depletion	99.8	99.1	98.3 +0.7/-1.2	96.8 +1.1/-1.6	92.1	75.7 +4.0/-4.6	69.4 +4.9/-5.5 at 74 mo		
D153ATG, D153DRG	EnTrust	Jun-05	200	100	121	-	+	Ш	∞	Excluding Normal Battery Depletion	99.8 +0.2/-1.6	99.8 +0.2/-1.6	99.3 +0.5/-1.6	98.3 +0.9/-2.0	97.5 +1.3/-2.5	97.5 +1.3/-2.5 at 62 mo			
										Including Normal Battery Depletion	99.6	99.6	98.0 +1.0/-2.0	90.2 +2.8/-3.8	57.2 +5.9/-6.4	52.0 +6.2/-6.6 at 62 mo			
D154ATG, D154DRG	EnTrust	Jun-05	28,000	16,000	975	11	+ 86	II	97	Excluding Normal Battery Depletion	100.0	99.9	99.8 +0.0/-0.1	99.7 +0.1/-0.1	99.5	99.5 +0.1/-0.1 at 69 mo			
										Including Normal Battery Depletion	99.9	99.7	99.2 +0.1/-0.1	97.7	90.4	76.6 +1.5/-1.5 at 69 mo			
D154AWG D164AWG (Non-advisory population)	Virtuoso DR	May-06	73,000	54,000	247	24	+ 72	II	96	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.8	99.7 +0.1/-0.1 at 58 mo				
										Including Normal Battery Depletion	99.9	99.7	99.4 +0.1/-0.1	98.5	96.6 +0.5/-0.6 at 58 mo				
D154AWG D164AWG (Advisory population)	Virtuoso DR	May-06	4,000	500	20	=	+ 1,785	II	1,796	Excluding Normal Battery Depletion	100.0	99.9	90.6	56.6 +1.8/-1.9 at 46 mo					
	Advisories: See page 148 – 2009 Potential Reduced Device Longevity	e page 148	– 2009 Pote	ential Reduce	d Device					Including Normal Battery Depletion	99.9	99.6 +0.2/-0.3	80.9	7.0 +1.2/-1.1 at 46 mo					
	See page 159 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	Performanc Jit Technolog	e note on A gy	nomalies in №	AOSFET														
D154VRC	EnTrust VR	Jun-05	14,000	8,600	74	11	+ 47	II	28	Excluding Normal Battery Depletion	99.9	99.9	99.8 +0.1/-0.1	99.7 +0.1/-0.1	99.4	99.3 +0.2/-0.3 at 70 mo			
										Including Normal Battery Depletion	99.9	99.6	99.3 +0.1/-0.2	98.7	97.6 +0.3/-0.4	95.6 +0.7/-0.8 at 70 mo			
D154VWC D164VWC (Non-advisory population)		May-06	33,000	24,000	49	12	+ 17	II	29	Excluding Normal Battery Depletion	100.0	100.0	999.9	99.9	99.9 +0.0/-0.1 at 56 mo				
	Advisories: See page 148 – 2009 Potential Reduced Device Longevity	e page 148	– 2009 Pote	ential Reduce	d Device	(0) (advisor	+ (3) = 3 isory-related subset)	= d subset	_	Including Normal Battery Depletion	99.9	99.8	99.6	99.4 +0.1/-0.1	98.9 +0.2/-0.3 at 56 mo				
	See page 159 - Performance note on Anomalies in MOSFET Integrated Circuit Technology	· Performanc uit Technolo	e note on A gy	nomalies in N	AOSFET														
10:+000	7																		

Implantable Cardioverter Defibrillators, continued

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		8 yr												
		7 yr												
		6 yr												
		5 yr												
ty (%)		4 yr												
Probabili	ant	3 yr	99.9 +0.0/-0.1 at 34 mo	99.4 +0.1/-0.2 at 34 mo	99.9 +0.0/-0.0 at 34 mo	99.6 +0.1/-0.1 at 34 mo	99.9 +0.0/-0.1 at 34 mo	99.4 +0.1/-0.2 at 34 mo	99.9 +0.0/-0.0 at 34 mo	99.6 +0.1/-0.1 at 34 mo	99.9 +0.0/-0.1 at 34 mo	99.4 +0.1/-0.2 at 34 mo	99.9 +0.0/-0.0 at 34 mo	99.6
Device Survival Probability (%)	Years After Implant	2 yr	100.0	99.7	99.9	99.7	100.0	99.7 +0.1/-0.1	99.9	99.7 +0.1/-0.1	100.0	99.7	99.9	99.7
Device	Years Af	1 yr	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.9	100.0+0.0/-0.0	96.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including								
	ls	toT	15		9		0		0		72		4	
	pesimorqn												1	
ctions	bosimosan	юЭ	II		II		Ш		II		II			
	erapy oction Not	ını	6 +		4		0 +		0 +					
Malfunctions	ofion Not	The The TuT	6		4		0		0		2 =		-	
Malfun	nction mpromised erapy sction Not	Dell har hun ioo ioo har hun	6		4		0 +		0 +		+ 5		+	
Malfun	oletions srapy notion mpromised mrapy srapy srapy	Act Iml Iol Iol Inl Inl Iol Inl	6 +		2 + 4		0 + 0		0 + 0		3 + 2		+ +	
Malfun	ive US inal Battery sinal Battery site of the control of the contr	Estable Strain S	38 6 + 9		10 2 + 4		2 0 + 0		2 0 + 0		3 + 2 =		m — + m	
Malfun	imated jve US ive US slants inal Battery slations srapy repy repy repy repy repy repy repy re	Region No. 10 More The The The The The The The The The Th	38,000 38 6 + 9		14,000 10 2 + 4		18,000 2 0 + 0		7,000 2 0 + 0		14,000 11 3 + 2 =		8,700 8 3 + 1 =	
Malfun	pease pistered maplants constructed by stable stab stable stab stable stable stab stab stab stab stab stab stab stab	Region No. 10 More The The The The The The The The The Th	42,000 38,000 38 6 + 9		16,000 14,000 10 2 + 4		19,000 18,000 2 0 + 0		8,000 7,000 2 0 + 0		16,000 14,000 11 3 + 2 =		10,000 8,700 8 3 + 1 =	

at 4 mo 100.0 +0.0/-0.0 at 3 mo	100.0 +0.0/-0.0 at 3 mo
Excluding Normal Battery Depletion	Including Normal Battery Depletion
0	
0	
0	
0	
300	
300	
Mar-11	
Protecta VR	
D334VRG	
	Protecta VR Mar-11 300 300 0 0 + 0 = 0 Excluding Normal Battery Depletion



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly

					Estimated Longevity					Elective		
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing		Charge ERI)***	End of Life (EOL) Battery Voltage
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	≤ 2.40 V [§]
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231Cx	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V [§]
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290Cx	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V		≤ 2.40 V

^{*} Volume and mass differ by connector style.

 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

 $^{^{***}}$ The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

[§] For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If three consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



Reference Chart continued

					Estimated Longevity					Recomn Replac (RRT	ement	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D154VRC	EnTrust VR	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D224DRG	Secura DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.1 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D224VRC	Secura VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.7 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D274DRG	Virtuoso II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D274VRC	Virtuoso II VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D284DRG	Maximo II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.1 7.0	4.5 7.0 8.2	4.6 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D284VRC	Maximo II VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.6 7.7	4.6 7.4 8.8	4.9 8.1 9.7	5.0 8.4 10.2	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D314DRG	Protecta XT DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT
D314VRG	Protecta XT VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT
D334DRG	Protecta DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT
D334VRG	Protecta VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT

^{*} Volume and mass differ by connector style.

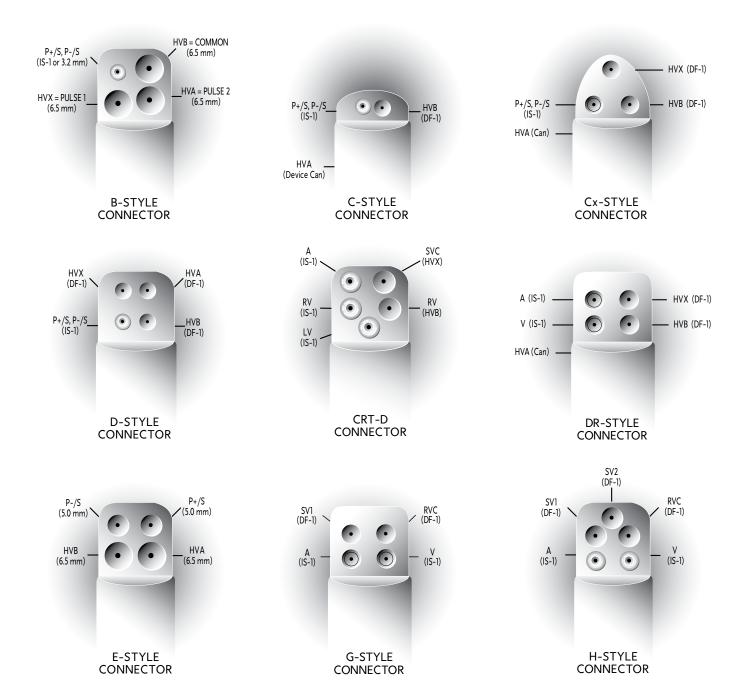
 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel.



ICD Connector Styles



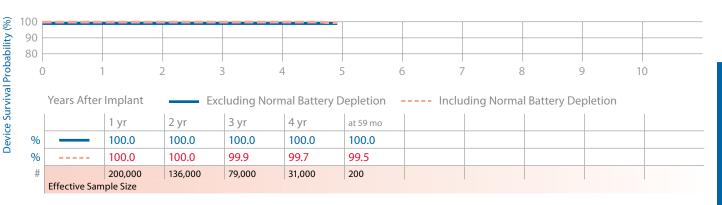
IPG Implantable Pulse Generators

Adapta DR ADDR01, ADDR03, ADDR06, ADD01

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	47	NBG Code	DDDR, DDD
Registered US Implants	266,000	Therapy Function Not Compromised	30	Serial Number Prefix	PWB, PWD,
Estimated Active US Implants	224,000	Electrical Component	30		PWC, PWF, NWB, NWC,
Normal Battery Depletions (US)	92	Therapy Function Compromised	17		NWD, NWF
		Electrical Component	15	Estimated Longevity	See page 78
Performance Note: See page 157 –		Electrical Interconnect	2		

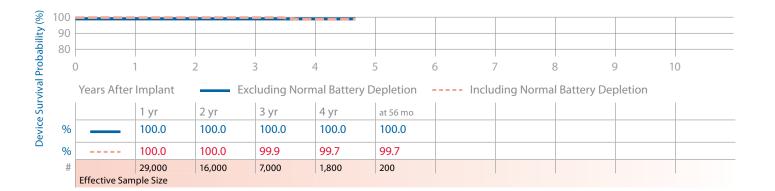
Performance Note: See page 157 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI



Adapta DR ADDRL1

Pacemakers with Measurement Lock-up ERI

US Market Release	Jul-06	Malfunctions (US)	3	NBG Code	DDDR
Registered US Implants	45,000	Therapy Function Not Compromised	2	Serial Number Prefix	PWE, NWE
Estimated Active US Implants	41,000	Electrical Component	2		
Normal Battery Depletions (US)	6	Therapy Function Compromised	1	Estimated Longevity	See page 78
Performance Note: <u>See page 157</u> – Performance note on Dual Chamber		Electrical Interconnect	1		



Adapta DR ADDRS1

Product Characteristics

apta	DK ADDI	151							Product Cha	racteristics	
US Mar	ket Release		Jul	-06 Ma	lfunctions (US)			4	NBG Code		DDDR
Registe	ered US Implan	ts	25,0	000 Th	erapy Function	Not Compromi	sed	2	Serial Number F	Prefix	PWA, NWA
Estimat	ted Active US I	mplants	20,0	000	Electrical Comp	ponent		2			
Normal	l Battery Deple	tions (US)		40 Th	erapy Function	Compromised		2	Estimated Long	evity	See page 7
Perforn	mance Note: <u>Se</u> mance note on akers with Mea		up ERI		Electrical Comp	ponent		2			
100											
80											
2	0	1	2	3	4	5	6	7	8	9	10
90 80 % % % %	Years After	1 yr	2 yr	3 yr	lormal Battery	at 57 mo		Includin	g Normal Batt	ery Depletio	n
%		100.0	100.0	100.0	100.0	100.0					
8 %		100.0	99.8	99.7	98.8	96.0					
#		18,000	12,000	6,300	2,400	200					
	Effective San	nple Size									

Adapta SR ADSR01, ADSR03, ADSR06

US Market Re	elease		Jul-06	Malfunc	tions (US)		5	5	NBG Code		SSIR
Registered U	S Implants		49,000) Therap	y Function No	t Compromise	d 1		Serial Number Prefix		NWN, NWM,
Estimated Ad	ctive US Imp	olants	35,000) Ele	ctrical Compor	nent	1				NWP, PWP, PWM, PWN
Normal Batte	Normal Battery Depletions (US) 44 Therapy Function Compromised					4	ļ	Estimated Longevity		See page 78	
Advisories	Advisories None Electrical Component					3	3				
				Ele	ctrical Intercon	nect	1				
100											
§ 90 —								+			
80 -											
o o	1	2	2 :	3 4	4	5	6	7	8	9	10
Pro											
Yea	rs After Ir	mplant	— Exc	luding Norm	nal Battery D	epletion	Inclu	ding	g Normal Battery De	epletion	
Device Survival Probability (%) 0 086 Aee		1 yr	2 yr	3 yr	4 yr	at 58 mo					
% = %		100.0	100.0	100.0	100.0	100.0					
å _% -		100.0	100.0	99.7	99.4	98.3					
#		34,000	22,000	12,000	4,600	100					
Effe	ctive Samp	le Size									



Adapta VDD ADVDD01

Product Characteristics

JS Mar	ket Release		Jul-	06 Malfu	unctions (US)			0	NBG Cod	de		VDD
Registe	ered US Implant	ts	8	00 The	rapy Function	Not Compro	mised	0	Serial Nu	Serial Number Prefix		
Estima	ted Active US Ir	nplants	7	00 The	Therapy Function Compromised				Estimated Longevity			See page
Norma	l Battery Deple	tions (US)		0								
Perforr	mance Note: <u>Se</u> mance note on I akers with Meas	Dual Chamber	-up ERI									
100					-							
80) 1		2	3	4	5	6	7	{	3	9	10
	Years After		1		rmal Battery	/ Depletion)·	· Includir	ng Norma	al Battery	Depletio	n
		1 yr	2 yr	3 yr	at 47 mo							
%		100.0	100.0	100.0	100.0							
%		100.0	100.0	100.0	100.0							
#		700	500	300	100							
	Effective San	I. C:										

AT500 AT501, 7253 **Product Characteristics**

S Market Releas	е	Mar-0	3 Malfu	nctions (US)			9	NBG Code		DDDRP
egistered US Im _l	plants	11,00	0 Ther	apy Function N	lot Compromise	d	4	Serial Number Pref	ix	IJF
stimated Active	US Implants	1,60	0 1	Electrical Comp	onent		1	Estimated Longevit	ty	See page
ormal Battery D	epletions (US)	2,41	0 1	Possible Early Ba	attery Depletion		3			
	e: <u>See page 163</u> –		Ther	apy Function C	ompromised		5			
erformance note ystem Follow-Ur	on AT500 Pacing		ı	Electrical Comp	onent		3			
, , , , , , , , , , , , , , , , , , , ,				Electrical Interco	onnect		1			
				Possible Early Ba	attery Depletion		1			
100										
90							<u> </u>			
80										
70										
60										
50										
40										
30										
20										
10						1	•			
0										
0	1	2	3	4	5	6	7	8	9	10
Years A	fter Implant	Exc	luding No	rmal Battery	Depletion	Ir	ncludir	ng Normal Battery	/ Depletion	
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at	80 mo		
%	- 100.0	100.0	100.0	99.9	99.9	99.9		9.9		

84.4

5,500

51.0

2,400

15.1

300

99.8

8,900

99.5

8,200

97.6

7,400

%

99.9

9,700

Effective Sample Size

EnPulse DR E1DR01, E1DR03, E1DR06

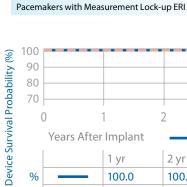
Product Characteristics

0

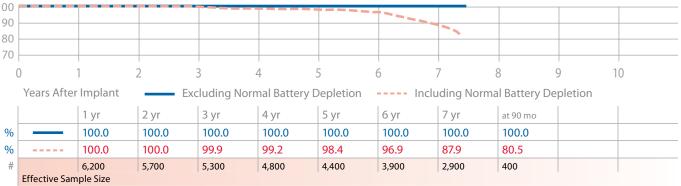
US Market Release	Dec-03
Registered US Implants	7,000
Estimated Active US Implants	3,000
Normal Battery Depletions (US)	319
Performance Note: See page 157 –	

Malfunctions (US)
Therapy Function Not Compromised
Electrical Component
Therapy Function Compromised

NBG Code	DDDR
Serial Number Prefix	PRA, PRB, PRE
Estimated Longevity	See page 78

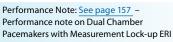


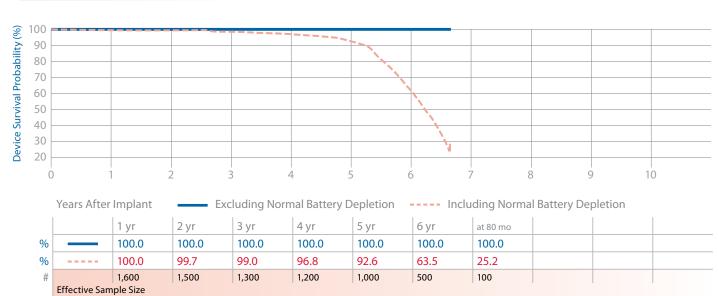
Performance note on Dual Chamber



EnPulse DR E1DR21

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	1,900	Therapy Function Not Compromised	0	Serial Number Prefix	PPT
	,	.,			
Estimated Active US Implants	200	Therapy Function Compromised	0	Estimated Longevity	See page 78
Normal Battery Depletions (US)	323				

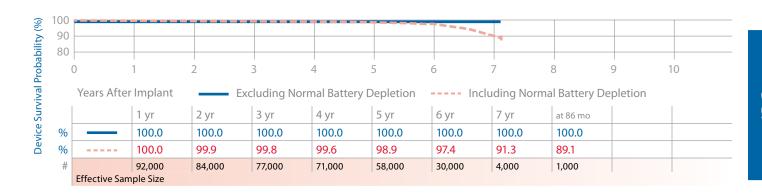






EnPulse 2 DR E2DR01, E2DR03, E2DR06

· · · · ·					
US Market Release	Feb-04	Malfunctions (US)	22	NBG Code	DDDR
Registered US Implants	101,000	Therapy Function Not Compromised	17	Serial Number Prefix	PNB, PNC, PNH
Estimated Active US Implants	59,000	Electrical Component	14		
Normal Battery Depletions (US)	1,122	Electrical Interconnect	1	Estimated Longevity	See page 78
Performance Note: See page 157 –		Possible Early Battery Depletion	2		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Therapy Function Compromised	5		
racemakers with measurement Lock-up En		Battery	1		
		Electrical Component	3		
		Electrical Interconnect	1		



Malfunctions (US)

Therapy Function Not Compromised Therapy Function Compromised Electrical Component

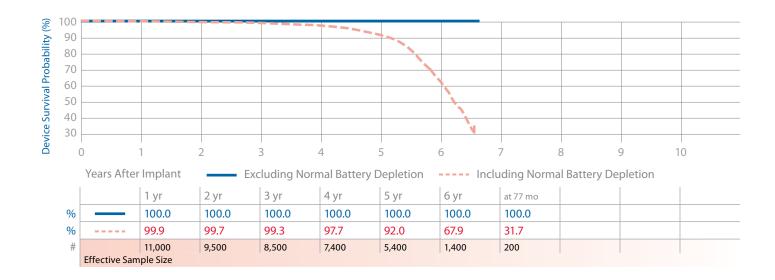
EnPulse 2 DR E2DR21

US Market Release	Feb-04
Registered US Implants	12,000
Estimated Active US Implants	4,500
Normal Battery Depletions (US)	903

Performance Note: <u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Product Characteristics

1	NBG Code	DDDR
0	Serial Number Prefix	PMU
1	Estimated Longevity	See page 78
1		



EnPulse 2 DR E2DR31, E2DR33

Product Characteristics

% % #	Years After	1 yr 100.0 100.0 600	2 yr 100.0 100.0 500	3 yr 100.0 100.0 500	4 yr 100.0 100.0 500	y Depletion 5 yr 100.0 100.0 400	6 yr 100.0 99.2	at 74 100 99.3	2	ery Depletion	n
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 74	1 mo	ery Depletion	n
%	Years After	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 74	ł mo	ery Depletion	n
	Years After						1	1		ery Depletion	n
	Years After	Implant	E	excluding No	ormal Batter	y Depletion	In	cluding	g Normal Batt	ery Depletion	n
(
-	0	1	2	3	4	5	6	7	8	9	10
80											
90											
100							-				
acem	akers with Mea	surement Lock	-ир ЕКІ								
erforr	mance Note: Se	Dual Chamber									
	al Battery Deple			1							
	ited Active US I	•		400 The	erapy Function	Compromised		0	Estimated Long	gevity	See page
	ered US Implan				erapy Function	•		0	Serial Number		PNL, PNM
eaiste	rket Release				functions (US)			0	NBG Code	DDDR	

EnPulse 2 SR E2SR01, E2SR03, E2SR06

Dec-03

Malfunctions (US)

US Market Release

Product Characteristics

SSIR

NBG Code

Registered US Implants	25,0	00 Th e	rapy Function	n Not Compro	mised	3 S	erial Number Prefi	х	PMW, PMY,	
Estimated Active US Implants	10,0	00	Electrical Component			2		PNA		
Normal Battery Depletions (U	5) 3	86	Possible Early Battery Depletion			1 E	stimated Longevit	У	See page	
Advisories	No	ne The	rapy Function	n Compromise	d	1				
			Other			1				
100										
90										
80										
70										
0 1	7	3	4	5	6	7	8	9	10	
0 1	2	5	7	J	O	/	0	9	10	
Years After Impla	nt — E>	cluding No	ormal Batte	ry Depletio	n Ir	ncluding I	Normal Battery	Depletion	I	
1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 86 mo			
% 100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0			

97.8

10,000

94.2

4,000

82.0

500

100.0

21,000

Effective Sample Size

99.9

18,000

99.5

16,000

98.9

14,000

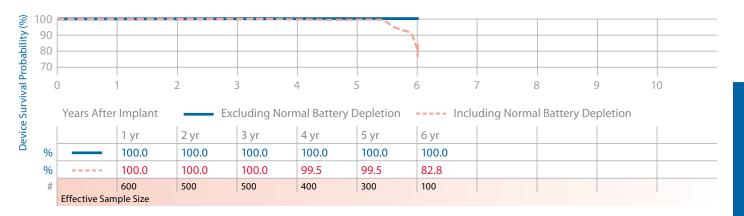


EnPulse 2 VDD E2VDD01

Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Product Characteristics

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	600	Therapy Function Not Compromised	0	Serial Number Prefix	PMV
Estimated Active US Implants	300	Therapy Function Compromised	0	Estimated Longevity	See page 78
Normal Battery Depletions (US)	28				
Performance Note: See page 157 –					

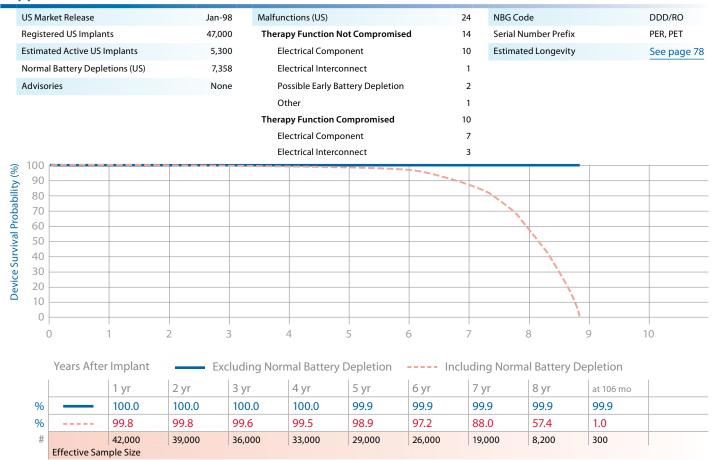


EnRhythm DR P1501DR

US Market Release		May	-05 N	Malfunctions (US)			1,055	NBG Code	DDDRP
Registered US Implants		108,0	000	Therapy Function	Not Comprom	ised	1,009	Serial Number Prefix	PNP
Estimated Active US Imp	lants	81,0	000	Battery (112	malfunctions re	lated to advisor	ry) 967	Estimated Longevity	See page 7
Normal Battery Depletio	ns (US)		113	Electrical Co to advisory)	omponent (1 ma	alfunction relate	ed 19		
Advisories: See page 1 Voltage Displayed at De				Possible Ear related to ac	ly Battery Depl Ivisory)	etion (1 malfun	ction 22	!	
				Electrical In	terconnect		1		
Performance Note: See p Anomalies in MOSFET In				Therapy Function	Compromised		46	j	
Circuit Technology	tegrateu			Battery			5	j	
				Electrical Co	mponent		36	j	
				Electrical In	terconnect		3	1	
				Possible Ear	ly Battery Depl	etion	2	2	
100									
90						-			
80									
0 1		2	3	4	5	6	7	8 9	10
Years After In	nplant	E	xcluding	Normal Batter	y Depletion	Ir	cluding Norma	al Battery Depletion	
1	yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 73 mo		
	00.0	100.0	99.9	99.8	98.1	95.6	95.2		
	00.0	99.9	99.8	99.4	95.8	89.7	86.7		
% 1	00.0								
	2,000	75,000	59,000	44,000	26,000	1,500	500		

Kappa 400 DR KDR401, KDR403

Product Characteristics



Kappa 400 SR KSR401, KSR403

JS Market	Release		Fe	b-98 M	alfunctions (US)			5 NB	G Code		SSIR
Registered	US Implant:	s	15	,000 T	herapy Function	Not Comprom	ised	4 Serial Number Prefix			PEU, PGD
stimated.	Active US Im	plants	1	,900	Electrical Com	ponent		3 Est	imated Longevit	y	See page
Normal Ba	tery Deplet	ions (US)	1	,368	Possible Early	Battery Depleti	on	1			ee page 70
Advisories	, .		N	lone T	herapy Function	Compromised	I	1			
					Electrical Inter	•		1			
100					z.eet.rear.inter						
90											
80 —											
70 —											
60											
50											
40											
30 —											
20 —											
10											
0											
0	1		2	3	4	5	6	7	8	9	10
Ye	ars After	Implant		Excluding I	Normal Batter	y Depletion	In	cluding No	ormal Battery	Depletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	
%		99.8	99.7	99.5	99.1	98.6	96.9	90.8	64.6	17.4	
#		13,000	11,000	9,800	8,500	7,200	5,900	4,400	2,000	200	

Jan-99

25,000

2,000

3,759



US Market Release

%

99.9

21,000

Effective Sample Size

99.8

19,000

99.8

17,000

99.5

15,000

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Performance Note: See page 157 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

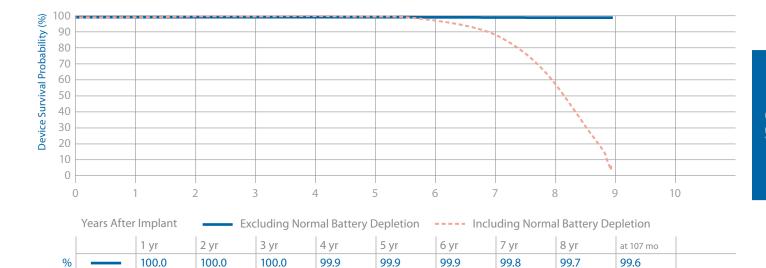
Advisories: See page 155 – 2002 Potential Fractured Power Supply Wires; See also page 149 - 2009 Potential Separation of Interconnect Wires

Kappa 600 DR KDR601, KDR603, KDR606

Malfunctions (US)	63
Therapy Function Not Compromised	5
Electrical Component	4
Other	1
Therapy Function Compromised	58
Electrical Component	3
Electrical Interconnect (34 malfunctions related to advisory)	55

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PHF, PHH, PHG
Estimated Longevity	See page 78



98.8

13,000

96.9

12,000

87.8

8,800

57.6

4,100

5.2

200

Kappa 600 DR KDR651, KDR653

JS Market Relea		Mar		lfunctions (US)			56	NBG Cod			DDD/RO
Registered US Implants		16,0		Therapy Function Not Compromised		sed	3		ımber Prefix		PLJ, PLK
stimated Activ	· ·	1,5	500	Electrical Com	ponent		1	Estimate	d Longevity		See page 7
Normal Battery Depletions (US) Advisories: See page 155 - 2002 Potential			533	Possible Early Battery Depletion		n	2				
			Therapy Function Compromised				53				
	r Supply Wires; See			Electrical Com	ponent		1				
page 149 – 2009 Potential Separation of Interconnect Wires			Electrical Interconnect (30 malfunctions related to advisory)				52				
	ote: <u>See page 157</u> – te on Dual Chambe			(30 mananenoi	is related to davis	iory)					
acemakers with	n Measurement Loc										
100			T								
80											
70											
60											
50											
40											
30									\		
20									1		
10									1		
0									*		
0	1	2	3	4	5	6	7	8	3	9	10
Years	After Implant	F	xcludina N	lormal Batter	v Depletion	1	ncludir	ng Norma	al Battery D	enletion	
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7)		8 yr	at 103 mo	
%	1 00.0	100.0	100.0	100.0	100.0	99.9	99		99.5	99.4	
%	4000	99.9	99.8	99.4	98.2	94.9	81		43.8	6.3	
#	13,000	11,000	10,000	9,200	8,100	7,000		000	1,800	200	
	e Sample Size	11,000	10,000	9,200	0,100	7,000	7 3,0		1,000	200	

Jan-99

300 70 17

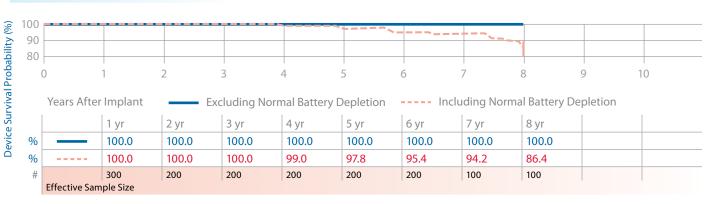


Kappa 700 D KD701, KD703, KD706

US Market Release

Malfunctions (US)	0	NBG Code	DDD
Therapy Function Not Compromised	0	Serial Number Prefix	PHK, PHM, PHL
Therapy Function Compromised	0	Estimated Longevity	See page 79

Registered US Implants
Estimated Active US Implants
Normal Battery Depletions (US)
Advisories: See page 155 – 2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires
Performance Note: <u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI



Jan-99

206,000

34,000

30,156

US Market Release

Interconnect Wires

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Performance Note: See page 157 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Effective Sample Size

Advisories: See page 155 – 2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of

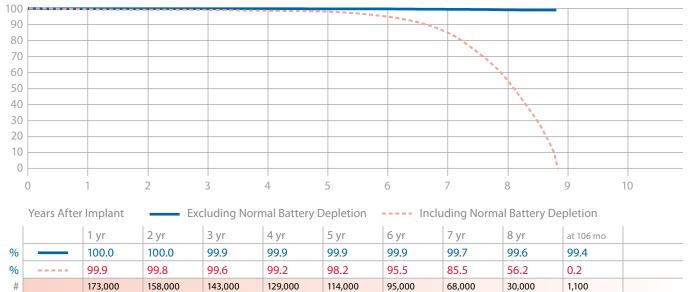
Kappa 700 DR KDR701, KDR703, KDR706

Malfunctions (US)	736
Therapy Function Not Compromised	37
Battery	1
Electrical Component	27
Electrical Interconnect	2
Possible Early Battery Depletion	4
Other	3
Therapy Function Compromised	699
Electrical Component	17
Electrical Interconnect (414 malfunctions related to advisory)	681
Possible Early Battery Depletion	1

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PGU, PGY, PGW
Estimated Longevity	See page 79





95,000

Feb-99

9,800

800

1,330



Kappa 700 DR KDR721

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

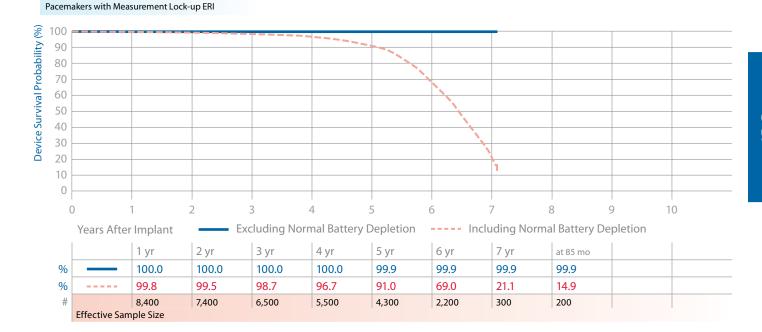
Advisories: See page 155 – 2002 Potential

Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires Performance Note: See page 157 -Performance note on Dual Chamber

US Market Release

Malfunctions (US)	5
Therapy Function Not Compromised	1
Electrical Component	1
Therapy Function Compromised	4
Electrical Interconnect (4 malfunctions related to advisory)	4

NBG Code	DDD/RO
Serial Number Prefix	PGR
Estimated Longevity	See page 79



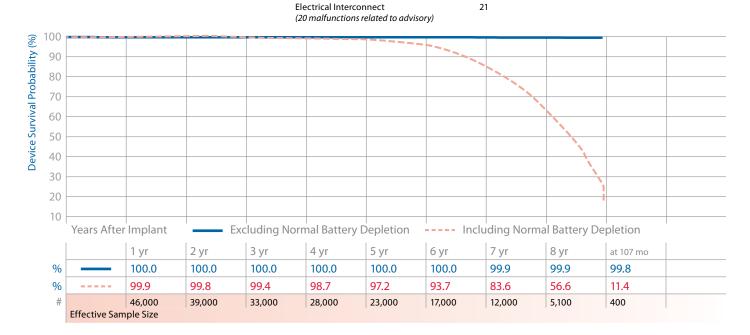


Kappa 700 SR KSR701, KSR703, KSR706

US Market Release	Jan-99	Malfunctions (US)
Registered US Implants	55,000	Therapy Function Not Compromise
Estimated Active US Implants	7,700	Electrical Component
Normal Battery Depletions (US)	4,500	Possible Early Battery Depletion
Advisories: See page 149 – 2009 Potential		Therapy Function Compromised
Separation of Interconnect Wires		Electrical Component
		Electrical Interconnect

Product Characteristics

NBG Code	SSIR
Serial Number Prefix	PHT, PHW, PHU
Estimated Longevity	See page 79



na 700 VDD KVDD701

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Rappa 700 VDD KVDD701				Product Characteristics	
US Market Release	Jan-99	Malfunctions (US)	4	NBG Code	VDD/RO
Registered US Implants	1,700	Therapy Function Not Compromised	0	Serial Number Prefix	PHP
Estimated Active US Implants	200	Therapy Function Compromised	4	Estimated Longevity	See page 79
Normal Battery Depletions (US)	171	Electrical Interconnect	4		
Advisories: See page 155 – 2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires Performance Note: See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		(4 malfunctions related to advisory)			
100					
3 90					
€ 80		•			
Q 70					
g 60					
le 50					
40					
iee Survival Probability (%) 80 70 60 40 30					

()	1	2 3	3 4	4 !	5	6	7	3 9	9 1	10
	Years After	Implant	Exc	luding Norn	nal Battery [Depletion	Inclu	ıding Norma	al Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 97 mo	
%		99.9	99.9	99.9	99.8	99.8	99.6	99.6	99.6	99.6	
%		99.8	99.8	99.3	98.7	98.5	94.2	72.8	42.1	41.3	
#		1,500	1,300	1,200	1,000	1,000	800	400	100	100	
	Effective Sample Size										



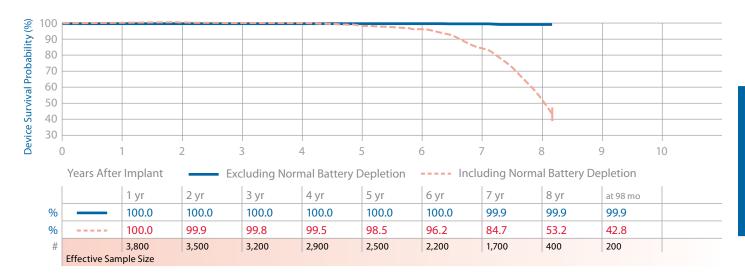
Kappa 800 DR KDR801, KDR803

US Market Release	Jan-02
Registered US Implants	4,300
Estimated Active US Implants	1,100
Normal Battery Depletions (US)	474

Performance Note: <u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Product Characteristics

Malfunctions (US)	3	NBG Code	DDD/RO
Therapy Function Not Compromised	0	Serial Number Prefix	PKW, PKY
Therapy Function Compromised	3	Estimated Longevity	See page 79
Electrical Interconnect	3		



Kappa 900 DR KDR901, KDR903, KDR906

S Mark	et Release		Jan	02	Malfund	ctions (US)			72	NBG Co	de		DDR/RO
egister	ed US Implan	ts	125,0	00	Thera	py Function N	lot Compromis	sed	19	Serial N	umber Prefix		PKM, PKN, PKP
timate	d Active US I	mplants	45,0	00	Ele	ectrical Comp	onent		17				
ormal E	Battery Deple	etions (US)	10,5	541	Ele	ectrical Interco	onnect		1	Estimate	ed Longevity		See page 79
	nce Note: See				Ot	her			1				
		Dual Chamber urement Lock-u	ın EDI		Thera	py Function C	Compromised		53				
еттак.	ers with Meas	urement Lock-t	ір скі		Ele	ectrical Comp	onent		9				
					Ele	ectrical Interco	onnect		44				
100 =													
90 –													
80 -									1				
70 –													
50 –													
50 –											1		
40 –											1		
30 -											1		
20 –											i i		
10 –													
0													
0		1	2	3	4	4	5	6	7		8	9	10
,	Vaava Aftava	فمرما مرسف	Г.		NI	I D-44	D +	l so	مانامانام	a. Na was	al Dattami C	\ambatian	
	Years After				ig ivorn	nal Battery					al Battery D	epietion	
		1 yr	2 yr	3 yr		4 yr	5 yr	6 yr	7 y	/r	8 yr	at 101 mo	
%		100.0	100.0	100.	0	100.0	100.0	100.0	99	.9	99.9	99.9	
%		100.0	99.9	99.8		99.4	98.6	96.5	87.	.7	57.2	18.2	
#		113,000	103,000	94,00	00	86,000	75,000	59,000	40,	000	11,000	900	
E	Effective Sam	iple Size											

Device Survival Probability (%)

US Market Release

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Advisories: See page 149 – 2009
Potential Separation of Interconnect Wires

Kappa 900 SR KSR901, KSR903, KSR906

Malfunctions (US) 37,000 **Therapy Function Not Compromised** 9,500 **Electrical Component** 1,844 Electrical Interconnect (1 malfunction related to advisory) Possible Early Battery Depletion **Therapy Function Compromised** Electrical Interconnect (7 malfunctions related to advisory)

Product Characteristics

17	NBG Code		SSIR
9	Serial Number Prefix	(PLF, PLG, PLH
7			
1	Estimated Longevity	1	See page 79
1			
8			
8			
•			
	\ \ \ \ \		
	1		
			1.0
/	8	9	10

()	1	2 3	3 4	1 5	5	6	7 8	3 9)	10
	Years After	Implant	Exc	luding Norn	nal Battery D	Depletion	Inclu	iding Norma	l Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo	
%		100.0	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	
%		99.9	99.8	99.6	98.9	97.5	94.5	83.9	49.4	25.2	
#		30,000	26,000	22,000	19,000	15,000	10,000	6,000	1,100	200	
	Effective Sam	nple Size									

Kappa 900 VDD KVDD901

US Mar	The properties of the proper											
Registe	ered US Implant	S	60	0 Thera	py Function No	ot Compromise	ed	2	Serial Nu	ımber Prefix		PLE
Estimat	ted Active US Im	nplants	9	0 So	oftware/Firmwa	are Malfunction	1	1	Estimate	d Longevity		See page 79
Normal	l Battery Deplet	tions (US)	7	9 0	ther			1				
			Wires	Thera	py Function Co	ompromised		0				
Perforn	nance note on D	Dual Chamber										
8	akers with Meas	urement Lock-	up ERI									
<u>2</u> 100												
90 g												
g 80												
a 70							<u> </u>	-				
≥ 60 k												
Ins 50							\					
Device Survival Probability 00 00 00 00 00 00 00 00 00) 1		2 :	3	4	5	6	7	8	3	9	10
۵	Years After	Implant	Exc	cluding Nor	mal Battery I	Depletion	Incl	udin	g Norma	al Battery D	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 8	3 mo			
%		100.0	100.0	100.0	100.0	100.0	99.6	99.	.6			
%		100.0	100.0	100.0	99.0	97.9	90.7	54.	.7			
#		600	500	400	400	300	300	100)			
	Effective Samp	ple Size				,					'	,

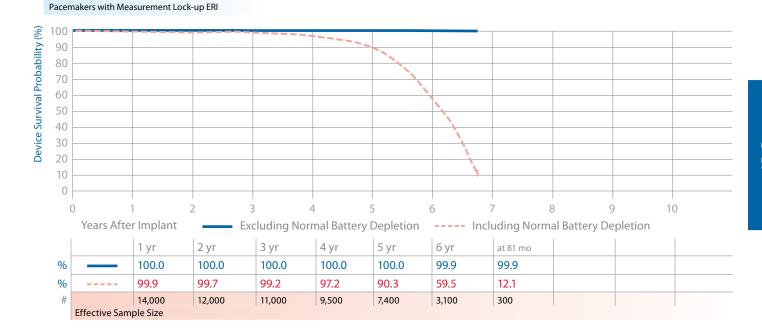


Kappa 900 DR KDR921

Performance Note: <u>See page 157</u> – Performance note on Dual Chamber

Product Characteristics

I I I I I I I I I I I I I I I I I I I					
US Market Release	Jan-02	Malfunctions (US)	4	NBG Code	DDD/RO
Registered US Implants	16,000	Therapy Function Not Compromised	1	Serial Number Prefix	PKR
Estimated Active US Implants	2,200	Electrical Component	1		
Normal Battery Depletions (US)	2,493	Therapy Function Compromised	3	Estimated Longevity	See page 79
Advisories: See page 149 – 2009 Potential Separation of Interconnect Wires		Electrical Interconnect (3 malfunctions related to advisory)	3		



Legend II 8424, 8426, 8427

US Mar	ket Rel	ease				Nov-9	91	Malfun	ctions (l	JS)				3	5 1	NBG Cod	de				SSIRO	
Registe	ered US	Implan	ts			59,00	0	Thera	py Func	tion No	t Comp	romise	d	2	4 9	Serial Nu	ımber F	refix			2P, 2T,	2U
Estima	ted Act	ive US Ir	mplants	i		5,90	0	Ва	ttery M	alfuncti	on				2 E	Estimate	ed Long	evity			See p	age
Norma	l Batter	y Deple	tions (U	IS)		2,56	57	Ele	ectrical	Compo	nent			1	8							
Adviso	ries					Non	ie	Po	ssible E	arly Bat	tery De	pletion			4							
								Thera	py Fund	tion Co	mprom	ised		1	1							
								Ele	ectrical	Compo	nent				9							
								Ele	ectrical	Interco	nnect				2							
100																						
90																						-
80 -																						
70																						
60																						
50 -																		7				
40																						-
0	1	2	. 3	4	- 5	6	7	8	9) 1(0 1	1 12	2 13	3 14	1 1:	5 10	5 1	7 18	8 19	20) 2	1
	Years	s After	Impla	nt		E xc	cludin	g Norr	nal Ba	ttery [Deplet	ion		Inclu	uding	Norma	al Batt	ery De	pletion	n		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	at 212 n	no		
%		100.0	-		-	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9			
%		99.9	99.7	99.5	99.2	98.9	98.2	97.3	94.8	91.6	88.7	85.5	82.2	77.2	71.0	64.5	58.4	52.7	46.4			
#											13,000		-	6,400	4,900	3,800	2,700	1,300	200			
	Effecti	ve Sam	ple Size	2																		



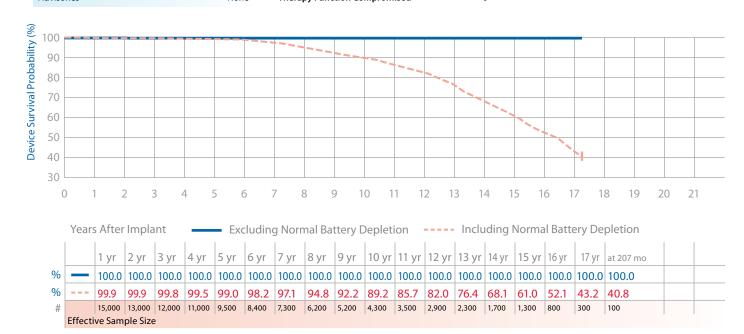
Minix/Minix ST 8340, 8341, 8341M, 8342, 8330, 8331, 8331M

Product Characteristics

	rket Rel	ease				Nov	-88	Malfu	unctio	ns (US)					50) N	NBG Co	de				SSICO,	VVICO
egiste	ered US	Implan	ts			59,0	000	The	rapy F	unctio	n Not (Compr	omise	d	15		erial N	umber	Prefix				
stimaf	Anket Release		See pa	ge 79																			
lorma	l Batter	y Deple	tions (U	IS)		1,	741		Batter	y Malf	unctior	1			1								
					tential	Delaye	d		Possib	le Earl	y Batte	ry Dep	letion		1								
estora	Market Release Nov-88 59,000 Therapy Function Not Compromised 15 Serial Number Prefix UQ, US, UU, UV, UV, UV, UV, UV, UV, UV, UV, UV																						
									Elect	trical C	ompon	ent			32								
									Elect	trical Ir	ntercon	nect			1								
									Batte	ery Ma	lfunctio	n			1								
									Othe	er					1								
100 -																							
90 -																							
80																							
70																						1	
60																							
) 1	1 2	2 3	3	4	5	6	7	8	9	10	11	1.	2 1	3	14	15	16	17	18	19	20	21
C		Δftor	· Impla	nt		<u> —</u> Е	kcludi	na Na	rmal	Batte	erv De	pletio	on		Incl	udino	ı Norr	nal Ba	atterv	Deple	etion		
С	Years													ı									
C	Years															4.5	10	17	10 .//	10			
C	Years		2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	10 yr	17 yr	10 91	19 yr	20 yr	at 242 mo	
%	Years	1 yr																					
	_	1 yr	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	

Minuet 7107, 7108 **Product Characteristics**

US Market Release	Mar-92	Malfunctions (US)	3	NBG Code	DDDCO
Registered US Implants	17,000	Therapy Function Not Compromised	3	Serial Number Prefix	1Z1, 2G1
Estimated Active US Implants	2,000	Electrical Component	2	Estimated Longevity	See page 79
Normal Battery Depletions (US)	950	Possible Early Battery Depletion	1		
Advisories	None	Therapy Function Compromised	0		





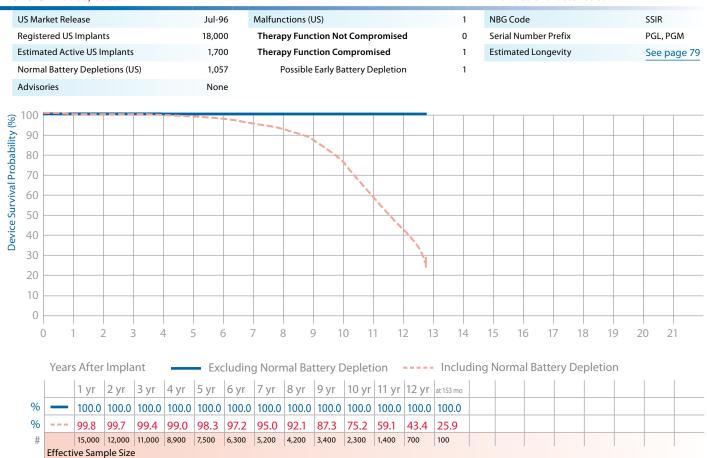
Effective Sample Size

S Ma	irket	Rele	ase				Jul-9	6	Malfund	ctions (l	JS)				4	NBG C	ode					DDD/I	RO
gist	tered	l US I	mplan	ts			26,00	0	Thera	y Func	tion No	t Comp	romise	d	0	Serial	Numbe	r Prefix				PGJ, P	'GK
tima	ated .	Activ	e US I	mplants	5		2,60	0	Thera	y Func	tion Co	mprom	ised		4	Estim	ated Lor	ngevity	,			See p	age 7
orm	al Bat	ttery	Deple	tions (L	JS)		2,80	7	Е	lectrica	l Comp	onent			2								
dvis	ories						Non	e	E	lectrica	l Interco	onnect			2								
00																							
90																							
80																							
70																							_
60												1										-	_
50												1											
40												``											-
30													<u> </u>										-
20													<u> </u>										-
10													\										_
0																							-
	0	1		2 :	3	4 5	5 6	5 7	7 8	3 9) 1	0 1	1 1	2 1	3 14	15	16	17	18	1	9 2	20 2	21
	Ye	ears	After	Impla	ant		Exc	ludin	a Norn	nal Ba	tterv D	Depleti	on		Includin	ıg Norr	nal Ba	ttery l	Dep	letio	n		
		1		2 yr	3 yr	4 yr		6 yr			,				at 145 mo				ĺ				
%		-		100.0	-	100.0	-	-	-	-	-			-									+

--- 99.8 99.8 99.5 99.3 98.7 97.7 96.2 92.4 84.5 66.5 41.8 12.8 8.0 **22,000 20,000 18,000 16,000 14,000 12,000 11,000 8,900 6,900 4,300 2,000 200**

Preva SR 8088, 8089

Product Characteristics



Prevail S 8085, 8086

IC Mari	des Dele					0-4.0	\r	Malfina	-+: <i>(</i>	LIC)					1	NIDC C	1-				SSI	
	ket Rele					Oct-9			ctions (NBG Cod						
-		Implan				4,20					ot Comp		d			Serial Nu					PE	Y, PFA
Estimat	ted Acti	ive US II	mplants	5		50	00	Thera	py Fund	ction Co	mprom	nised			1	Estimate	d Long	evity			Se	e page 7
Normal	l Batter	y Deple	tions (L	JS)		5	55		Electrica	al Comp	onent				1							
Adviso	ries					Nor	ie															
100																						
100																						
90																					_	
80															1							
70																						
0	1	2) :	3 4	1 5	5 (5 7	7 {	3 9	9 1	0 1	1 1	2 1	3 1	4 1	5 1	6 1	7	18	19	20	21
	Years	After	Impla	ant		- Ex	cludin	g Norr	mal Ba	ttery [Deplet	ion		Inclu	uding	Norma	ıl Batt	ery D	eplet	ion		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 169 m						
%		100.0	100.0	100.0			99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9						
%		99.7	99.6		99.6	99.1	98.9	97.9	96.8	95.2	92.8	90.1	89.3	86.8	85.2	85.2						
#				2,100	1,700	1,300	1,100	900	800	700	600	500	400	300	100	100						
			ple Size														1		1			1

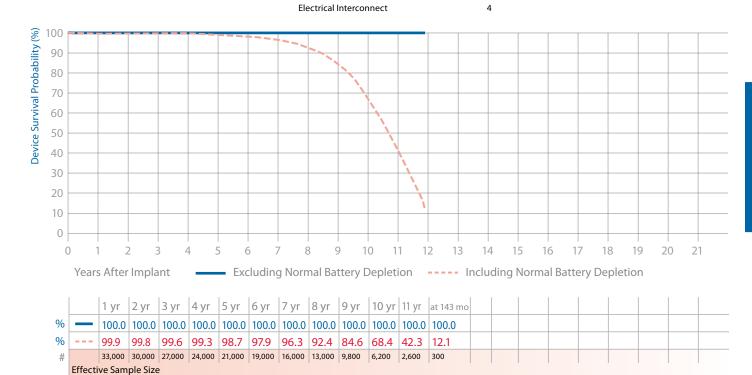


Prodigy DR 7860, 7861, 7862

37		
US Market Release	Oct-95	Malfunctions (US)
Registered US Implants	37,000	Therapy Function Not Compromised
Estimated Active US Implants	3,400	Electrical Component
Normal Battery Depletions (US)	3,831	Possible Early Battery Depletion
Advisories	None	Other
		Therapy Function Compromised

Product Characteristics

11	NBG Code	DDD/RO
5	Serial Number Prefix	PDH, PDJ, PDK
2		
2	Estimated Longevity	See page 80
1		
6		
2		



Electrical Component

Prodiav SR 8158, 8160, 8161, 8162

Product Characteristics

ııy,	y JN	0130,	, 6160,	8161,	8102										P	roduc	l Clia	racte	ristic	5		
Mar	ket Rel	ease				Oct-9	5	Malfund	tions (l	JS)				4	N	BG Cod	e				SSIF	R
giste	ered US	Implant	ts			22,00	0	Therap	y Func	tion No	t Comp	romise	d	2	Se	erial Nu	mber f	refix				I, PED, PE
Estimated Active US Implants						2,50	0	Ba ⁻ Po	1 1							PEF	FLF					
rma	l Batter	y Deple	tions (U	S)		1,29	2	Therap	y Func	tion Co	mprom	ised		2	Es	timate	d Long	evity			See	page 8
lviso	ries					Non	e	Ele	ctrical (Compor	nent			1								
								Ele	ectrical I	ntercon	nect			1								
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90																						
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C		l 2	2 3		1 5			7 8						3 14	15				18	19	20	21
	Years	s After	Impla	nt		- Exc	luding	g Norn	nal Ba	ttery D)epleti	ion		Includi	ng N	lorma	l Batt	ery D	eplet	ion		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 152 mo								
%	_	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0								
%		99.7	99.6	99.2	98.7	97.8	96.5	94.8	91.6	86.1	74.3	60.0	44.8	30.7								
#		19,000	16,000	14,000	12,000	9,700	8,100	6,600	5,400	4,100	2,800	1,700	700	100								

Sensia DR SEDROL SEDOL

Effective Sample Size

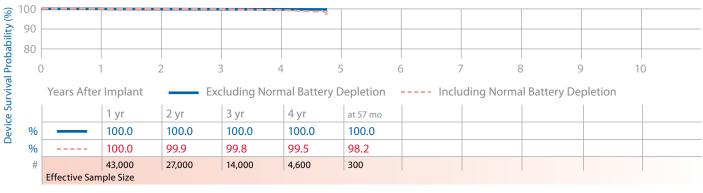
US Market Release		Ju	ıl-06 Ma	alfunctions (US)			10	NBG Code		DDD, DDDR		
Registered US Implar	nts	95	,000 TI	herapy Function	Not Compromis	ed	6	Serial Number	PWL, PWK,			
stimated Active US	mplants	75	,000	Electrical Com	ponent		6			NWL, NWK		
Normal Battery Depl	etions (US)		52 T I	herapy Function	Compromised		4	Estimated Lon	gevity	See page		
Performance Note: <u>S</u>	ee page 157 –			Electrical Com	ponent		3					
Performance note on Pacemakers with Mea				Electrical Inter	connect		1					
100												
100												
90												
90	1	2	3	4	5	6	7	8	9	10		
90 80	1						7					
90	1 r Implant			4 Normal Batter		6	7	8 ng Normal Bat				
90 80	1 r Implant 1 yr						7					
90 80			Excluding N	Normal Batter	y Depletion		7 Includir					
90 80 0 Years Afte	1 yr	2 yr	Excluding N	Normal Batter	y Depletion at 58 mo		7 Includir					



Sensia SR SESR01, SES01

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	4	NBG Code	SSIR, SSI		
Registered US Implants	63,000	Therapy Function Not Compromised	3	Serial Number Prefix	PWR, PWS,		
Estimated Active US Implants	45,000	Electrical Component	3		NWR, NWS		
Normal Battery Depletions (US)	41	Therapy Function Compromised	1	Estimated Longevity	See page 80		
Advisories	None	Electrical Interconnect	1				



Sigma 100 S SS103, SS106

Effective Sample Size

Data as of July 31, 2011

US M	arket Release		Aug-9	9 Malfun	ctions (US)			0	NBG Code	e		SSI
Regis	tered US Implan	ts	80	0 Thera	py Function No	t Compromise	d	0	Serial Nu	mber Prefix		PJG, PJH
Estim	ated Active US Ir	mplants	10	0 Thera	py Function Co	mpromised		0	Estimated	Longevity		See page 80
Norm	al Battery Deple	tions (US)	1	7								
	sories: See page ration of Intercor		tential									
_© 100										_	T	
<u>©</u> 90							`			1		
abolii 80												
Device Survival Probability (%)	1		1 2 3	3	4 5	5 (5	7	8	(9	10
vival	Years After	Implant	Exc	luding Nor	mal Battery [Depletion	Incl	uding	g Norma	Battery De	pletion	
Sul		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yı	r	8 yr	at 98 mo	
.ĕ. %		100.0	100.0	100.0	100.0	100.0	100.0	100	0.0	100.0	100.0	
å %		100.0	100.0	99.5	99.5	98.7	98.7	96.	5	93.6	93.6	
#	±	600	500	400	300	200	200	200		100	100	



Sigma 200 DR SDR203

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

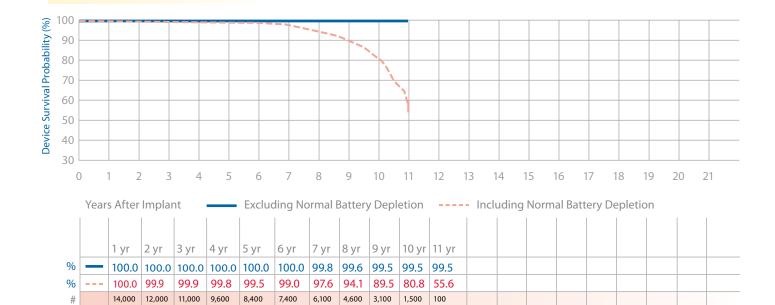
Advisories: See page 153 – 2005 Potential Separation of Interconnect Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires

US Market Release

Aug-99	Malfunctions (US)	31
16,000	Therapy Function Not Compromised	1
4,300	Electrical Component	1
475	Therapy Function Compromised	30
	Electrical Component	1
	Electrical Interconnect (19 malfunctions related to advisory)	29

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PJD
Estimated Longevity	See page 80



Sigma 200 SR SSR203

Effective Sample Size

Product Characteristics

<u> </u>	nu z	200 .	JI 3.	311203													Todu	ct Cité	aracte	2113410	-3		
ι	JS Mar	rket Rel	ease				Sep-99) N	1alfunct	ions (US	S)				11	1	NBG Co	de				SS	IR
R	legiste	ered US	Implan	ts			12,000) .	Therapy	y Functi	ion Not	Compr	omised		0	9	Serial N	umber	Prefix			PJ	G
E	Estimated Active US Implants						2,300)	Therapy	y Functi	ion Com	promis	ed		11	ı	Estimated Longevity						e page 80
Ν	Normal Battery Depletions (US)					225	5		trical In	·)	11												
S	epara page 1	tion of	Intercor	e 153 – 2 nnect Wi ential Se	res; <u>See</u>	also																	
(%)	100								-														
ty (9	90																						
abilli	80										``\												
rob	70																						
alP												Y											
Device Survival Probability (%)	60) 1	1 2	2 3	4	5	6	7	8	9	10	11	12	. 13	14	1	5 1	6	17	18	19	20	21
)evice		Years	s After	Impla	nt		E xc	luding	Norm	al Batt	tery De	epletic	on -		Includ	ling	Norma	al Batt	tery [Deple	tion		
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 133 mo									
	%	_	100.0	100.0	100.0	100.0	99.9	99.9	99.8	99.8	99.7	99.7	99.7	99.7									
	%		99.9	99.9	99.8	99.7	99.2	98.6	97.1	95.2	91.3	84.0	69.7	63.1									
	#		9,600	7,900	6,700	5,600	4,700	4,000	3,200	2,400	1,600	900	200	100									

Effective Sample Size

Sigma 300 DR SDR303, SDR306

Product Characteristics

	Effecti	ve Sam	ple Size																				
#		92,000	82,000	73,000	64,000	54,000	43,000	32,000	22,000	13,000	6,000	300											
%		100.0	99.9	99.9	99.7	99.4	98.9	97.9	95.1	90.3	81.6	51.6											
%	_	100.0	100.0	100.0	99.9	99.9	99.9	99.8	99.6	99.5	99.5	99.5											
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr											
	Years	After	Impla	nt		E xc	luding	Norm	nal Bat	tery De	epletio	n -		Includ	ding	Norn	nal Ba	ittery	Deple	tion			
	0	1	2	3	4	5	6	7	8	9 1	0 1	1 12	2 1	3 1	4	15	16	17	18	19	20	2	21
40																							-
50																							-
60																							H
70																							\vdash
80																							H
90																							H
100			T																				Г
										nterconn nctions re		advisory	<i>(</i>)	184									
	nnect \		entiai se	paratio	1101			Ele	ctrical C	ompone	ent			8									
			nect Wi					Therap	y Funct	ion Com	promis	ed		192									
			· • 153 – 2		tential			Pos	ssible Ea	ırly Batte	ery Depl	etion		1									
			tions (U	S)		1,982				nterconn				2		250						.c pu	عر
_		ive US Ir				37,000			•	Compone	•	Jilliseu		5				ngevity				ee pa	
		ease Implant	t c			107,000			•	ion Not	Compre	micad		200				er Prefix				D, PJE	
	ket Rel					Aug-99	, ,	10 If	tions (U	C)				200		NBG C	ada				D.	DD/RC	`

Sigma 300 SR SSR303, SSR306

Product Characteristics

US Market Release	Aug-99	Malfun	nctions	(US)				45	NBG	Code						SSIR	
Registered US Implants	54,000	Thera	apy Fun	ction	Not Con	npromise	ed	3	Seria	l Num	ber P	refix				PJG, P.	JH
Estimated Active US Implants	13,000	El	lectrical	Comp	onent			1	Estin	nated	Longe	evity				See p	age 8
Normal Battery Depletions (US)	713	El	lectrical	Interd	onnect			1									
Advisories: See page 153 – 2005 Potential		0	Other					1									
Separation of Interconnect Wires; See also		Thera	apy Fun	ction	Compro	mised		42									
page 149 – 2009 Potential Separation of Interconnect Wires		El	lectrical	Comp	onent			3									
			lectrical			l to adviso	orv)	39									
100																	
90																	
80																	
70						'n											
60			1	1	10	11	10 10		4.5		-		10	10			1
0 1 2 3 4	5 6	-		9	10	11	12 13	14	15	16	1.	/	18	19	20) 2	21
Years After Implant	Exclud	ing Nori	mal Ba	attery	/ Deple	etion	Ir	ncludi	ng Nor	mal I	Batte	ery D	eple	tion			1
1 yr 2 yr 3 yr 4 yr	r 5 yr	6 yr 7	yr 8	3 yr	9 yr	10 yr	at 131 mo										
% — 100.0 100.0 100.0 100		-	_	99.7	99.7	99.7	99.7										
% 100.0 99.9 99.8 99.0 %				94.8	90.2	81.9	62.3						+				
# 43,000 36,000 30,000 25,0		15,000 11		7,200	4,200	1,900	200										
Effective Sample Size		, /	,,,,,		,	,											

Product Characteristics

JS Mar	ket Release		Sep	-99 Ma	Ifunctions (US)			1	NBG Cod	le		VDDD
Registe	ered US Implan	ts		500 T h	erapy Function N	ot Compromise	ed	0	Serial Nu	mber Prefix		PJD
stimat	ted Active US I	mplants	1	100 Th	erapy Function Co	ompromised		1	Estimate	d Longevity		See page 8
Normal	l Battery Deple	etions (US)		41	Electrical Interco	nnect		1				_
	ries: See pag	<u>e 153</u> – 2005 P nnect Wires	otential		(1 malfunction re	lated to advisory	<i>ı</i>)					
00												
90									`~			
80												
70												
50												
50												
	0	1	2	3	4	5	6	7		8	9	10
	Years After	Implant	Ex		lormal Battery	Depletion	Inc	ludin	g Norma	l Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7	yr	8 yr	at 105 mo	
%		100.0	100.0	100.0	100.0	100.0	100.0	10	0.00	99.5	99.5	
%		100.0	100.0	100.0	100.0	99.4	98.1		4.1	89.4	77.0	
#		500	500	400	400	300	300	20	00	200	100	

Thera-i DR 7960i, 7961i, 7962i

Product Characteristics

US Ma	rket Re	lease				Oct-9)5	Malfun	ctions (l	US)				49	NBG Co	ode					DDD/F	RO
Registe	ered US	5 Implar	its			121,00	0	Thera	py Func	tion No	ot Comp	oromise	d	23	Serial N	lumbe	r Prefix	<			PDB, P	DC,
Estima	ted Ac	tive US I	mplants	i		11,00	0	Ва	attery N	lalfunct	ion			3							PDD	
Norma	l Batte	ry Deple	etions (U	IS)		13,71	2	Ele	ectrical	Interco	nnect			1	Estima	ted Lor	ngevity	y			See pa	age 80
Adviso	ries					Non	ie	Ele	ectrical	Compo	nent			7								
								Po	ssible E	arly Bat	tery De	pletion		9								
									her					3								
											mprom	nised		26								
									ectrical					20								
								Ele	ectrical	Compo	nent			6								
100									-				_									
80																						
60																						
40												**										
20												•	1									
0													1									
0	1	1 2	2 3	4	. 5	6	7	' 8	9) 1(0 1	1 1	2 13	3 14	15	16	17	18	19	20) 2	1
	Year	s Afte	r Impla	nt		E xc	cluding	g Norr	nal Ba	ttery [Deplet	ion		- Includin	g Norm	al Ba	ttery	Dep	letion	1		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 147 mo								
%		100.0	100.0	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9								
%		99.9	99.8	99.6	99.4	99.0	98.1	96.7	93.2	85.8	71.3	48.2	19.2	3.3								
#		109,000												300								



Thera-i SR 8960i, 8961i, 8962i

Product Characteristics

cra	1.	אכ	89601,	8961i	, 8902	41											Produ	ct Cha	aracte	eristic	.5			
US N	1arke	et Rele	ease				Oct-9	5	Malfund	tions (l	JS)				8	3	NBG Co	de				SS	IR	
Regi	stere	ed US	Implant	ts			50,00	0	Therap	y Func	tion No	t Comp	romise	d	:	2	Serial N	umber	Prefix				U, PD)V,
Estin	nate	d Acti	ive US Ir	nplants			4,70	0	Ele	ctrical (Compor	nent				1						PD	W	
Norn	nal E	Batter	y Deple	tions (U	S)		2,81	7	Po	ssible E	arly Bat	tery Dep	oletion			1	Estimat	ed Long	gevity			Se	e pa	ge
Advi	sorie	es					Non	e	Therap	y Func	tion Co	mprom	ised		(5								
									Ele	ctrical (Compor	nent			3	3								
									Ele	ctrical I	ntercor	nect			3	3								
100	. –																							
90) -																							
80																								_
70																					_	_		
60																								
50																								
30																								
100 90 80 70 60 50 40)																							
30															1									
20															-					-	-	-	-	
	0	1	1 2	2 3	3 4	1 5	5 6	5 7	7 8	3 9) 1	0 1	1 1	2 13	3 14	4	15	16	17	18	19	20	21	l
	\	Years	s After	Impla	nt		– Exc	luding	g Norn	nal Ba	ttery D	Depleti	ion		Inclu	ıding	g Norm	al Bati	tery D	eple	tion			
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 16	2 mo							
9	6		100.0			100.0			100.0	-	-	-	-	100.0	-									
9	· -		99.9				-					80.1				24.4			-		-	-		

42,000 37,000 32,000 27,000 23,000 20,000 17,000 14,000 11,000 7,800 5,000 2,700 800 100

Thera-i VDD 8968i

Effective Sample Size

Draduct Characteristics

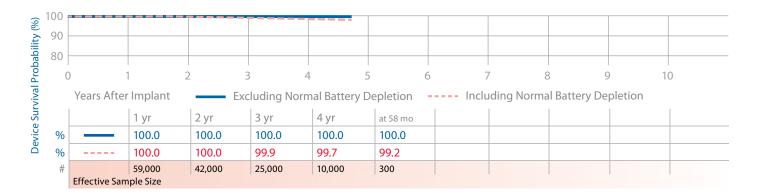
era-ı \	VDL	896	8i													Produ	ct Ch	aract	eristi	CS			
JS Marke	et Rele	ease				Mar-9	5	Malfun	ctions (l	JS)				0		NBG Co	de				VE	DD	
Register	ed US	Implan ^a	ts			4,90	0									Serial N	umber	Prefix			PE	C	
Estimate	d Acti	ve US Ir	mplants	5		60	0									Estimate	ed Lon	gevity	,		Se	e pa	ge 8
Normal E	Battery	y Deple	tions (U	JS)		32	2																
Advisorie	es					Non	e																
100																							
90																							
80																							
70																							
60 -																							
50 —																							
40																							
30																+	+	+	+	+	_	_	_
0	1	2	2 3	3 4	4 !	5 6) /	7 8	3 9	9 1	0 1	1 1.	2 13	3 14		15 1	16	17	18	19	20	21	
`	Years	After	Impla	ant	_	E xc	luding	g Norr	nal Ba	ttery [) epleti	ion		Includ	ding	Norm	al Bat	tery l	Deple	etion			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	-	-	12 yr	13 yr	at 15	7 mo							
% -		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0		100.0	100.0	100.0	100.0	100	.0							
/° _		99.9			99.6	99.3	99.2		98.0		89.1	75.5	59.0	40.3	38.8	3							
#		4,200	3,800	3,400	3,000	2,700	2,400	2,100	1,900	1,600	1,300	900	500	100	100								

Effective Sample Size

Versa DR VEDR01

Product Characteristics

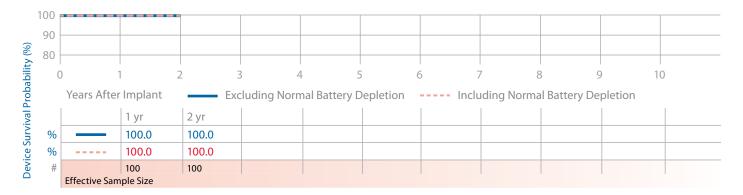
US Market Release	Jul-06	Malfunctions (US)	6	NBG Code	DDDR
Registered US Implants	77,000	Therapy Function Not Compromised	4	Serial Number Prefix	PWH, NWH
Estimated Active US Implants	61,000	Electrical Component	4	Estimated Longevity	See page 80
Normal Battery Depletions (US)	46	Therapy Function Compromised	2		
Performance Note: <u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Electrical Component	2		



Revo MRI SureScan RVDR01

Product Characteristics

US Market Release	Feb-11	Malfunctions (US)	0	NBG Code	DDDRP
Registered US Implants	8,600	Therapy Function Not Compromised	0	Serial Number Prefix	PTN
Estimated Active US Implants	8,500	Therapy Function Compromised	0	Estimated Longevity	See page 80
Normal Battery Depletions (US)	0				



Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions

	yistered Implants	sn	266,000 23	<u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	45,000 41	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	25,000 20	<u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	49,000 35		800 700	<u>See page 157</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	11,000 1,	See page 163 – Performance note on AT500 Pacing System Follow-Up Protocol	7,000 3,0	<u>See page 157</u> – Performance note on Dual Chamber Pacemakers <i>w</i> ith Measurement Lock-up ERI	1,900 20	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI
	bətemi SU əvi: stnslq	t5A	224,000	Dua up ER	41,000	n Dua -up ER	20,000	on Dua k-up ER	35,000		0	Dua ר up ER	1,600	AT50 ו	3,000	n Dua -up ER	200	on Dua k-up ER
	rmal Battery pletions (US)	ΙΟΝ	92	l Chamber II	9	l Chamber II	40	l Chamber II	44		0	l Chamber II	2,410	0 Pacing	319	l Chamber II	323	l Chamber II
Malfunctions (US)	yerapy notion mpromised erapy notion Not mpromised	Tho Tha	17 + 30 = 47		1 + 2 = 3		2 + 2 = 4		4 + 1 + 5		0 = 0 + 0		5 + 4 = 9		0 + 1 = 1		0 = 0 + 0	
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
Device	Years A	1 yr	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	+0.0/-0.1	100.0	100.0	100.0	100.0
Device Survival Probability (%)	Years After Implant	2 yr 3	100.0	100.0 + 0.0/-0.0 +	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	99.8 + 0.1/-0.1	100.0 + +0.0/-0.0	100.0 9	100.0 +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0	99.8 + 0.1/-0.1	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	99.7
Probabi	ant	3 yr	100.0	99.9 + 0.0/-0.0+	100.0 + +0.0/-0.0	99.9 + 0.0/-0.1	100.0 +0.0/-0.0	99.7 + 0.1/-0.1	100.0 + +0.0/-0.0	99.7 +0.1/-0.1	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0	99.5 +0.1/-0.2 +	100.0 + +0.0/-0.0	99.9 +0.1/-0.1	100.0 + +0.0/-0.0	99.0 +0.4/-0.7
lity (%)		4 yr 5 yr	100.0 100.0 +0.0/-0.0 +0.0/-0.0 at 59 mo	99.7 99.5 +0.0/-0.0 +0.1/-0.1 at 59 mo	100.0 +0.0/-0.0	99.7 99.7 +0.1/-0.3 at 56 mo	100.0 +0.0/-0.0	98.8 +0.3/-0.4 at 57 mo	100.0 +0.0/-0.0 at 58 mo	99.4 98.3 +0.1/-0.2 +0.5/-0.7 at 58 mo	100.0 +0.0/-0.0 at 47 mo	100.0 +0.0/-0.0 at 47 mo	99.9 +0.1/-0.1 +0.1/-0.1	97.6 84.4 +0.3/-0.4 +0.8/-0.9	100.0 +0.0/-0.0 +0.0/-0.0	99.2 +0.2/-0.3 +0.3/-0.4	100.0 +0.0/-0.0 +0.0/-0.0	96.8 +0.8/-1.1 +1.4/-1.7
	-	6 yr	0.0 or	1.0 Or	0.0 or	0r	0.0 or	8. O	0.0 or	7.0 or			99.9	51.0	100.0	96.9	100.0 +0.0/-0.0	63.5
	-	7 yr											99.9 1 +0.1/-0.1 at 80 mo	15.1 +1.5/-1.4 at 80 mo	100.0 +0.0/-0.0	87.9	100.0 0 +0.0/-0.0 at 80 mo	25.2 +4.0/-3.8 at 80 mo
		8 yr													100.0 +0.0/-0.0 at 90 mo	80.5 +1.6/-1.7 at 90 mo		
,		10 yr																
		12 yr																
	-	14 yr																
		16 yl																

	Malfunctions (US)		Device	Surviva	Device Survival Probability (%)	oility (%)								IP
tapplants basemi SU evi: stnelc stnery (SU) snoiteld	versoy notion mpromised years year years years years years years years years years years years year years years years years years years years years years years year years year year year year year year years year year year year year year y y		Years A	Years After Implant	olant	-								PG Imp
toA qml	in4 io2 hdT hdT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr 12	12 yr 14	14 yr 16	olar 16 yr
101,000 59,000 1,122	5 + 17 = 22	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 at 86 mo				ntable I
See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Including Normal Battery Depletion	100.0	99.9	99.8	99.6	98.9	97.4 +0.1/-0.1	91.3 84.0.5/-0.5	89.1 +0.9/-0.9 at 86 mo				Pulse C
12,000 4,500 903	+ 0 + 1	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0 +0.0/-0.0 at 77 mo					Senera
See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Including Normal Battery Depletion	99.9	99.7 +0.1/-0.1	99.3 +0.1/-0.2	97.7 +0.3/-0.3	92.0	67.9	31.7 +3.6/-3.5 at 77 mo					tors, co
600 400 1	0 = 0 +	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0 +0.0/-0.0 at 74 mo					ontinue
See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Including Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	99.2	99.2 +0.6/-2.4 at 74 mo					ed
25,000 10,000 386	+ 3 = 4	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 86 mo				
		Including Normal Battery Depletion	100.0	99.9	99.5 +0.1/-0.1	98.9 +0.2/-0.2	97.8 +0.2/-0.3	94.2 +0.5/-0.5	82.0 +1.9/-2.1	71.5 +4.3/-4.9 at 86 mo				
600 300 28	0 = 0 + 0	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0						
See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Including Normal Battery Depletion	100.0	100.0	100.0	99.5	99.5	82.8 +5.3/-7.4						
108,000 81,000 113	46 + 1,009 = 1,055	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.8	98.1 +0.1/-0.1	95.6 +0.3/-0.4	95.2 +0.4/-0.5 at 73 mo					
Advisories: See page 146 – 2010 Low Battery Voltage Displayed at Device Interrogation	(0) + (114) = 114	Including Normal Battery Depletion	100.0	99.9	99.8	99.4 +0.1/-0.1	95.8	89.7	86.7 +1.5/-1.7 at 73 mo					
See page 159 – Performance note on anomalies in MOSFET Integrated Circuit Technology	(advisory-related subset)													
47,000 5,300 7,358	10 + 14 = 24	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9 +0.0/-0.0 at 106 mo			
See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Including Normal Battery Depletion	99.8	99.8	99.6	99.5	98.9	97.2 +0.2/-0.2	88.0 +0.4/-0.4	57.4 +0.7/-0.7	1.0 +0.4/-0.3 at 106 mo			
15,000 1,900 1,368	+ + + 5	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 9 yr			
		Including Normal Battery Depletion	99.8	99.7	99.5	99.1	98.6 +0.2/-0.3	96.9	90.8	64.6	17.4 +2.2/-2.1 at 9 yr			

Device Survival Summary continued

					E	Malfunctions	ons (US)		Device	Surviva	Probal	Device Survival Probability (%)								
	er	rket e	ered Jants	sn	ri Battery (SU) snoii	no romised	py on Not romised		\ \ \	4 V C C C C C C C C C C C C C C C C C C	4									Шрапс
(lime7	apoW dmuN	NS Wa	Regiss US Im	stimisa AvitoA Islqml					1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Kappa 600 DR	KDR601, KDR603, KDR606	Jan-99	25,000	2,000	3,759	+ + +	5 = 63	Excluding Normal Battery Depletion	100.0	100.0	100.0	99.9	9.	99.9	-	99.7	. 0			
	Advisories: See page 155–2002 Potential F Power Supply Wires; See also page 149 – 20 Potential Separation of Interconnect Wires	See page 1	ee also pag fInterconr	Advisories: See page 155–2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires	tured	(34) + (0) (advisory-related	(0) = (34) lated subset)	Including Normal Battery Depletion	99.9	99.8	99.8 +0.1/-0.1	99.5	98.8 +0.2/-0.2	96.9+0.3/-0.3	87.8	57.6	5.2 +1.0/-0.9 at 107 mo			enerato
	See page 157 – Performance note on Dual Pacemakers with Measurement Lock-up ERI	57 – Perfor with Meas	rmance no: urement L	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															
Kappa 600 DR	KDR651, KDR653	Mar-01	16,000	1,500	2,633	53 +	3 = 56	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	99.9	99.7 +0.1/-0.2	99.5	99.4 +0.2/-0.3 at 103 mo			
	Advisories: Power Supp Potential Se	See page 1	ee also page f Interconr	Advisories: See page 155 – 2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires	ctured	(30) + (advisory-n	(30) + (0) = (30) (advisory-related subset)	Including Normal Battery Depletion	100.0	99.9	99.8	99.4 +0.1/-0.2	98.2 +0.3/-0.3	94.9	81.3 +0.9/-1.0	43.8	6.3 +1.3/-1.1 at 103 mo			
	See page 157 – Performance note on Dual Pacemakers with Measurement Lock-up ERI	57 – Perfor with Meas	rmance no	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															
Kappa 700 D	KD701, KD703, KD706	Jan-99	300	70	17	+	0 = 0	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0				
	Advisories: See page 155–2002 Potential F Power Supply Wires; See also page 149 – 20 Potential Separation of Interconnect Wires	See page 1	ee also page finterconr	Advisories: See page 155–2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires	ctured	(0) + (0) (advisory-relate	(0) = (0) elated subset)	Including Normal Battery Depletion	100.0	100.0	100.0	99.0	97.8 +1.4/-3.5	95.4	94.2 +2.7/-4.8	86.4				
	See page 157 – Performance note on Dual (Pacemakers with Measurement Lock-up ERI	57 – Perfor with Meas	rmance no: urement L	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															
Kappa 700 DR	KDR701, KDR703, KDR706	Jan-99	206,000	34,000	30,156	+ 669	37 = 736	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9	99.9	99.9	99.7	99.6	99.4 +0.1/-0.1 at 106 mo			
	Advisories: Power Supp Potential Se	See page 1 oly Wires; Se sparation ol	ee also page f Interconr	Advisories: See page 155 – 2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires	ctured	(414) + (advisory-re	(414) + (0) = (414) (advisory-related subset)	Including Normal Battery Depletion	99.9	99.8	99.6	99.2 +0.0/-0.0	98.2	95.5	85.5 +0.2/-0.2	56.2	0.2 +0.1/-0.1 at 106 mo			
	See page 157 – Performance note on Dual Pacemakers with Measurement Lock-up ERI	57 – Perfor with Meas	rmance no	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															
Kappa 700 DR	KDR721	Feb-99	008'6	800	1,330	4	1 = 5	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9 +0.1/-0.1 at 85 mo				
	Advisories: Power Supp Potential Se	See page 1	ee also page finterconr	Advisories: See page 155–2002 Potential Fractured Power Supply Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires	ctured	(4) + (advisory-re	(4) + (0) = (4) (advisory-related subset)	Including Normal Battery Depletion	99.8	99.5	98.7 +0.2/-0.3	96.7	91.0	69.0	21.1	14.9 +2.0/-1.9 at 85 mo				
	See page 157 – Performance note on Dual Pacemakers with Measurement Lock-up ERI	57 – Perfor s with Meas	rmance no urement L	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															

Continued

1 1	mplantable	14 yr 16 yr 2	lse Ge	nerato 	rs. con	tinued										
		12 yr 1														
		10 yr	99.8 +0.1/-0.1 at 107 mo	11.4 +1.2/-1.1 at 107 mo	99.6 +0.2/-0.6 at 97 mo	41.3 +4.7/-4.8 at 97 mo		99.9 +0.1/-0.4 at 98 mo	42.8 +3.4/-3.4 at 98 mo	99.9 +0.0/-0.1 at 101 mo	18.2 +1.2/-1.1 at 101 mo	99.9 +0.1/-0.1 at 99 mo	25.2 +3.1/-3.0 at 99 mo			
		8 yr	99.9	56.6 +0.9/-0.9	99.6	42.1		99.9	53.2	99.9	57.2 +0.6/-0.6	99.9	49.4			
		7 yr	99.9	83.6	99.6	72.8		99.9	84.7	99.9	87.7 +0.3/-0.3	99.9	83.9 +0.7/-0.8		99.6 +0.3/-1.9 at 83 mo	54.7 +6.5/-7.0 at 83 mo
		6 yr	100.0 +0.0/-0.0	93.7	99.6	94.2		100.0	96.2 +0.7/-0.8	100.0	96.5	99.9	94.5		99.6	90.7
(9)		5 yr	100.0	97.2 +0.2/-0.2	99.8 +0.1/-0.4	98.5		100.0	98.5	100.0	98.6	100.0	97.5		100.0	97.9
bility (9		4 yr	100.0	98.7 +0.1/-0.1	99.8	98.7		100.0	99.5	100.0	99.4 +0.0/-0.0	100.0	98.9		100.0	99.0
Device Survival Probability (%)	plant	3 yr	100.0	99.4 +0.1/-0.1	99.9	99.3		100.0	99.8 +0.1/-0.2	100.0	99.8	100.0	99.6		100.0 +0.0/-0.0	100.0
e Surviv	Years After Implant	2 yr	100.0 +0.0/-0.0	99.8	99.9	99.8 +0.1/-0.5		100.0	99.9	100.0	99.9	100.0	99.8		100.0 +0.0/-0.0	100.0 +0.0/-0.0
Device	Years	1 yr	100.0 +0.0/-0.0	99.9	99.9	99.8 +0.1/-0.5		100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	99.9		100.0 +0.0/-0.0	100.0 +0.0/-0.0
			Excluding nal Battery Depletion	ding tery tion	ding tery tion	ding tery tion		ing tery	ling tery tion	ing ion	ing ery ion	ing ing	ding tery tion		ding tery tion	ding ttery etion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion
Malfunctions	yepy notion mpromised sreby Notion Not notromised al	Fur Cor The	25 + 3 = 28 Exdu Normal Ba Depl	(20) + (0) = (20) Inclu (advisory-related subset) Normal Bat Deple	4 + 0 = 4 Exclus	(4) + (0) = (4) Inclus (advisory-related subset) Deple		3 + 0 = 3 Exclud	Incluc Normal Bat' Deple	53 + 19 = 72 Exclud Normal Batt Deplet	Includ Normal Batt Deplet	8 + 9 = 17 Exclud	Incluc Normal Bat Deple		0 + 2 = 2 Exclus	Inclu Normal Ba Deple
Malfunctions	nction mpromised srapy iction Not mpromised	The Fur Cor The Fur Fur Too	+ 3 = 28	$\frac{(20)}{(advisory-related subset)}$	+ 0 = 4	(advisory-related subset)		+ 0 = 3		+ 19 = 72	Includ Normal Batt Deplet	+ 9 = 17		Ja.	+ 5 +	
Malfunctions	srapy oction npromised srapy crion Not npromised	Mori The Fun Too The Fun Too Too	25 + 3 = 28 Norm	$\frac{(20)}{(advisory-related subset)}$	4 + 0 + 4 Norm	(advisory-related subset)	al Chamber :RI	3 + 0 = 3 Norm		10,541 53 + 19 = 72	Includ Normal Batt Deplet	8 + 9 = 17		al Chamber :RI	0 + 5 = 2	
Malfunctions	ive US sharts sh	Esti Act Imp Mon Dep The Fur Con The Fur Con	4,500 25 + 3 = 28 Norm	$\frac{(20)}{(advisory-related subset)}$	Norm	(advisory-related subset)	e note on Dual Chamber ant Lock-up ERI	474 3 + 0 = 3 Norm		53 + 19 = 72	Includ Normal Batt Deplet	1,844 8 + 9 = 17		e note on Dual Chamber ant Lock-up ERI	79 0 + 2 = 2	
Malfunctions	implants ive US ive US solidate solidat	Reg USI Esti Mori Mori Mori Mori Mori Mori Mori Mor	Jan-99 55,000 7,700 4,500 25 + 3 = 28 Norm	$\frac{(20)}{(advisory-related subset)}$	200 171 4 + 0 = 4 Norm	(advisory-related subset)	- Performance note on Dual Chamber th Measurement Lock-up ERI	1,100 474 3 + 0 = 3 Norm		45,000 10,541 53 + 19 = 72	Includ Normal Batt Deplet	Jan-02 37,000 9,500 1,844 8 + 9 = 17		- Performance note on Dual Chamber th Measurement Lock-up ERI	90 79 0 + 2 = 2	
Malfunctions	Market ease jistered implants ive US shants shants shants shetions scrion iction iction Not iction Not iction Not iction Not	Regarded to the control of the contr	55,000 7,700 4,500 25 + 3 = 28 Norm	= (20) d subset)	1,700 200 171 4 + 0 = 4 Norm	Norm	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	4,300 1,100 474 3 + 0 = 3 Norm	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Deple	125,000 45,000 10,541 53 + 19 = 72	Includ Normal Batt Deplet	37,000 9,500 1,844 8 + 9 = 17	Advisories: See page 149 – 2009 Potential Separation of Interconnect Wires Normal Bat Deple	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	600 90 79 0 + 2 = 2	Advisories: See page 149 – 2009 Potential Separation of Interconnect Wires Normal Ba

Device Survival Summary continued

	Implantabl		uise G	enerat	.015, cc	·	- 0.										
		16 yr				99.9 +0.0/-0.0 at 212 mo	46.4 +1.8/-1.9 at 212 mo	99.9 +0.0/-0.1 at 242 mo	66.9 +2.3/-2.4 at 242 mo	100.0 +0.0/-0.0 at 207 mo	40.8 +2.7/-2.7 at 207 mo					99.9 +0.1/-0.3 at 169 mo	85.2 +2.8/-3.4 at 169 mo
		14 yr				99.9	71.0 +0.9/-0.9	99.9	80.9	100.0	68.1	100.0 +0.0/-0.0 at 145 mo	8.0 +1.5/-1.3 at 145 mo	100.0 +0.0/-0.0 at 153 mo	25.9 +2.9/-2.8 at 153 mo	99.9	85.2 +2.8/-3.4
		12 yr				99.9	82.2 +0.6/-0.6	99.9	84.0 +0.6/-0.6	100.0 +0.0/-0.0	82.0 +1.0/-1.1	100.0 +0.0/-0.0	12.8 +1.3/-1.2	100.0 +0.0/-0.0	43.4 +2.0/-2.0	99.9 +0.1/-0.3	89.3 +2.1/-2.5
		10 yr				99.9	88.7 +0.4/-0.5	99.9	87.5 +0.5/-0.5	100.0 +0.0/-0.0	89.2 +0.7/-0.8	100.0 +0.0/-0.0	66.5	100.0 +0.0/-0.0	75.2 +1.3/-1.4	99.9	92.8
		8 yr				99.9	94.8 +0.3/-0.3	99.9	92.3 +0.4/-0.4	100.0	94.8 +0.5/-0.5	100.0	92.4 +0.5/-0.5	100.0 +0.0/-0.0	92.1	99.9	96.8
		7 yr	99.9 +0.0/-0.1 at 81 mo	12.1 +1.5/-1.4 at 81 mo		99.9	97.3 +0.2/-0.2	99.9	95.4 +0.3/-0.3	100.0 +0.0/-0.0	97.1	100.0	96.2 +0.3/-0.3	100.0	95.0 +0.5/-0.5	99.9	97.9
		6 yr	99.9	59.5		99.9	98.2	99.9	97.8 +0.2/-0.2	100.0 +0.0/-0.0	98.2 +0.2/-0.3	100.0	97.7	100.0	97.2 +0.3/-0.4	99.9	98.9
(%)		5 yr	100.0	90.3		99.9	98.9	99.9	98.8 +0.1/-0.1	100.0	99.0	100.0	98.7	100.0	98.3 +0.2/-0.3	99.9 +0.1/-0.3	99.1
Device Survival Probability (%)		4 yr	100.0	97.2 +0.3/-0.3		99.9	99.2	99.9	99.2	100.0	99.5	100.0	99.3	100.0	99.0	100.0	99.6
/al Prob	nplant	3 yr	100.0	99.2		100.0	99.5	99.9	99.5	100.0	99.8	100.0	99.5	100.0	99,4	100.0	99.6
e Surviv	Years After Implant	2 yr	100.0	99.7		100.0	99.7	99.9	99.7	100.0	99.9	100.0	99.8 +0.1/-0.1	100.0	99.7	100.0	99.6
Devic	Years	1 yr	100.0	99.9		100.0	99.9	100.0 +0.0/-0.0	99.8	100.0	99.9	100.0	99.8	100.0	99.8	100.0	99.7
			ding tery	ding tery tion		6 5 6	ing ion	i e i o	er y ion	토 축 은	한 한 등	D 한 등 등	한잔	5 분 등	한 한 등	ը ² . Բ	ery ion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ls	JoT.	4 Exclud			35 Excludi Normal Batt	Includ Normal Batt Deplet	50 Exclud Normal Batt Deplet	— Includi Normal Batt Depleti	3 Excludi Normal Batte Depleti	Includi Normal Batte Depleti	4 Excludii Normal Batte Depleti	Includir Normal Batte Depletic	1 Excludi Normal Batte Depleti	Includi Normal Batte Depleti	1 Excludi Normal Batte Depleti	Includ Normal Batt Deplet
5	npromised	uoo	4			= 35	Includ Normal Batt Deplet	= 50		m II	Includi Normal Batte Depleti	A Norm	Includir Normal Batte Depletic	 -	Includi Normal Batte Depleti	= 1 Norm	Includ Normal Batt Deplet
ctions		nu7 no2	1 4			24 = 35	Includ Normal Batt Deplet	15 = 50	— Includi Normal Batt	8 8	Includi Normal Batte Depleti	0 = 4 Norm	Includir Normal Batte Depletic	0 = 1	Includi Normal Batte Depleti	0 = 1	Includ Normal Batt Deplet
Malfunctions	rction Not npromised	no no adT nu no no	4	= 3 d subset)		= 35	Includ Normal Batt Deplet	= 50	— — Includ Normal Batt Deplet	m II	includi Normal Batte Depleti	A Norm	Includii Normal Batte Depletii	 -	Includi Normal Batte Depleti	= 1 Norm	includ Normal Batt Deplet
Malfunctions	iction pseimorqu estion Mot formised	Dep The To To The The Ton	+	(3) + (0) = 3 (advisory-related subset)	mber	+ 24 = 35	Includ Normal Batt Deplet	+ 15 = 50	 	+ 3	Includi Normal Batto Depleti	+ 0 + Norm	Includii Normal Batte Depletic	+ 0 +	Includi Normal Batte Depleti	+ 0 = 1	Includ Normal Batt Deplet
Malfunctions	yderions yderion iction npromised serion Not iction Not npromised	Acti Imp Nor The Fun Con The Tun Ton	3 + 1 = 4	(3) + (0) = 3 (advisory-related subset)	on Dual Chamber :k-up ERI	11 + 24 = 35	Includ Normal Batt Deplet	35 + 15 = 50	 	0 +	Includi Normal Batto Depleti	A + 0 = 4 Norm	Includii Normal Batte Depletii	1 + 0 = 1	Includi Normal Batte Depleti	+ 0 + 1 Norm	Includ Normal Batt Deplet
Malfunctions	ive US sharts sharts sherions srapy roction srapy srapy srapy srapy srapy srapy srapy srapy	Estiting Mort Mort Mort Mort The Fundament T	2,493 3 + 1 = 4	(3) + (0) = 3 (advisory-related subset)	nance note on Dual Chamber ement Lock-up ERI	2,567 11 + 24 = 35	Includ Normal Batt Deplet	1,741 35 + 15 = 50	 	950	Includi Normal Batto Depleti	2,807 4 + 0 = 4 Norm	Includii Normal Batte Depletii	1,057 1 + 0 = 1	Includi Normal Batte Depleti	55 1 + 0 = 1 Norm	Indud Normal Batt Deplet
Malfunctions	Implants ive US ive US slants mal Battery sletions sletions iction iction Not repy very iction Not repy	Reger North Mort The Fundament of States of St	2,200 2,493 3 + 1 = 4	(3) + (0) = 3 (advisory-related subset)	– Performance note on Dual Chamber ith Measurement Lock-up ERI	5,900 2,567 11 + 24 = 35	Includ Normal Batt Deplet	7,600 1,741 35 + 15 = 50	 	2,000 950 0 + 3 = 3	Includi Normal Batto Depleti	2,600 2,807 4 + 0 = 4 Norm	Includia Normal Batte Depletit	1,700 $1,057$ 1 $+$ 0 $=$ 1	Includi Normal Batte Depleti	500 55 1 + 0 = 1 Norm	Includ Normal Batt Deplet
Malfunctions	Market ease jistered limplants ive US ive US shell shell shell shell strion srapy	US I Red US I Esti Imp Inp Inp Inp Inp Inp Inp Inp Inp Inp In	16,000 2,200 2,493 3 + 1 = 4		See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	59,000 5,900 2,567 11 + 24 = 35	Includ Normal Batt Deplet	59,000 7,600 1,741 35 + 15 = 50	Advisories: See page 156 – 1991 Potential Delayed — — — Induding Restoration of Permanent Settings Deplet	17,000 2,000 950 0 + 3 = 3	Includi Normal Batte Depleti	26,000 2,600 2,807 4 + 0 = 4 Norm	Includii Normal Batte	18,000 1,700 1,057 1 + 0 = 1	Includi Normal Batte Depleti	4,200 500 55 1 + 0 = 1 Norm	Indud Normal Batt Deplet

					_	Malfunctions	ions		E	Device	Device Survival Probability (%)	Probab	ility (%)								
			b str				toN bəsir														ппріа
γlin	del nber	Narket sase	isterec mplan	SU evi	noitel	rapy ction nprom	rapy ction nprom	ĮE		Years A	Years After Implant	lant									IIIIal
me4		geje	N2 I Bed	itoA qml	Deb	Fun Con	Fun Con	tot		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr 8	8 yr	10 yr	12 yr	14 yr	16 yr
Prodigy DR	7860, 7861, 7862	Oct-95	37,000	3,400	3,831	+	ار اا	=	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0+0.0/-0.0	100.0 +	100.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 +(100.0 + +0.0/-0.0	100.0 +0.0/-0.0 at 143 mo		uise de
									Including Normal Battery Depletion	99.9	99.8 +0.0/-0.1	99.6	99.3	98.7	97.9 +0.2/-0.2 +	96.3 + +0.3/-0.3 +	92.4 +0.4/-0.4 +0	68.4 +0.9/-0.9	12.1 +1.2/-1.2 at 143 mo		inerau
Prodigy SR	8158, 8160, 8161, 8162	Oct-95	22,000	2,500	1,292	2 +	2 ==	4	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0 +	100.0 1 +0.0/-0.0	100.0+	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 152 mo	ors, conti
									Including Normal Battery Depletion	99.7	99.6	99.2 +0.1/-0.1	98.7	97.8 +0.2/-0.3 +	96.5 +0.3/-0.4 +	94.8 +0.4/-0.5 +	91.6 74	74.3 4+1.2/-1.3	44.8 +1.8/-1.8	30.7 +2.7/-2.6 at 152 mo	nueu
Sensia DR	SEDR01, SED01	90-Inf	95,000	75,000	52	+	9	10	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 at 58 mo							
	See page 157 – Performance note on Dual (Pacemakers with Measurement Lock-up ERI	$\frac{7}{2}$ – Perforr with Measu	nance note	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	nber				Including Normal Battery Depletion	100.0	100.0 +0.0/-0.0	99.8	99.6	99.0 +0.4/-0.6 at 58 mo							
Sensia SR	SESR01, SES01	90-Inf	63,000	45,000	14	+	II E	4	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 at 57 mo							
									Including Normal Battery Depletion	100.0	99.9	99.8	99.5	98.2 +0.8/-1.5 at 57 mo							
Sigma 100 S	SS103, SS106	Aug-99	800	100	17	+	0	0	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0+0.0/-0.0+	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 +	100.0+	100.0 +0.0/-0.0 +0	100.0 +0.0/-0.0 at 98 mo			
	Advisories: See page of Interconnect Wires	see page 15 ect Wires	3 – 2005 P.	Advisories: <u>See page 153</u> – 2005 Potential Separation of Interconnect Wires		$\frac{(0)}{(0)} + (0) = (0)$ (advisory-related subset)	(0) = elated subs	(0) set)	Including Normal Battery Depletion	100.0	100.0	99.5	99.5	98.7 +0.8/-2.3 +	98.7 +0.8/-2.3 +	96.5 + +1.8/-3.6 +	93.6 +2.8/-4.9 +2 at	93.6 +2.8/-4.9 at 98 mo			
Sigma 200 DR	SDR203	Aug-99	16,000	4,300	475	30 +	=	31	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.8 + 0.1/-0.1	99.6 +0.1/-0.2 +(99.5 +0.2/-0.2 a	99.5 +0.2/-0.2 at 11 yr		
	Advisories: Sof Interconn Potential Sep	ect Wires; saration of	3 – 2005 Prose also para Interconn€	Advisories: See page 153 – 2005 Potential Separation of Interconnect Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires		(19) + (0) (advisory-related	= d sub	(19) set)	Including Normal Battery Depletion	100.0	99.9	99.9	99.8	99.5	99.0 +0.2/-0.2 +	97.6 +0.3/-0.4 +	94.1 80	80.8 +1.3/-1.4 ************************************	55.6 +4.2/-4.5 at 11 yr		
Sigma 200 SR	SSR203	Sep-99	12,000	2,300	225	+	0	11	Excluding Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	100.0	99.9	99.9 +0.1/-0.2	99.8 +0.1/-0.2 +	99.8 +0.1/-0.2 +(99.7 +0.1/-0.3	99.7 +0.1/-0.3 at 133 mo		
	Advisories: Sof Interconn Potential Sep	ect Wires;	3 – 2005 Prose also para Interconn€	Advisories: See page 153 – 2005 Potential Separation of Interconnect Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires		$\frac{(11)}{4} + (0) = (11)$ (advisory-related subset)	(0) = elated subs	(11) set)	Including Normal Battery Depletion	99.9	99.9 +0.1/-0.1	99.8	99.7	99.2 +0.2/-0.3	98.6 +0.3/-0.4	97.1 +0.5/-0.6 +	95.2 8.	84.0 +1.6/-1.8	63.1 +4.7/-5.1 at 133 mo		
Sigma 300 DR	SDR303, SDR306	Aug-99	107,000	37,000	1,982	192 +	II &	200	Excluding Normal Battery Depletion	100.0	100.0	100.0	99.9	99.9	99.9	99.8 + 0.0/-0.1 +	99.6 +0.1/-0.1 +0.1/-0.1	99.5 +0.1/-0.1	99.5 +0.1/-0.1 at 11 yr		
	Advisories: See page 153 – 2005 Potential S of Interconnect Wires; See also page 149 – 2 Potential Separation of Interconnect Wires	see page 15 ect Wires;	3 – 2005 Properties of the second	Advisories: See page 153 – 2005 Potential Separation of Interconnect Wires; See also page 149 – 2009 Potential Separation of Interconnect Wires		$\frac{(137)}{(advisory-related subset)}$	(0) = (0) elated subs	c	Including Normal Battery Depletion	100.0 +0.0/-0.0	99.9	99.9	99.7	99.4	98.9 +0.1/-0.1	97.9 + +0.1/-0.1	95.1 8 +0.2/-0.2 +0.2/-0.3	81.6 +0.6/-0.7	51.6 +3.2/-3.3 at 11 yr		
continued	p																				

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		16 yr														
		14 yr					99.9 +0.0/-0.0 at 147 mo	3.3 +0.6/-0.6 at 147 mo	100.0 +0.0/-0.0 at 162 mo	24.4 +2.4/-2.4 at 162 mo	100.0 +0.0/-0.0 at 157 mo	38.8 +4.1/-4.2 at 157 mo				
		12 yr	99.7 +0.1/-0.1 at 131 mo	62.3 +3.0/-3.1 at 131 mo			99.9	19.2 +0.6/-0.6	100.0	51.5	100.0+0.0/-0.0	59.0 +2.9/-3.0				
		10 yr	99.7 +0.1/-0.1	81.9	99.5 +0.4/-2.6 at 105 mo	77.0 +5.7/-7.1 at 105 mo	99.9	71.3 +0.4/-0.4	100.0	80.1	100.0	89.1 +1.4/-1.6				
		8 yr	99.7 +0.1/-0.1	94.8	99.5	89.4 +3.3/-4.7	99.9	93.2 +0.2/-0.2	100.0	94.5 +0.3/-0.3	100.0	98.0				
		7 yr	99.8	97.2 +0.2/-0.3	100.0	94.1 +2.2/-3.6	99.9	96.7	100.0	96.9	100.0 +0.0/-0.0	99.1				
		6 yr	99.9 +0.0/-0.0	98.5	100.0 +0.0/-0.0	98.1 +1.0/-2.2	100.0	98.1 +0.1/-0.1	100.0	98.2 +0.2/-0.2	100.0 +0.0/-0.0	99.2 +0.3/-0.4				
(%)		5 yr	100.0	99.2	100.0	99.4	100.0	99.0	100.0	98.9	100.0	99.3 +0.2/-0.3	100.0 +0.0/-0.0 at 58 mo	99.2 +0.2/-0.3 at 58 mo		
ability (9		4 yr	100.0	99.6	100.0	100.0 +0.0/-0.0	100.0	99.4 +0.0/-0.1	100.0	99.3	100.0	99.6	100.0	99.7		
Device Survival Probability (%)	nplant	3 yr	100.0	99.8	100.0	100.0	100.0	99.6	100.0	99.6	100.0	99.6 +0.2/-0.3	100.0	99.9		
e Surviv	Years After Implant	2 yr	100.0	99.9	100.0	100.0	100.0	99.8	100.0	99.8	100.0	99.8	100.0	100.0	100.0	100.0
Devic	Years	1 yr	100.0	100.0	100.0	100.0	100.0	99.9	100.0	99.9	100.0	99.9	100.0	100.0	100.0	100.0
			وتق	ם אַ ב	ه خرم	ם אַ ב	のシェ	ם אַ פ	ロンロ	$\rho > r$	のシェ	$\rho > r$	のシェ	9 > 4	のシェ	ם לים
			Excluding Normal Battery Depletio	Including Normal Battery Depletion	Excluding Normal Battery Depletio	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion						
	Įe	otoT.	45 Excludii Normal Batte Deplet		1 Excludin Normal Batter Depleti		49 Excludin Normal Batter Depletio	Includin Normal Batter Depletio	8 Excludin Normal Batter Depletio	Includin Normal Batter Depletio	O Excludin Normal Batter Depletio	Includin Normal Batter Depletio	6 Excludin Normal Batter Depletio	Includin Normal Batter Depletio	0 Excludin Normal Batter Depletio	Includin Normal Batteı Depletio
suc	ction Not npromised	Fun Con		= (34) ed subset)	= 1 Excludin Normal Batter Depleti	= (1) d subset)	= 49	Includin Normal Batter Depletio		Includin Normal Batter Depletio		Includin Normal Batter Depletio		Includin Normal Batter Depletio		Includin Normal Batteı Depletio
	bəsimorqn	The Con	45	= (34) ed subset)	-	= (1) d subset)	49	Includin Normal Batter Depletio	∞	Includin Normal Batter Depletio	0	Includin Normal Batter Depletio	9	Includin Normal Batter Depletio	0	Includin Normal Battee Depletio
Malfunctions	rapy ction Not npromised	The Tun The Tun Tun	3 = 45	(0) = (34) related subset)	0 = 1	= (1) ted subset)	23 = 49	Includin Normal Batter Depletio	2 = 8	Includin Normal Batter Depletio	0 = 0	Includin Normal Batter Depletio	4 = 6	Includin Normal Batter Depletio	0 = 0	Includin Normal Batter Depletio
	oction npromised rapy oction Not oction Sed	The Fun Con The fun Fun Too	+ 3 = 45	(34) + (0) = (34) (advisory-related subset)	+ 0 = 1	(1) + 0 = (1) (advisory-related subset)	+ 23 = 49	Includin Normal Batter Depletio	+ 5	Includin Normal Batter Depletio	0 = 0 +	Indudin Normal Batter Depletio	+ 4 = 6		0 = 0 +	Includin Normal Batter Depletio
	repy repy oction npromised repy retion Not npromised	Acti Imp Nor Dep Fun Con The The Tun To O	42 + 3 = 45	(34) + (0) = (34) (advisory-related subset)	+ 0 + 1	(1) + 0 = (1) (advisory-related subset)	26 + 23 = 49	Includin Normal Batter Depletio	+ 5 = 8	Includin Normal Batter Depletio	0 = 0 + 0	Includin Normal Batter Depletio	2 + 4 = 6		0	Includin Normal Batter Depletio
	nlants mal Battery nletions repy rction npromised repy repy repy repy repy repy repy repy	Esti Acti Imp Mon Mon Dep The Fun Con The	713 42 + 3 = 45	(34) + (0) = (34) (advisory-related subset)	1 + 0 + 1 + 0 + 1	(1) + 0 = (1) (advisory-related subset)	13,712 26 + 23 = 49	Includin Normal Batter Depletio	2,817 6 + 2 = 8	Includin Normal Batter Depletio	322 0 + 0 = 0	Indudin Normal Batter Depletio	46 2 + 4 = 6		0 = 0 + 0	Includin Normal Batter Depletio
	mated ve US lants lants mal Battery sletions repy crion npromised repy repy repy repy repy repy repy	Regerence Regere	13,000 713 42 + 3 = 45	(34) + (0) = (34) (advisory-related subset)	100 41 1 + 0 = 1	(1) + 0 = (1) (advisory-related subset)	11,000 13,712 26 + 23 = 49	Includin Normal Batter Depletio	4,700 $2,817$ 6 $+$ 2 $=$ 8	Includin Normal Batter Depletio	600 322 0 + 0 = 0	Indudin Normal Batter Depletio	61,000 46 2 $+$ 4 $=$ 6		8,500 0 0 + 0 0 0 0,8	Includin Normal Batter Depletio
	Market seese istered mplants Ve US Nee US Ne	Reld Regolater More The Fun Con The Fun	54,000 13,000 713 42 + 3 = 45	= (34) ed subset)	600 100 41 1 + 0 = 1	= (1) d subset)	121,000 11,000 13,712 26 + 23 = 49	Includin Normal Batter Depletio	50,000 4,700 2,817 6 + 2 = 8	Includin Normal Batter Depletio	4,900 600 322 0 + 0 = 0	Indudin Normal Batter Depletio	77,000 61,000 46 2 + 4 = 6	See page 157 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depletio	8,600 8,500 0 0 + 0 = 0	Includin Normal Batter Depletio



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated L	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	$1000\\ Lead\Omega$	Elective Replacement Indicators
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.3 5.4	10.0 8.9 7.2	**
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 5.1	7.9 7.5 6.3	**
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.7 7.3 4.9	11.2 9.4 7.1	**
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

		Estimated Long	gevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g., VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g., VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.

 $[\]ensuremath{^{**}}\text{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

Estimated	Longevity
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Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 5.1	7.9 7.5 6.3	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Revo MRI SureScan	RVDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.7 7.3 4.9	11.2 9.4 7.1	**

 $^{^{**}\}mbox{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 28 years with its multicenter, global chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted, nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads that are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, non-randomized multicenter, global study designed to monitor the performance of market-released cardiac therapy products. Medtronic has been monitoring the performance of its cardiac therapy products with a multicenter study for 28 years and has evaluated the performance of more than 75,000 leads, with data reported from 14 countries on four continents.

The primary purpose of the SLS is to evaluate and publish the long-term reliability and performance of Medtronic market-released cardiac therapy products by analyzing product survival probabilities. Product-related adverse events, indicating the status of the product, are collected to measure survival probabilities. The data gathered in this study may also be used to support the design and development of investigational plans for new cardiac therapy products. The SLS is designed to continue indefinitely, encompassing new products as they become commercially available.

Eligible products for study enrollment include all Medtronic market-released cardiac therapy products. Medtronic may limit overall enrollment of any product when the number of enrollments provides an adequate number to effectively assess product survivability. Medtronic reserves the right to close enrollment of a product at a site level in order to ensure all participating sites have an equal opportunity to enroll.

To ensure a sufficiently large and representative source of data, participating clinical centers must meet specific selection criteria. In addition, centers are selected to be representative of the range of clinical environments in which Medtronic conducts business.

Investigators enroll qualified subjects with specific Medtronic market-released cardiac therapy products and follow these subjects from their implant date until they can no longer be followed (e.g., death and lost to follow-up). Using a Clinical Investigation Plan, each center monitors and reports on the performance of specific Medtronic market-released cardiac therapy products (e.g., product-related adverse events, replacements and abandonments) and subject status (e.g., subject death and subject withdrawal from the study). Subjects will be followed by their respective center in accordance with the center's established practices for routine follow-up.

Patients are eligible for enrollment in the study if:

- They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2. They participated in a qualifying study of a marketreleased Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

The Standard Actuarial Method is used to determine estimates of lead survival.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. The follow-up schedule for this study is based on utilizing routine, scheduled office/clinic visits and unscheduled office/ clinic visits prompted by symptoms or complaints. Data collected at each follow-up includes routine clinical electrical data, any system modifications, and any lead or generator adverse events.

Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is abandoned or explanted, the patient is no longer available for follow-up, or more than 24 months have passed since last follow-up. The data analyses assume that the patient is still part of the study and no lead complications had occurred as of the report cutoff date unless specifically reported by the center.

Medtronic evaluates center compliance with study protocol through clinical monitoring at each study site. Additionally, study center personnel must be trained in the study procedures prior to participating, and they must adhere to the policies and procedures of their local ethics boards.

Lead Complications

All adverse events are critically evaluated by a Medtronic technical review committee and the investigator is asked to assess the relationship of the adverse event to the presence or performance of the implanted system, generator and/or lead(s).

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3,000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance
- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Data Analysis Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

Survival times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, subject leaves the study, the lead is no longer being used, or no data has been reported within a specified time interval), or the cutoff date of the report. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are in the tables in this report.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in 1-year intervals, the curves are actually computed and plotted using 3-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, including data from 14 countries on four continents, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report for at least 20 years as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

Medtronic, at its discretion, may stop providing updated performance information on lead models that received original US market-release approval 20 or more years ago. These models may be removed from this report at that time.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

The results of the analysis is presented in four categories. The lead reporting categories are:

• Conductor Fracture: Conductor malfunction with complete or intermittent loss of continuity that could interrupt current flow (e.g., fractured conductors), including those associated with clavicle flex fatigue or crush damage.

- Insulation Breach: A malfunction of the insulation allowing inappropriate entry of body fluids or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, abrasions, and material degradation.
- Crimps/Welds/Bonds: Any malfunction in a conductor or lead body associated with a point of connection.
- Other: Malfunctions of specific lead mechanical attributes, such as sensors, connectors, seal rings, or malfunction modes not included in the three categories

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS centers around the world.

US Reports of Acute Lead Observations (Occurring within First Month of Service)

In the first weeks following lead implantation, physiologic responses and lead performance can vary until longterm lead stability is attained. Acute (defined as the first month after implant) lead performance may be subject to a number of factors, including patient-specific anatomy,

clinical conditions and/or varying implant conditions/ techniques. After a period of time, the implant and the lead performance stabilizes. It is for this reason that the System Longevity Study results, which are intended to measure long-term performance, do not include complications that occur within the first 30 days after implant.

Information about the clinical experience in the first month of service is included in this report. The source for this information is Medtronic's complaint handling system database. The information is summarized in tables titled "US Reports of Acute Lead Observations." To be included in this summary of observations, a lead must first be successfully implanted and registered in Medtronic's Device and Registrant Tracking system.

Each Event Report received by Medtronic's complaint handling system is assigned one or more Reason for Report codes based on the information received. The Reason for Report codes have been grouped into Acute Lead Observation categories. The categories used for this product performance report are drawn from the "FDA Guidance for Submission of Research and Marketing Applications for Permanent Pacemaker Leads and for Pacemaker Lead Adapter 510(k) Submissions." The categories are:

- 1. Cardiac Perforation
- 2. Conductor Fracture
- 3. Lead Dislodgement
- 4. Failure to Capture
- 5. Oversensing
- 6. Failure to Sense
- 7. Insulation Breach
- 8. Impedance Abnormal
- 9. Extracardiac Stimulation
- 10. Unspecified

Although multiple observations are possible for any given lead, only one observation is reported per lead. The observation reported is the observation highest on the list. For example, if an Event Report includes observations for both Lead Dislodgement and Failure to Sense, Lead Dislodgement is reported.

The lead event reported to Medtronic may or may not have involved clinical action or product returned to Medtronic. The lead may have remained implanted and in service.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides the number of leads registered as implanted and the number remaining active in the United States based on the status recorded in the Medtronic Device and Registrant Tracking system.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

2187 Attain LV

Product Characteristics

US Market Release	Aug-01	Serial Number Prefix	LEY	US Returned Product Analysis
Registered US Implants	11,900	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Conductor Fracture 0 Crimp/Weld/Bond 0
Estimated Active US Implants	3,100	Polarity	Unipolar	Insulation Breach 0
Advisories	None	Steroid	No	Other 1

System Longevity Study Results Qualifying Complications 1 Total 134 Failure to Capture Number of Leads Enrolled in Study 6,409 Cumulative Months of Follow-Up Number of Leads Active in Study 22 100 Lead Survival Probability (%) 90 80 2 3 4 5 8 9 10 Years After Implant 2 yr 3 yr 4 yr 1 yr at 54 mo % 99.1 99.1 99.1 99.1 99.1 109 92 71 57 51

2188 Attain CS

Effective Sample Size

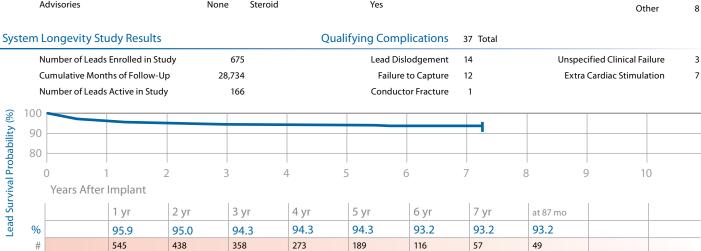
Product Characteristics

U	JS Market Release		Aug-01	Serial Nur	nber Prefix	LEB				US Retui	ned Product A	nalysi
R	Registered US Implan	ts	1,800	Type and	or Fixation		nous, Coronar Vein, Canted	/ Sinus/			ductor Fracture mp/Weld/Bond	
Е	stimated Active US I	mplants	300	Polarity		Bipolar					sulation Breach	
Α	Advisories		None	Steroid		No					Other	
tem l	Longevity Study	Results			Qua	lifying Comլ	olications	1 Total				
N	Number of Leads Enro	olled in Study	1:	5		Extra Cardiac	Stimulation	1				
C	Cumulative Months o	f Follow-Up	48	7								
N	Number of Leads Acti	ive in Study	(0								
100		ı	1									
90	Survival estimate n	ot available due	to insufficien	t sample size	2							
80												
00	1	2	3			5	6	7	8	9	10	
(0 1	2	5	_	+	5	0	/	ŏ	9	10	
	Years After Imp	olant										
90 80												
#												
#	Effective Sample Si											

4193 Attain OTW

Product Characteristics

US Market Release	May-02	Serial Number Prefix	ВАА	US Returned Product Analysis
Registered US Implants	100,600	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Conductor Fracture 41 Crimp/Weld/Bond 0
Estimated Active US Implants	40,200	Polarity	Unipolar	Insulation Breach 4
Advisories	None	Steroid	Yes	Other 8



4194 Attain OTW

Effective Sample Size

Product Characteristics

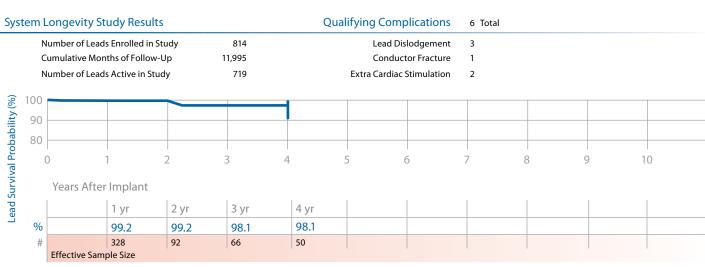
	US Market Releas	Aug-04	Serial Num	Serial Number Prefix		LFG				US Returned Product Analysis				
	Registered US Im	plants	99,800	Type and/o	r Fixation		ous, Left Ver ein, Distal D	tricular ouble Curve			or Fracture Veld/Bond	8		
	Estimated Active	64,100	64,100 Polarity						Insulation Breach					
	Advisories		None	Steroid		Yes				Other		6		
Systen	n Longevity Stu	udy Results			Quali	fying Comp	lications	16 Total						
	Number of Leads	Enrolled in Stud	dy 1,15	51		Lead Disl	odgement	9		Extra Cardia	c Stimulation	2		
	Cumulative Mont	25,77	74		Failure to Capture 4									
	Number of Leads	83	39		Insula	ation (ESC)	1							
Lead Survival Probability (%) 8 6 0														
roba 8	0													
/al F	0 1	2	3	4	5	5 6	5	7	8	9	10			
d Surviv	Years After	Implant												
Lead		1 yr	2 yr 3	3 yr	4 yr	5 yr								
(%	99.1	98.2	98.2	97.8	96.4								
	#	669	408 2	37	143	50								

Effective Sample Size

4195 Attain StarFix

Product Characteristics

US Market Release	Aug-08	Serial Number Prefix	AAD	LIC Poturned Product Analysis		
OS Iviai ket Neiease	Aug-00	Serial Nulliber Frenz	AAD	US Returned Product Analysis		
Registered US Implants	11,500	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein,	Conductor Fracture 1		
			Deployable Lobe Fixation	Crimp/Weld/Bond 0		
Estimated Active US Implants	9,600	Polarity	Unipolar	Insulation Breach 1		
Advisories	None	Steroid	Yes	Other 7		



4196 Attain Ability

Product Characteristics

	U	S Market Releas	se	May-09	Sei	rial Number Prefix	(PVI			US Retu	US Returned Product Analysi			
	R	egistered US Im	nplants	33,300	Туј	pe and/or Fixation		Transvenous, Left Preformed Body, I				nductor Fracture imp/Weld/Bond	2		
	E	stimated Active	29,100	0 Polarity			Bipolar			Insulation Breach					
	A	dvisories	None	Ste	eroid		Yes				Other	0			
Syste	m L	ongevity St	udy Results			Qı	ualifyin	g Complication	ns 1	0 Total					
	N	lumber of Leads	s Enrolled in Stu	udy 1,6	555			Lead Dislodgeme	ent -	4					
	C	umulative Mon	Jp 14,6	512			Failure to Captu	ıre	3						
	Number of Leads Active in Study			y 1,4	56		Extra	Cardiac Stimulation	on :	3					
% 10	00														
oility	90														
obal	30														
al Pro	() .	1 :	2 3		4	5	6	7	8	9	10			
Lead Survival Probability (%)		Years After	Implant												
-ead			1 yr	at 21 mo											
	%		99.2	99.2											
	#		371	38											
		Effective Samp													

4296 Attain Ability Plus

Product Characteristics

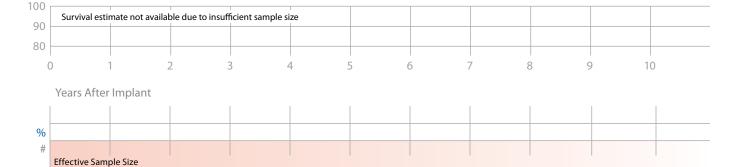
US Market Release	Apr-11	Serial Number Prefix	RRA	US Returned Product Analysis
Registered US Implants	500	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Conductor Fracture 0 Crimp/Weld/Bond 0
Estimated Active US Implants	500	Polarity	Bipolar	Insulation Breach 0
Advisories	None	Steroid	Yes	Other 0

System Longevity Study Results

Qualifying Complications

Total

Number of Leads Enrolled in Study	Lead Dislodgement
Cumulative Months of Follow-Up	Conductor Fracture
Number of Leads Active in Study	Extra Cardiac Stimulation



4396 Attain Ability Straight

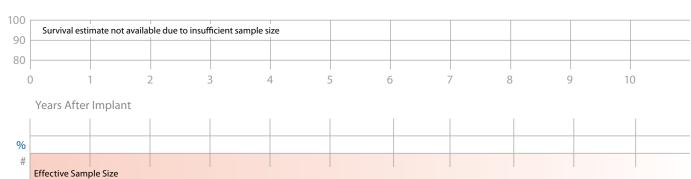
Product Characteristics

US Market Release	Mar-11	Serial Number Prefix	RAE	US Returned Product Analysis
Registered US Implants	300	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Tines	Conductor Fracture 0 Crimp/Weld/Bond 0
Estimated Active US Implants	300	Polarity	Bipolar	Insulation Breach 0
Advisories	None	Steroid	Yes	Other 0

System Longevity Study Results

Qualifying Complications

Number of Leads Enrolled in Study	Lead Dislodgement
Cumulative Months of Follow-Up	Failure to Capture
Number of Leads Active in Study	Extra Cardiac Stimulation



Lead Survival Summary (95% Confidence Interval)

		Se		Study		onths of tudy	Device Survival Probability (%)									
		t Relea	rolled	tive in	g tions	ve Mor p in Stu	Years A	fter Imp	lant							
Model Number	Family	US Market Release	Leads Enrolled	Leads Active in Study	Qualifying Complications	Cumulative Months of Follow-Up in Study	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
2187	Attain LV	Aug-01	134	22	1	6,409	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1 at 54 mo					
2188	Attain CS	Aug-01	15	0	1	487	100.0 at 0 mo									
4193	Attain OTW	May-02	675	166	37	28,734	95.9 +1.3/-1.8	95.0 +1.4/-2.1	94.3 +1.6/-2.3	94.3 +1.6/-2.3	94.3 +1.6/-2.3	93.2 +2.0/-2.9	93.2 +2.0/-2.9	93.2 +2.0/-2.9 at 87 mo		
4194	Attain OTW	Aug-04	1,151	839	16	25,774	99.1 +0.4/-0.8	98.2 +0.8/-1.2	98.2 +0.8/-1.2	97.8 +1.0/-1.7	96.4 +2.1/-4.7					
4195	Attain StarFix	Aug-08	814	719	6	11,995	99.2 +0.5/-1.2	99.2 +0.5/-1.2	98.1 +1.3/-4.2	98.1 +1.3/-4.2						
4196	Attain Ability	May-09	1,655	1,456	10	14,612	99.2 +0.4/-0.7	99.2 +0.4/-0.7 at 21 mo								
4296	Attain Ability Plus	Apr-11	500	500												
4396	Attain Ability Straight	Mar-11	300	300												

Source: System Longevity Study Data as of July 31, 2011

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
2187	Attain LV	Aug-01	11,900	3,100	0	0	0	1
2188	Attain CS	Aug-01	1,800	300	1	0	0	0
4193	Attain OTW	May-02	100,600	40,200	41	0	4	8
4194	Attain OTW	Aug-04	99,800	64,100	8	0	35	6
4195	Attain StarFix	Aug-08	11,500	9,600	1	0	1	7
4196	Attain Ability	May-09	33,300	29,100	2	0	0	0
4296	Attain Ability Plus	Apr-11	500	500	0	0	0	0
4396	Attain Ability Straight	Mar-11	300	300	0	0	0	0

Source: Returned Product Analysis Data as of July 31, 2011

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
2187	Attain LV	11,900	0	0	9	4	0	1	0	0	1	0
2188	Attain CS	1,800	0	0	2	0	0	0	0	0	0	0
4193	Attain OTW	100,600	0	0	45	11	1	0	0	0	15	2
4194	Attain OTW	99,800	1	2	85	19	1	0	1	6	18	3
4195	Attain StarFix	11,500	0	0	20	6	0	0	0	0	15	0
4196	Attain Ability	33,300	1	2	70	22	0	0	1	3	31	2
4296	Attain Ability Plus	500	0	0	0	0	0	0	0	0	0	0
4396	Attain Ability Straight	300	0	1	1	0	0	0	0	0	1	0

Report Cutoff Date: July 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain LV	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain CS	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 BI
4193	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI
4195	Attain StarFix	Transvenous Cardiac Vein Deployable Lobes	Polyurethane (55D)	MP35N	Platinum Alloy	IS-1 UNI
4196	Attain Ability	Transvenous Cardiac Vein Preformed Body	Polyurethane (outer) SI-polyimide (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI
4296	Attain Ability Plus	Transvenous Cardiac Vein Distal Double Curve	Polyurethane (outer) Silicone (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI
4396	Attain Ability Straight	Transvenous Cardiac Vein Tines	Polyurethane (outer) Silicone (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI

Defibrillation Leads

6721, 6921 Epricardial Patch

Product Characteristics

US Market Release	Feb-93	Serial Number Prefix	TBH, TBG, TBB, TAD, TAC, or TAB	US Returned Product Analysi	S
Registered US Implants	8,700	Type and/or Fixation	Epicardial Defib Patch, Suture	Conductor Fracture 6	56
Estimated Active US Implants	1,400	Polarity	Defib Electrode only	Crimp/Weld/Bond	1
Advisories	None	Steroid	No	Insulation Breach	9
				Other	0

System Longevity Study Results

Qualifying Complications 47 Total

132

95

64

56

51

		,				,						
Number of Leads Enrolled in Study			udy	407		Failure	to Capture	8 Impedance Out of Range				
(Cumulative Mon	ths of Follow-U	Jp 2	3,289		Conduct	or Fracture	21		Overse	ensing 12	
N	Number of Lead	s Active in Stud	у	7	Insul	ation (not furth	er defined)	2				
100												
90												
80												
70												
	0 1	1 2	2 3	3 4	1 5	5 6	5	7 8	3	9 1	10	
	Years After I	mplant										
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 111 mo	
%		96.5	95.0	92.7	91.9	90.0	85.1	83.7	83.7	83.7	83.7	

176

6930 Sprint Fidelis

330

Effective Sample Size of Lead Group Overall

301

256

Lead Survival Probability (%)

Product Characteristics

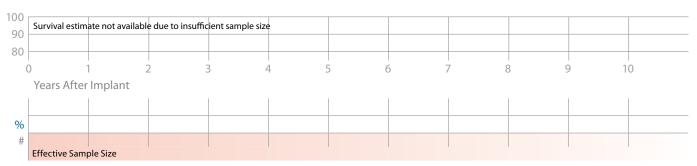
209

US Market Release	Sep-04	Serial Number Prefix	LFK	US Returned Product Analy	ysis
Registered US Implants	400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	3
Estimated Active US Implants	200	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories		Steroid	Yes	Insulation Breach	0
See page 151 – 2007 Potential Co	onductor			Other	0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 4 143 Cumulative Months of Follow-Up Number of Leads Active in Study



Lead Survival Probability (%)

6931 Sprint Fidelis

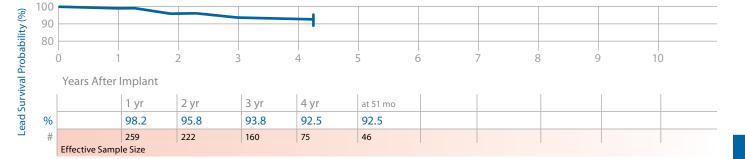
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFL	US Returned Product Analysis
Registered US Implants	8,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 404
Estimated Active US Implants	4,400	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond 0
Advisories		Steroid	Yes	Insulation Breach 0
See page 151 – 2007 Potential Co Wire Fracture	onductor			Other 3

System Longevity Study Results

Qualifying Complications 18 Total

Number of Leads Enrolled in Study	294	Lead Dislodgement	2	Impedance Out of Range	4
Cumulative Months of Follow-Up	10,789	Failure to Capture	3	Oversensing	3
Number of Leads Active in Study	177	Conductor Fracture	4	Other	1
		Enilura to Conco	1		



6932 Sprint

Lead Survival Probability (%)

Product Characteristics

US Market Release	Aug-96	Serial Number Prefix	TCA	US Returned Product Analysis
Registered US Implants	14,900	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture 20
Estimated Active US Implants	4,700	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 21
				Other 3

System Longevity Study Results

Qualifying Complications 10 Total

Number of Leads Enrolled in Study	411	Failure to Capture	2	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	24,716	Failure to Sense	2	Oversensing	4
Number of Leads Active in Study	53	Impedance Out of Range	1		



6933, 6937, 6937A, 6963 SVC/CS **Product Characteristics**

	US Mark	ket Relea	ise		[Dec-93	Sei	rial Nun	nber Pre	efix	TAT	, TBU, TI	OB, TAF				US Re	eturne	d Pro	duct A	nalysis
	Register	red US In	nplants			16,100	Тур	oe and/	or Fixati	ion	Tra	nsvenou	s CS or SVC	Defib				Cond	uctor Fi	racture	165
	Estimate	ed Activ	e US Im	plants		2,500	Ро	larity			One	e Coil						Crin	np/Welc	d/Bond	0
	Advisor	ies				None	Ste	eroid			No							Ins	ulation	Breach	31
																				Other	3
ten	n Longe	evity St	tudy R	esults						Qual	ifying	Comp	lications	47 T	otal						
	Numbei	r of Lead	ls Enroll	ed in Stu	dy		966				L	ead Disl	odgement	1			In	npedan	ce Out o	of Range	3
	Cumulative Months of Follow-Up 54,319 Failure to Capture 6									Unspecified Clinical Failure											
	Number	r of Lead	ls Active	in Study	/		22				C	onducto	or Fracture	16			Ex	tra Card	diac Stir	nulation	4
												Failu	e to Sense	1					Ove	rsensing	10
										Insula	ation (n	ot furthe	er defined)	2							
10																					
	30																				
	0	1	2	3	4	5	6	7	8	9	10	11 1	2 13	14	15	16	17	18	19	20	21
	Years	After	Implai	nt																	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 138 mo								
9	6	98.4	97.5	97.2	96.7	95.4	94.9	93.9	93.4	92.2	91.2	91.2	91.2								
	4	000	677	FCC	470	201	200	212	162	107	77	F7	40								



6935 Sprint Quattro Secure **Product Characteristics**

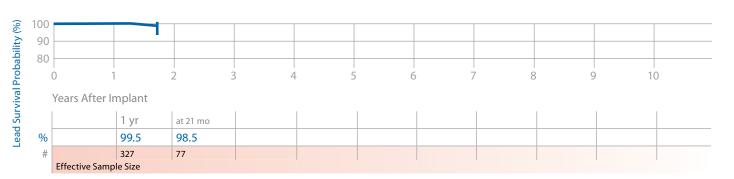
US Market Release	Nov-08	Serial Number Prefix	TAU	US	Returned Product An	alysis
Registered US Implants	21,800	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in		Conductor Fracture	10
Estimated Active US Implants	20, 200	Polarity	True Bipolar/One Coil		Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes		Insulation Breach	0
Performance Note: <u>See page 158</u> Helix Retraction of the Sprint Quatand Sprint Quattro Secure 6947		5			Other	6

Qualifying Complications

5 Total

System Longevity Study Results

Number of Leads Enrolled in Study 1,040 **Conductor Fracture** Cumulative Months of Follow-Up 10,220 Failure to Sense 1 Number of Leads Active in Study 955 Oversensing



6936, 6966 Transvene

Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TAV, TAL	US Returned Product An	alysis
Registered US Implants	23,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	176
Estimated Active US Implants	2,500	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	336
				Other	7

System Longevity Study Results

Qualifying Complications 187 Total

7	dance Out of Range	Imped		15	ure	to Capt	Failure				1,349		rolled in Study	Number of Leads Enrol
5	ified Clinical Failure	Unspecif		21	ure	or Fract	Conduc	(5,048	7:	of Follow-Up	Cumulative Months of
6	Cardiac Stimulation	Extra C		7	nse	re to Se	Failu				21		tive in Study	Number of Leads Activ
112	Oversensing			14	ed)	er defin	ot furth	ation (n	Insu					
														100
														100



Years After Implant

Lead Survival Probability (%)

			1															
		1 yr	2 yr	3 yr	4 yr	5 yr	буг	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 150 mo				
%		98.2	97.0	95.2	94.3	91.1	86.8	79.8	75.9	70.2	65.8	63.6	61.8	59.5				
#		1,140	956	807	659	530	414	284	210	142	104	75	56	49				
	Effecti	ve Samı	ple Size															

6939, 6999 Sub-Q Patch

Product Characteristics

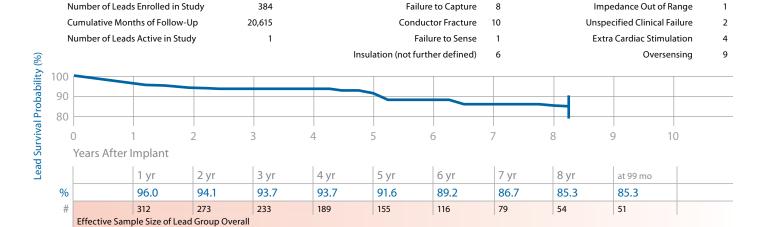
384

US Market Release	Dec-93	Serial Number Prefix	TBA, TAP	US Returned Product Analysis
Registered US Implants	3,700	Type and/or Fixation	Subcutaneous Defib Patch, Suture	Conductor Fracture 28
Estimated Active US Implants	300	Polarity	Defib Electrode Only	Crimp/Weld/Bond 0
Advisories	None	Steroid	No	Insulation Breach 4
				Other 1

System Longevity Study Results

Qualifying Complications 41 Total

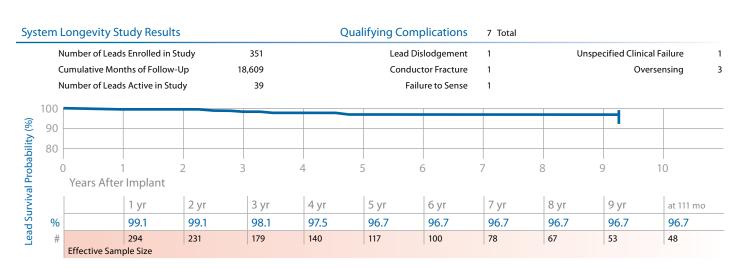
8



6942 Sprint

Product Characteristics

US Market Release	Jul-97	Serial Number Prefix	ТСВ	US Returned Product Analysi	is
Registered US Implants	17,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	14
Estimated Active US Implants	5,900	Polarity	Integrated Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	21
				Other	2



6943 Sprint

Product Characteristics

1,311

US Market Release	Oct-97	Serial Number Prefix	TCE	US Returned Product An	alysis
Registered US Implants	20,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	59
Estimated Active US Implants	7,000	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	23
				Other	3

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 81 Total Lead Dislodgement

					ollow-U		7	77,836 269				(Failure to Conductor Failure	Fractur	e 17	7				nce Out ed Clini Ov		re ng	8 3 36
(%)	100																				Oti		
oility	90											-											
obak	80																						
al Pr	C)	1 2	2 3	3 4	1 !	5 (6 7	7 8	3 9	9 1	0 1	1 12	13	14	15	16	17	18	19	20	21	
urviv		Years	After	Impla	ant																		
Lead Survival Probability (%)			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 126 mo										
	%		98.6	97.7	96.5	95.6	93.7	92.4	91.5	91.2	89.9	87.9	87.9										
	#	Efforti	1,146	981 ole Size	874	745	615	478	347	248	144	64	46										

Insulation (not further defined)

6944 Sprint Quattro

Product Characteristics

US Market Release	Dec-00	Serial Number Prefix	TDC	US Returned Product An	alysis
Registered US Implants	38,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	65
Estimated Active US Implants	21,100	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	2
				Other	1

System Longevity Study Results **Qualifying Complications** 5 Total 425 Number of Leads Enrolled in Study Failure to Sense Cumulative Months of Follow-Up 12,245 Impedance Out of Range Number of Leads Active in Study 258 **Unspecified Clinical Failure** 1 Oversensing 2 Lead Survival Probability (%) 100 90 80 2 3 4 5 6 8 9 10 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr at 78 mo 94.6 % 100.0 100.0 99.1 97.0 94.6 94.6 # 239 140 102 82 61 56 51 **Effective Sample Size**

6945 Sprint

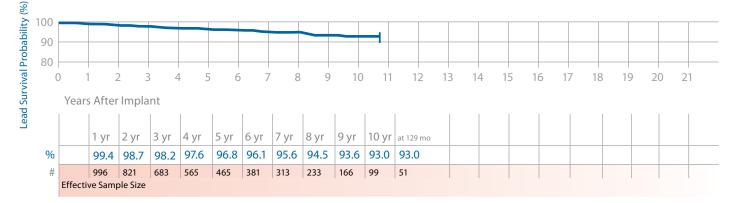
Product Characteristics

US Market Release	Sep-97	Serial Number Prefix	TDA	US Returned Product An	alysis
Registered US Implants	42,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	108
Estimated Active US Implants	14,100	Polarity	Integrated Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	32
				Other	6

System Longevity Study Results

Qualifying Complications 37 Total

Number of Leads Enrolled in Study	1,154	Failure to Capture	2	Unspecified Clinical Failure	1
Cumulative Months of Follow-Up	65,570	Conductor Fracture	7	Extra Cardiac Stimulation	1
Number of Leads Active in Study	147	Failure to Sense	4	Oversensing	17
		Impedance Out of Range	5		



6947 Sprint Quattro Secure

Product Characteristics

US Market Release	Nov-01	Serial Number Prefix	TDG	US Returned Product Analysis
Registered US Implants	321,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 265
Estimated Active US Implants	225,900	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond 4
Advisories	None	Steroid	Yes	Insulation Breach 15
Performance Note: See page 158 Helix Retraction of the Sprint Qua and Sprint Quattro Secure 6947		35		Other 54

System Longevity Study Results

Qualifying Complications 29 Total

Number of Leads Enrolled in Study	2,703	Lead Dislodgement	3	Impedance Out of Range	6
Cumulative Months of Follow-Up	96,273	Failure to Capture	1	Unspecified Clinical Failure	2
Number of Leads Active in Study	1,537	Conductor Fracture	4	Oversensing	9
		Failure to Sense	2		



6948 Sprint Fidelis

Effective Sample Size

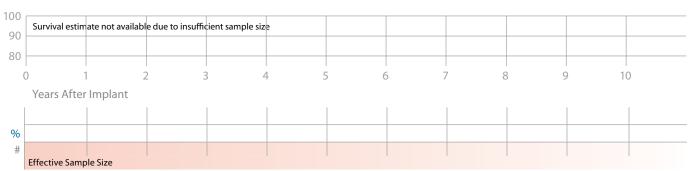
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product Ana	ılysis
Registered US Implants	10,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	102
Estimated Active US Implants	5,800	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	0
Advisories		Steroid	Yes	Insulation Breach	1
See page 151 – 2007 Potential Co Wire Fracture	nductor			Other	0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	30
Cumulative Months of Follow-Up	1,253
Number of Leads Active in Study	19



Lead Survival Probability (%)

6949 Sprint Fidelis

Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFJ	US Returned Product Ar	alysis
Registered US Implants	186,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	4,724
Estimated Active US Implants	97,400	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	2
Advisories		Steroid	Yes	Insulation Breach	11
See page 151 – 2007 Potential Co Wire Fracture	onductor			Other	45

System Longevity Study Results

Qualifying Complications 49 Total

Number of Leads Enrolled in Study	795	Lead Dislodgement	1	Insulation (not further defined)	1
Cumulative Months of Follow-Up	33,013	Failure to Capture	2	Impedance Out of Range	9
Number of Leads Active in Study	388	Conductor Fracture	20	Oversensing	13
		Failure to Sense	2	Other	1



6996 Sub-Q Lead

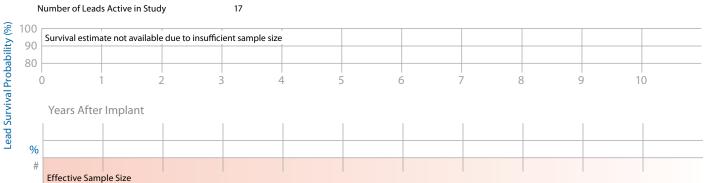
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	TCR	US Returned Product Ana	ılysis
Registered US Implants	3,200	Type and/or Fixation	Subcutaneous Defib Coil, Suture	Conductor Fracture	12
Estimated Active US Implants	1,900	Polarity	One Defib Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	0
				Other	0

System Longevity Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	30	Conductor Fracture	1
Cumulative Months of Follow-Up	822		



	Lead Survival Summary (95% Confidence Interval)	ummai	ry (95%	Confide	nce Inte	ırval)													
		əsɐə႞ર	pa	ýpnì2 ni	sı	Nonths in Study	Device 5	Survival I	Device Survival Probability (%)	ty (%)									
oer H	٨	arket Re	Enrolle	evitɔA ;	fying Jicatior	l avitslı qU-wol	Years Af	Years After Implant	ant	_	_	-	-	-	-	-	_		
əpoW	rlims 7	ew sn	speə7	speəŋ	Qualit Gomp		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr	18 yr
6721, 6921	Epicardial Patch	Feb-93	407	7	47	23,289	96.5 +1.5/-2.4	95.0	92.7 +2.3/-3.4	91.9 +2.5/-3.5	90.0	85.1 +3.9/-5.2	83.7 +4.2/-5.6	83.7 +4.2/-5.6	83.7 +4.2/-5.6 at 111 mo				
6930	Sprint Fidelis	Sep-04	4	2	0	143	100.0 at 0 mo												
	Advisories: See page 151 –	- 2007 Potential Conductor Wire Fracture	ial Conduc	tor Wire Fra	cture														
6931	Sprint Fidelis	Sep-04	294	17.7	18	10,789	98.2 +1.1/-2.5	95.8 +1.9/-3.2	93.8 +2.4/-3.9	92.5 +2.8/-4.4	92.5								
	Advisories: See page 151 –	– 2007 Potential Conductor Wire Fracture	ial Conduc	tor Wire Fra	cture						at 51 mo								
6932	Sprint	Aug-96	411	53	10	24,716	99.2 +0.5/-1.7	98.3 +0.9/-2	98.3 +0.9/-2	98.3 +0.9/-2	97.8	97.8	97.8	96.8 +1.8/-3.8	96.8	95.1 +2.8/-6.4 at 129 mo			
6933, 6937, 6937A, 6963	svc/cs	Dec-93	996	22	47	54,319	98.4 +0.7/-1.0	97.5	97.2 +0.9/-1.4	96.7	95.4	94.9	93.9	93.4 +1.9/-2.7	91.2	91.2 +2.8/-4.2 at 138 mo			
6935	Sprint Quattro Secure Nov-08 1,040 955 5 See page 158 – Performance note on Helix Retraction 6935 and 6947	Nov-08 ce note on H	1,040 elix Retract	955 ion 6935 ar	5 1d 6947	10,220	99.5 +0.3/-1.2	98.5 +1.0/-2.7 at 21 mo											
6936,	Transvene	Dec-93	1,349	21	187	75,048	98.2 +0.6/-1	97.0 +0.8/-1.2	95.2	94.3 +1.3/-1.6	91.1	86.8 +2.3/-2.8	79.8	75.9	65.8	61.8 +5.6/-6.2	59.5 +6.2/-6.8 at 150 mo		
6669	Sub-Q Patch	Dec-93	384	-	14	20,615	96.0 +1.6/-2.7	94.1 +2/-3.1	93.7 +2.2/-3.2	93.7 +2.2/-3.2	91.6	89.2 +3.3/-4.7	86.7 +4/-5.5	85.3 +4.6/-6.4	85.3 +4.6/-6.4 at 99 mo				
6942	Sprint	76-Inf	351	39	^	18,609	99.1 +0.6/-1.9	99.1 +0.6/-1.9	98.1 +1.1/-2.7	97.5	96.7	96.7	96.7	96.7	96.7 +1.8/-3.7 at 111 mo				
6943	Sprint	Oct-97	1,311	569	81	77,836	98.6 +0.5/-0.9	97.7 +0.7/-1.1	96.5 +1.0/-1.2	95.6	93.7	92.4	91.5	91.2	87.9 +3.2/-4.3	87.9 +3.2/-4.3 at 126 mo			
6944	Sprint Quattro	Dec-00	425	258	5	12,245	100.0	100.0	99.1 +0.8/-5.5	97.0 +2/-5.9	94.6	94.6 +3.1/-7.2	94.6 +3.1/-7.2 at 78 mo						
6945	Sprint	Sep-97	1,154	147	37	65,570	99.4 +0.4/-0.6	98.7 +0.5/-1	98.2 +0.7/-1.1	97.6 +0.8/-1.3	96.8 +1.1/-1.6	96.1	95.6	94.5	93.0 +2.2/-3.1	93.0 +2.2/-3.1 at 129 mo			
6947	Sprint Quattro Secure Nov-01 2,703 1,537 29 See page 158 – Performance note on Helix Retraction 6935 and 6947	Nov-01 ce note on H	2,703 Ielix Retract	1,537 tion 6935 ar	29 nd 6947	96,273	99.5 +0.2/-0.3	99.3 +0.3/-0.4	99.0	98.7	98.2 +0.7/-1	97.9	97.6 +0.9/-1.4	96.8 +1.4/-2.6	96.8 +1.4/-2.6 at 102 mo				
6948	Sprint Fidelis	Sep-04	30	19	0	1,253	100.0 at 0 mo												
	Advisories: See page 151 – .	- 2007 Potential Conductor Wire Fracture	ial Conduc	tor Wire Fra	cture														
6949	Sprint Fidelis	Sep-04	795	388	49	33,013	98.7 +0.6/-1.2	96.9	94.6 +1.5/-2.1	92.6 +1.9/-2.4	91.5	90.6							
	Advisories: See page 151 – 2007 Potential Conductor Wire Fracture	2007 Potent	tial Conduc	tor Wire Fra	acture							at como							
9669	Sub-Q Lead	Jun-01	30	17	-	822	100.0 at 0 mo												

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
6721, 6921	Epicardial Patch	Feb-93	8,700	1,400	66	1	9	0
6930	Sprint Fidelis	Sep-04	400	200	3	0	0	0
6931	Sprint Fidelis	Sep-04	8,100	4,400	404	0	0	3
6932	Sprint	Aug-96	14,900	4,700	20	0	21	3
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	16,100	2,500	165	0	31	3
6935	Sprint Quattro Secure	Nov-08	21,800	20,200	10	0	0	6
6936, 6966	Transvene	Dec-93	23,600	2,500	176	0	336	7
6939, 6999	Sub-Q Patch	Dec-93	3,700	300	28	0	4	1
6942	Sprint	Jul-97	17,700	5,900	14	1	21	2
6943	Sprint	Oct-97	20,700	7,000	59	1	23	3
6944	Sprint Quattro	Dec-00	38,600	21,100	65	1	2	1
6945	Sprint	Sep-97	42,600	14,100	108	1	32	6
6947	Sprint Quattro Secure	Nov-01	321,700	225,900	265	4	15	54
6948	Sprint Fidelis	Sep-04	10,400	5,800	102	0	1	0
6949	Sprint Fidelis	Sep-04	186,600	97,400	4,724	2	11	45
6996	Sub-Q Lead	Jun-01	3,200	1,900	12	0	0	0

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
6721, 6921	Epicardial Patch	8,700	1	1	0	0	1	0	2	4	0	6
6930	Sprint Fidelis	400	0	0	0	0	0	0	0	0	0	1
6931	Sprint Fidelis	8,100	1	2	1	1	3	1	0	0	0	0
6932	Sprint	14,900	0	0	4	2	0	2	0	1	0	2
6933, 6937, 6937A, 6963	SVC/CS	16,100	0	0	1	1	1	0	1	0	0	5
6935	Sprint Quattro Secure	21,800	3	3	12	13	13	2	1	9	0	2
6936, 6966	Transvene	23,600	5	2	1	5	3	4	1	1	0	4
6939, 6999	Sub-Q Patch	3,700	0	0	0	0	0	0	0	0	0	1
6942	Sprint	17,700	0	1	1	4	1	0	0	3	0	2
6943	Sprint	20,700	1	0	0	1	1	1	1	2	0	0
6944	Sprint Quattro	38,600	0	2	11	10	10	3	0	6	0	6
6945	Sprint	42,600	0	1	4	7	9	1	2	1	1	1
6947	Sprint Quattro Secure	321,700	17	17	75	53	83	19	3	47	1	17
6948	Sprint Fidelis	10,400	0	1	7	7	2	0	0	0	0	2
6949	Sprint Fidelis	186,600	9	39	22	30	30	22	6	16	0	19
6996	SubQ	3,200	0	0	1	0	1	0	0	1	0	0

Report Cutoff Date: July 31, 2011

Reference Chart

			Pin Conf	figuration	_		
Model Number	Family	Туре	Pace/Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
6934S	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid
6935	Sprint Quattro Secure	Endo RV True Bipolar Sensing	IS-1	DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture

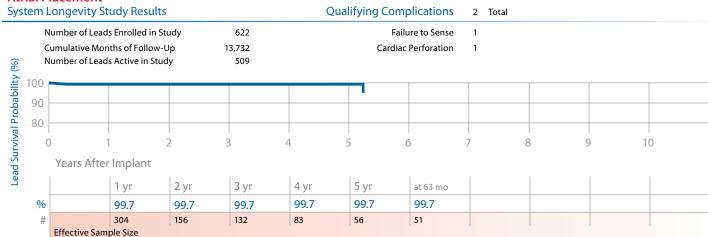
Pacing Leads

3830 SelectSecure

Product Characteristics

US Market Release	Aug-05	Serial Number Prefix	LFF	US Returned Product Anal	ysis
Registered US Implants	20,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	2
Estimated Active US Implants	16,400	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	7
				Other	3

Atrial Placement

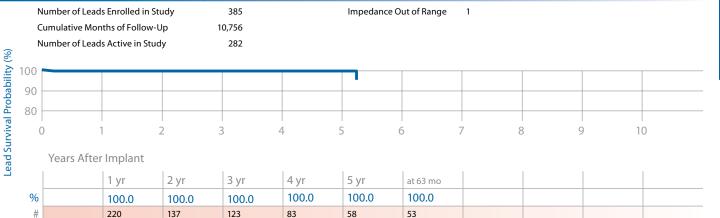


Ventricular Placement

System Longevity Study Results

Effective Sample Size





4023 CapSure SP

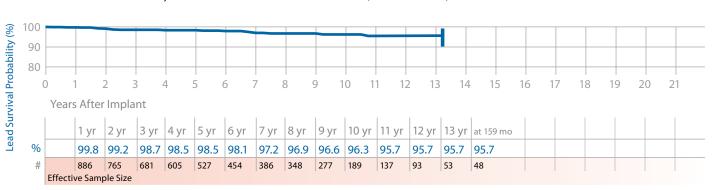
Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	LAK	US Returned Product Analysis
Registered US Implants	41,100	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 14
Estimated Active US Implants	8,000	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 4
				Other 2

System Longevity Study Results

Qualifying Complications 22 Total

Number of Leads Enrolled in Study	1,158	Lead Dislodgment	2	Impedance Out of Range	2
Cumulative Months of Follow-Up	72,820	Failure to Capture	16	Extra Cardiac Stimulation	1
Number of Leads Active in Study	250	Insulation (not further defined)	1		



4024 CapSure SP

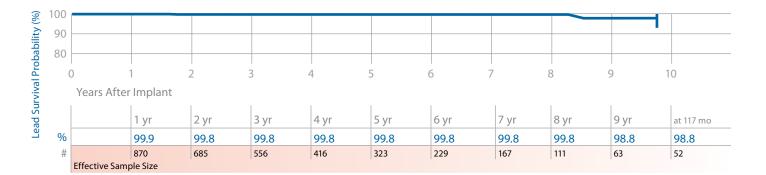
Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAJ	US Returned Product Ana	ysis
Registered US Implants	221,300	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	29
Estimated Active US Implants	45,600	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	147
				Other	8

System Longevity Study Results

Qualifying Complications 4 Total

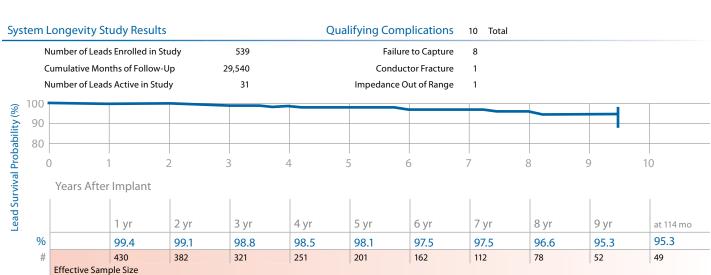
Number of Leads Enrolled in Study	1,215	Failure to Capture	3
Cumulative Months of Follow-Up	50,877	Insulation (not further defined)	1
Number of Leads Active in Study	18		



4033 CapSure Z

Product Characteristics

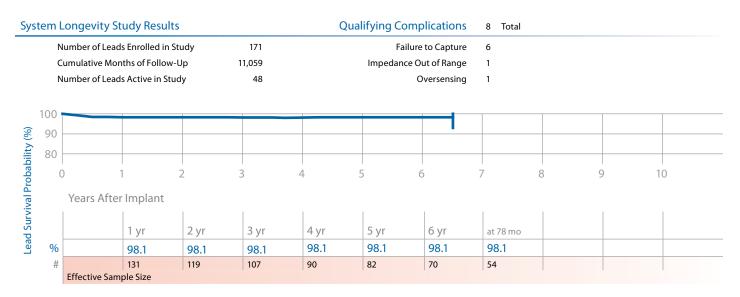
US Market Release	Not US released	Serial Number Prefix	LCA	US Returned Product Analysis
Registered US Implants	NA	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 0
Estimated Active US Implants	NA	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
				Other 0



4067 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LCV	US Returned Product Analysis
Registered US Implants	1,000	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 1
Estimated Active US Implants	200	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
				Other 0



4068 CapSureFix

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCE	US Returned Product An	alysis
Registered US Implants	124,300	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	41
Estimated Active US Implants	33,700	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	125
				Other	5

Atrial Placement

System Longevity Study Results Qualifying Complications 69 Total

Number of Leads Enrolled in Study	2,413	Lead Dislodgement	8	Insulation (ESC)	2
Cumulative Months of Follow-Up	131,388	Failure to Capture	22	Insulation (MIO)	2
Number of Leads Active in Study	339	Conductor Fracture	2	Impedance Out of Range	7
		Failure to Sense	11	Unspecified Clinical Failure	3
		Insulation (not further defined)	2	Extra Cardiac Stimulation	2
				Oversensing	8



	Tears	Aitei	ППріа	IIIC															
		1 vr	2 vr	3 vr	4 vr	5 vr	6 vr	7 vr	8 vr	9 vr	10 vr	11 vr	12 vr	13 vr	at 159 mo				
%		-	-	-	-	+ -	-	96.9	-	-	_			91.1	91.1				
#		1,907	1,637	1,370	1,116	898	735	567	448	321	232	177	117	61	45				
	Effectiv	ve Samr	ole Size																

Ventricular Placement

System Longevity Study Results

Qualifying Complications

N	Number	of Lead	ds Enro	lled in S	Study		1,799					F	ailure	to Cap	ture	21			li li	mpedar	ice Out	of Rang	је	7
C	Cumulat	ive Mo	nths of	Follow-	-Up		93,767					Co	nduct	or Frac	ture	3	3 Unspecified Clinical Failure					re	2	
N	Number	of Lead	ds Activ	e in Stu	ıdy		259						Failu	re to Se	ense	se 3 Extra Cardiac Stimulation					nc	2		
										Ins	ulatio	n (not	furth	er defir	ned)	1					Ove	ersensir	ıg	5
100																								
100													J											
90													╁									-	-	
80																								
		1	1	1	1			7	0		10	11	1	 		1 /	1 -	10	17	10	10	20	21	
	0	I	2	3	4	5	6	/	8	9	10	11	- 1	2	3	14	15	16	1/	18	19	20	21	
	Year	s Afte	er Imp	lant																				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10	yr 1	1 yr	at 138 r	no									
		-	-					-			_			_		_	_						\rightarrow	

94.2 94.2 92.6

65

169

105

Lead Survival Probability (%)

%

1,426 1,218 1,031 831

Effective Sample Size

99.3 | 98.7 | 98.7 | 98.2 | 97.8 | 97.3 | 96.2 | 95.5 | 94.2

4073 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBF	US Returned Product Analysis
Registered US Implants	700	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 0
Estimated Active US Implants	300	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
				Other 0



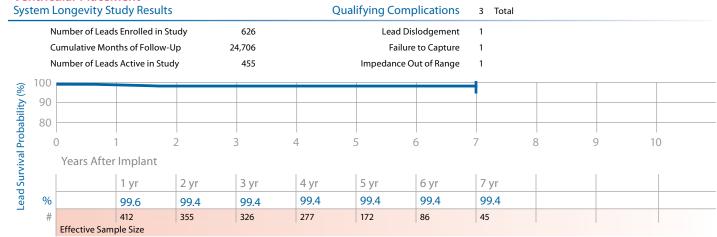
4074 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBD	US Returned Product Analysis
Registered US Implants	82,200	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 1
Estimated Active US Implants	52,600	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 14
				Other 1

1	Number of Lead	ls Enrolled in	Study	214		Lead	l Dislodgement	1			
Cumulative Months of Follow-Up		•	13,314 Failure to Sense			1	1				
	Number of Lead			152							
00											
90											
80											
	0	1	2	3	4	5	6	7	8	9	10
	Years Afte	r Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr			
%		99.1	99.1	99.1	99.1	99.1	99.1	99.1			
/0											

Ventricular Placement



4076 CapSureFix Novus

Product Characteristics

US Market Release	Feb-04	Serial Number Prefix	BBL	US Returned Product Ana	lysis
Registered US Implants	349,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	17
Estimated Active US Implants	271,600	Polarity	Bipolar	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	14
				Other	16

Atrial Placement

Syste	System Longevity Study Results Qualifying Complications								6 Total			
	Number of Leads Enrolled in Study		ıdy	1,657		Lead Dis	lodgement	3				
	Cumulative Months of Follow-Up		p 4.	5,725		Failure	to Capture	1				
	Number of Leads Active in Study		y	1,280		Failu	re to Sense	1				
						Insul	ation (not furth	er defined)	1			
(%	100											<u> </u>
Lead Survival Probability (%)	90											
abili	80											
roba			1		1	1	- ,		7		1	
al P		0 Years After	I Implant	_	3	4 !	5 (5	/	8	9 1	0
Z.		l ears Arter		I	I	I	I	I	1	1	I	ı
l Su			1 yr	2 yr	3 yr	4 yr	5 yr	at 66 mo				
ead	%		99.8	99.6	99.6	99.6	99.6	99.6				
	#		1,370	650	427	228	99	61				
		Effective Sam	ple Size									

Ventricular Placement

100

System Longevity Study Results Qualifying Complications 3 Total

Number of Leads Enrolled in Study Failure to Capture 2 1,226 Cumulative Months of Follow-Up 38,391 Extra Cardiac Stimulation Number of Leads Active in Study 908



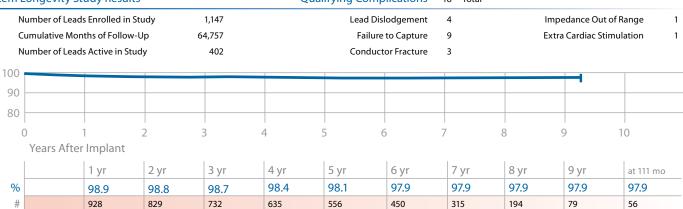
4092 CapSure SP Novus

Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEP	US Returned Product Analysis
Registered US Implants	169,200	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 7
Estimated Active US Implants	80,900	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 31
				Other 1

System Longevity Study Results

Qualifying Complications 18 Total



4523 CapSure SP

Effective Sample Size

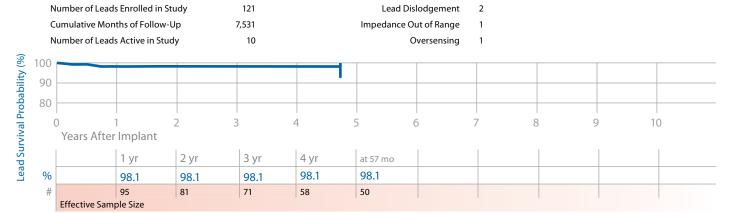
Lead Survival Probability (%)

Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	ZE	US Returned Product Analysis
Registered US Implants	11,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 1
Estimated Active US Implants	2,600	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 2
				Other 1

System Longevity Study Results

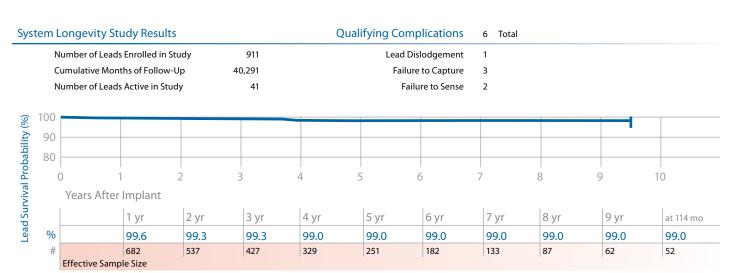
Qualifying Complications 4 Total



4524 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAR	US Returned Product Analysis
Registered US Implants	101,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 1
Estimated Active US Implants	26,100	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 49
				Other 3



4533 CapSure Z

Product Characteristics

206

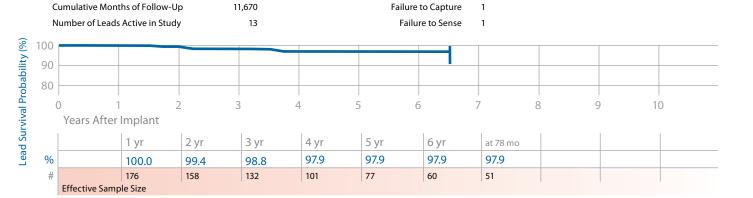
US Market Release	Not US released	Serial Number Prefix	LCB	US Returned Product Anal	ysis
Registered US Implants	NA	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	0
Estimated Active US Implants	NA	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	0
				Other	0

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 4 Total Lead Dislodgement

1

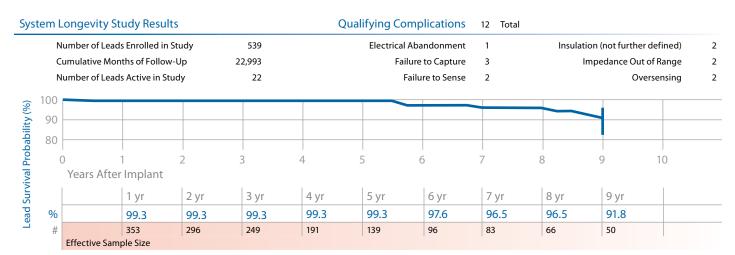


Oversensing

4558M Screw-In

Product Characteristics

US Market Releas	e	Nov-94	Serial Number Prefix	LDC	US Returned Product Analysis	
Registered US Im	plants	19,900	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture	1
Estimated Active	US Implants	4,300	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories		None	Steroid	No	Insulation Breach 1	8
					Other	0



4568 CapSureFix

Product Characteristics

656

31,676

US Market Release	Jan-97	Serial Number Prefix	LDD	US Returned Product Ana	lysis
Registered US Implants	69,600	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture	3
Estimated Active US Implants	24,400	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	49
				Other	1

System Longevity Study Results

Number of Leads Enrolled in Study

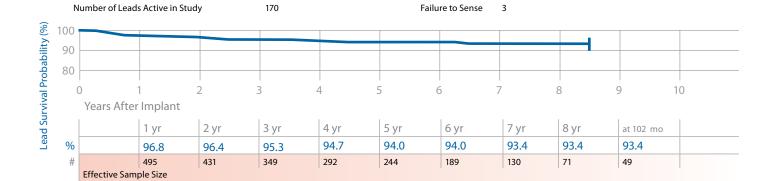
Cumulative Months of Follow-Up

Qualifying Complications 33 Total Lead Dislodgement

Failure to Capture

9

18



Impedance Out of Range

Medical Judgment

4574 CapSure Sense

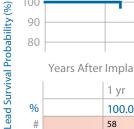
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBE	US Returned Product Analysis
Registered US Implants	53,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 5
Estimated Active US Implants	37,200	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 2
				Other 0

System Longevity Study Results

Qualifying Complications 0 Total

200 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 2,314 163 Number of Leads Active in Study



100



4592 CapSure SP Novus

Product Characteristics

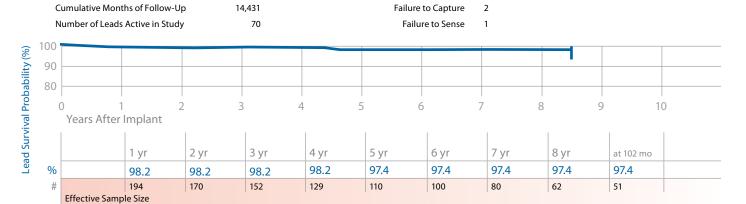
283

US Market Release	Oct-98	Serial Number Prefix	LER	US Returned Product Ana	alysis
Registered US Implants	82,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	6
Estimated Active US Implants	41,700	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	11
				Other	1

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 5 Total Lead Dislodgement



5023, 5023M CapSure SP

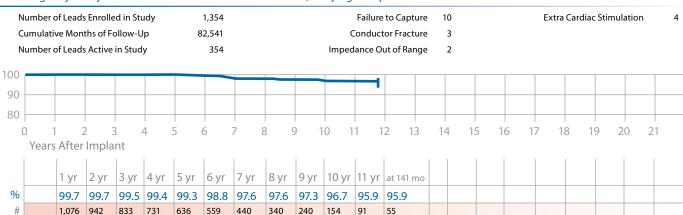
Product Characteristics

US Market Release		Nov-88	Serial Number Prefix	SX or LAS	US Returned Product Analy	ysis
Registered US Implar	nts	9,800	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	5
Estimated Active US I	Implants	2,200	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories		None	Steroid	Yes	Insulation Breach	0
					Other	0



Lead Survival Probability (%)

Qualifying Complications Total 19



5024, 5024M CapSure SP

Effective Sample Size

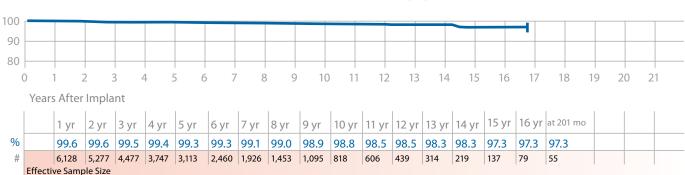
Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	SY or LAT	US Returned Product Analysis
Registered US Implants	200,700	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 51
Estimated Active US Implants	46,400	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 48
				Other 9

System Longevity Study Results

Qualifying Complications 56 Total

	Number of Leads Enrolled in Study	8,153	Lead Dislodgement	6	Impedance Out of Range	3
	Cumulative Months of Follow-Up	441,293	Failure to Capture	27	Unspecified Clinical Failure	1
	Number of Leads Active in Study	348	Conductor Fracture	3	Extra Cardiac Stimulation	2
			Failure to Sense	2	Oversensing	4
			Insulation (not further defined)	5	Other	2
			Insulation (ESC)	1		
100						



Lead Survival Probability (%)

Effective Sample Size

5033 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDK	US Returned Product Analysis
Registered US Implants	2,300	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 1
Estimated Active US Implants	500	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
				Other 0



5034 CapSure Z

Product Characteristics

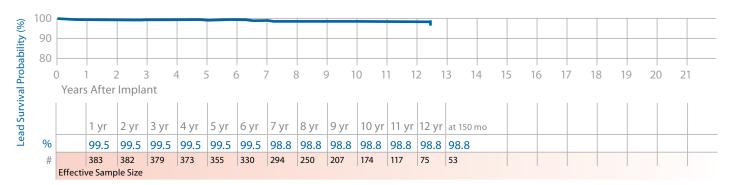
US Market Release	Feb-96	Serial Number Prefix	LDF	US Returned Product Analysis
Registered US Implants	56,000	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 12
Estimated Active US Implants	13,600	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 12
				Other 3

Atrial Placement

System Longevity Study Results

Qualifying Complications 5 Total

Number of Leads Enrolled in Study	386	Failure to Capture	2	Impedance Out of Range
Cumulative Months of Follow-Up	43,189	Conductor Fracture	1	
Number of Leads Active in Study	141	Failure to Sense	1	



Ventricular Placement

N	lumber	of Lead	s Enrolle	ed in Stu	udy		1,209					Lead I	Dislodge	ment	1				Fa	ailure to	Sense	
			ths of F		•		4,335						ire to Ca		7							
N	lumber	of Lead	s Active	in Stud	у		16					Cond	uctor Fra	cture	1							
100																						
90																						
80																						
00		1	1	1			1															
	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
		1 s Aftei	† 2 · Impla	3 int	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
		1 s Aftei	2 Impla	3 int	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
			2 Impla		4 4 4 yr	5 5 5 yr		7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7		9	10	11	12	13	14	15	16	17	18	19	20	21
		1 s After		3 ant 3 yr 99.1	· 		6 6 yr 98.8	-	8 yr 96.6		10	11	12	13	14	15	16	17	18	19	20	21

Number of Leads Active in Study

5054 CapSure Z Novus

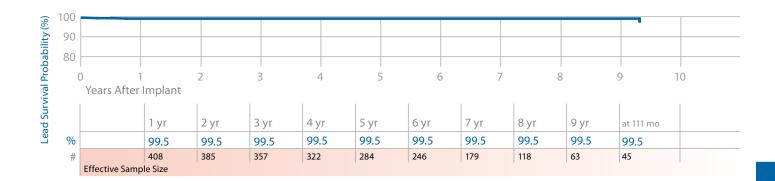
Product Characteristics

176

US Market Release	Jun-98	Serial Number Prefix	LEH	US Returned Product Analysis
Registered US Implants	93,000	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 8
Estimated Active US Implants	42,200	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 17
				Other 3

Atrial Placement

Longevity Study Results		Qualifying Complications	2 Total	
Number of Leads Enrolled in Study	424	Lead Dislodgement	1	
Cumulative Months of Follow-Up	31,594	Failure to Capture	1	



Ventricular Placement

%

99.5

656

Effective Sample Size

99.4

513

99.4

387

Syst	em l	Longevity St	tudy Resul	ts		Q	ualifying Co	mplications	9 Total						
Number of Leads Enrolled in Cumulative Months of Follo Number of Leads Active in S				/-Up	967 37,968 120		Fail	Dislodgement ure to Capture ailure to Sense	1 6 1	Impedance Out of Range					
(%)	100										_				
	90														
robability	80														
l Pro		0	1	2	3	4	5	6	7	8	9 10				
viva		Years After	r Implant												
ead Sur			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr				
Fe	%		99.5	99.4	99.4	991	991	97.8	97.8	97.8	97.8				

99.1

273

97.8

195

97.8

145

97.8

105

97.8

99.1

5068 CapSureFix

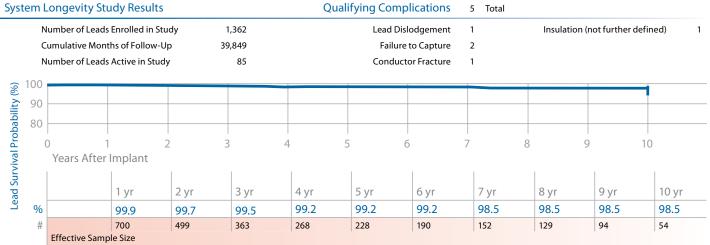
Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDJ	US Returned Product An	alysis
Registered US Implants	102,800	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	35
Estimated Active US Implants	32,200	Polarity	Bipolar	Crimp/Weld/Bond	2
Advisories	None	Steroid	Yes	Insulation Breach	51
				Other	4

Atrial Placement

Atrial System			udy Re	esults						Quali	fying (Complicat	ions	6	Total						
	Numbe	r of Lead	s Enrolle	ed in Stu	ıdy		967				Le	ad Dislodge	ment	1			Ir	npedan	ce Out	of Rang	e 1
	Cumula	tive Mon	ths of F	ollow-U	р	33	3,537				- 1	Failure to Ca _l	oture	2					Ove	rsensin	g 1
	Numbe	r of Lead	s Active	in Stud	y		42			Insula	tion (no	t further def	ined)	1							
§ 100																					
<u>i</u> 90)										-										
pap 80)																				
Pro	0	1	2 :	3 4	4 5	5 6	5 7	7 8	9	10) 11	12	13	14	15	16	17	18	19	20	21
Lead Survival Probability (%)	Yea	rs After	Impla	nt																	
Sur																					
ad		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 126 mo									
ه و م	ó	99.6	99.6	99.3	99.3	99.3	99.3	99.3	97.6	97.6	97.6	97.6									
i	#	552	424	321	253	210	159	130	103	78	62	48									
	Effec	ive Samp	ole Size																		

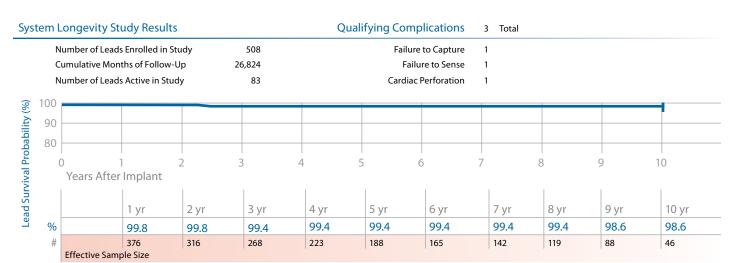
Ventricular Placement



5072 SureFix

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEM	US Returned Product Analysis
Registered US Implants	9,700	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 2
Estimated Active US Implants	4,300	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 6
				Other 0



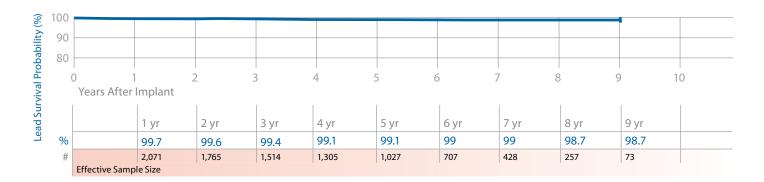
5076 CapSureFix Novus

Product Characteristics

US Market Release	Aug-00	Serial Number Prefix	PJN	US Returned Product An	alysis
Registered US Implants	1,349,300	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	284
Estimated Active US Implants	873,500	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	291
				Other	86

Atrial Placement

		19 Total	Qualifying Complications		System Longevity Study Results
3	Impedance Out of Range	4	Lead Dislodgement	2,737	Number of Leads Enrolled in Study
2	Extra Cardiac Stimulation	5	Failure to Capture	128,187	Cumulative Months of Follow-Up
2	Oversensing	1	Conductor Fracture	833	Number of Leads Active in Study
1	Cardiac Perforation	1	Insulation (not further defined)		



Ventricular Placement

System Longevity Study Results

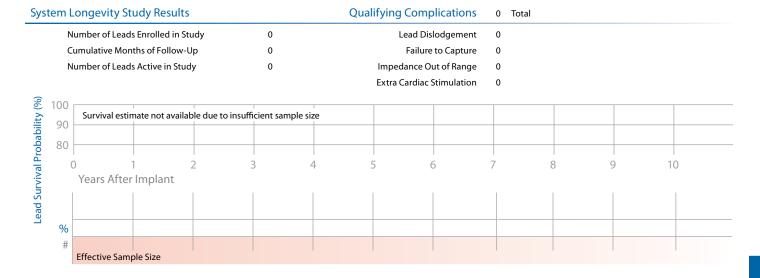
Qualifying Complications 10 Total

N	lumber of Leads	Enrolled in St	tudy	1,538		Lead	l Dislodgement	2		Failure to	Sense
C	Cumulative Months of Follow-Up			64,412	Failure to Capture		3 Impedance Out		Impedance Out of Range		
N	lumber of Leads	Active in Stu	dy	326		Cond	ductor Fracture	1		Cardiac Perfo	ration
100									-		
90											
80											
(O Years After	1 Implant	2	3	4	5	6	7	8	9	10
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 102 mo	
%		99.6	99.4	99.3	99.0	99.0	99.0	99.0	99.0	99.0	
#		1,084	897	742	609	472	360	220	124	62	
	Effective Samp	ole Size									

5086MRI CapSureFix Novus

Product Characteristics

US Market Release	Feb-11	Serial Number Prefix	LEP	US Returned Product Analysis
Registered US Implants	17,700	Type and/or Fixation	Transvenous, A or V, Screw-in	Conductor Fracture 0
Estimated Active US Implants	17,500	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
				Other 0



5092 CapSure SP Novus

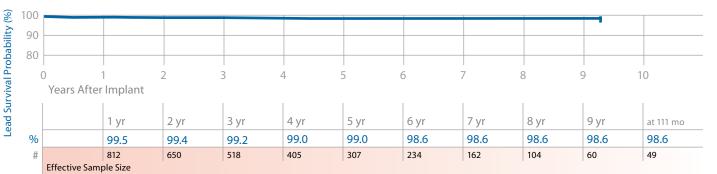
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Analysis
Registered US Implants	126,200	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 6
Estimated Active US Implants	60,200	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 32
				Other 1



Qualifying Complications 9 Total

Number of Leads Enrolled in Study	1,172	Lead Dislodgement	5
Cumulative Months of Follow-Up	46,543	Failure to Capture	2
Number of Leads Active in Study	159	Impedance Out of Range	1
		Extra Cardiac Stimulation	1



5524, 5524M CapSure SP

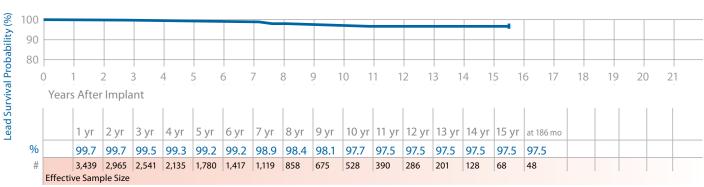
Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	US Returned Product Analysis
Registered US Implants	59,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 11
Estimated Active US Implants	17,100	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 11
				Other 2

System Longevity Study Results

Qualifying Complications 39 Total

4,497	Lead Dislodgement	4	Insulation (not further defined)	1
252,422	Failure to Capture	23	Impedance Out of Range	1
334	Conductor Fracture	1	Oversensing	4
	Failure to Sense	4	Other	1
	252,422	252,422 Failure to Capture 334 Conductor Fracture	252,422 Failure to Capture 23 334 Conductor Fracture 1	252,422 Failure to Capture 23 Impedance Out of Range 334 Conductor Fracture 1 Oversensing



5534 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDG	US Returned Product Analysis
Registered US Implants	26,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 3
Estimated Active US Implants	7,500	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 5
				Other 2

System Longevity Study Results

Qualifying Complications 6 Total

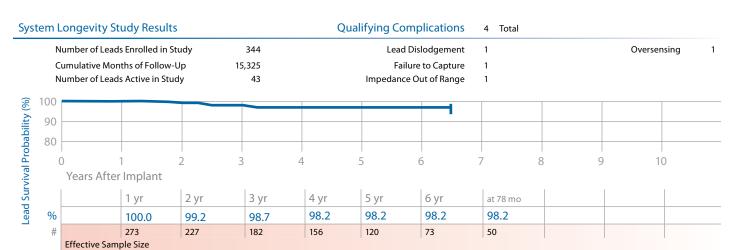
Number of Leads Enrolled in Study	264	Failure to Capture	5
Cumulative Months of Follow-Up	12,959	Impedance Out of Range	1
Number of Leads Active in Study	6		



5554 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEJ	US Returned Product Analysis
Registered US Implants	60,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 7
Estimated Active US Implants	30,000	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 15
				Other 1



5568 CapSureFix

Product Characteristics

1,053

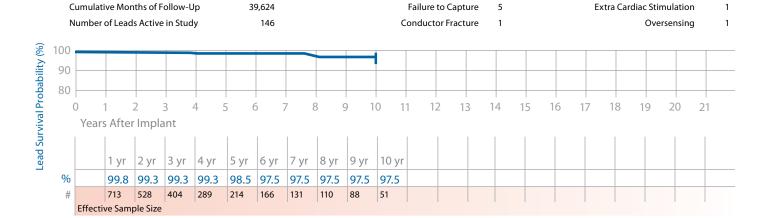
US Market Release	Jan-97	Serial Number Prefix	LDN	US Returned Product Analysis
Registered US Implants	85,200	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture 7
Estimated Active US Implants	49,500	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 24
				Other 6

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 11 Total Lead Dislodgement

1

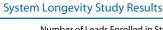


Failure to Sense

5592 CapSure SP Novus

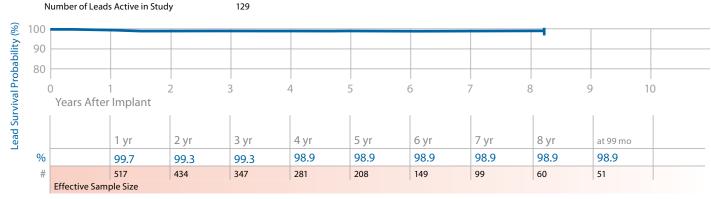
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEU	US Returned Product Analysis
Registered US Implants	32,400	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 3
Estimated Active US Implants	18,500	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 3
				Other 0



Qualifying Complications 5 Total





5594 CapSure SP Novus

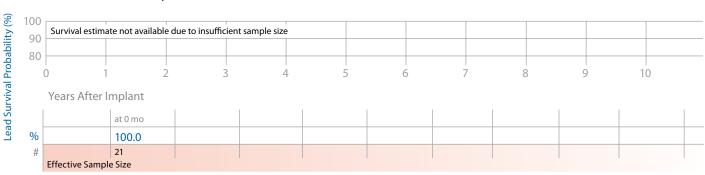
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	LFD	US Returned Product Analysis
Registered US Implants	14,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 4
Estimated Active US Implants	9,700	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 6
				Other 1

System Longevity Study Results

Qualifying Complications 0 Total

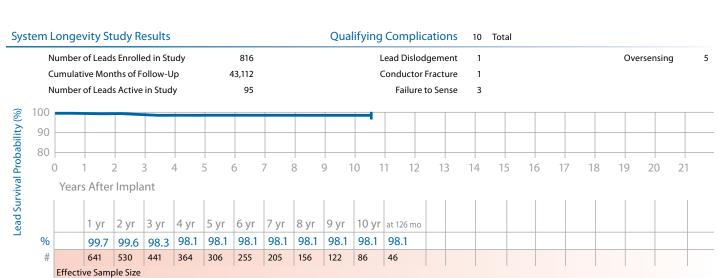
Number of Leads Enrolled in Study	21
Cumulative Months of Follow-Up	1,422
Number of Leads Active in Study	12



6940 CapSureFix

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	TCP	US Returned Product Analysis
Registered US Implants	25,300	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture 11
Estimated Active US Implants	7,900	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 17
				Other 1



	_	20 yr														
	_	18 yr														
		16 yr														
	-	14 yr			95.7 +1.6/-2.6 at 159 mo				91.1 +2.7/-3.9 at 159 mo							
	-	12 yr			95.7 +1.6/-2.6				92.0 +2.3/-3.2	92.6 +3/-4.7 at 138 mo						
	-	10 yr			96.3 +1.3/-2.1	98.8 +0.1/-5.0 at 117 mo	95.3 +2.5/-5.1 at 114 mo		94.1	94.2 +1.8/-2.6						97.9 +0.8/-1.3 at 111 mo
	-	8 yr			96.9 +1.2/-1.8	99.8 +0.1/-0.7	96.6		95.6	95.5 +1.4/-1.9						97.9
	-	7 yr			97.2 +1.1/-1.8	99.8 +0.1/-0.7	97.5 +1.3/-2.7	98.1 +1.3/-3.9 at 78 mo	96.9 +0.8/-1.1	96.2	100.0 at 75 mo	99.1 +0.7/-2.8	99.4			97.9
		6 yr	99.7 +0.2/-1.0 at 63 mo	100.0 at 63 mo	98.1 +0.8/-1.3	99.8 +0.1/-0.7	97.5	98.1 +1.3/-3.9	97.2 +0.7/-1	97.3 +0.9/-1.2	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.4	99.6 +0.2/-0.5 at 66 mo	99.5 +0.4/-1.6 at 69 mo	97.9 +0.8/-1.3
	_	5 yr	99.7 +0.2/-1.0	100.0	98.5	99.8 +0.1/-0.7	98.1 +1/-2.2	98.1	97.4	97.8 +0.7/-1.1	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.4	99.6	99.5	98.1
lity (%)	-	4 yr	99.7 +0.2/-1.0	100.0	98.5	99.8 +0.1/-0.7	98.5 +0.8/-1.9	98.1	98.0 +0.5/-0.8	98.2 +0.6/-1	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.4	99.6 +0.2/-0.5	99.8 +0.2/-0.5	98.4 +0.6/-1.1
Probabi	lant	3 yr	99.7 +0.2/-1.0	100.0	98.7	99.8 +0.1/-0.7	98.8 +0.7/-1.6	98.1	98.2 +0.5/-0.7	98.7	100.0	99.1	99.4 +0.4/-1.4	99.6	99.8 +0.2/-0.5	98.7
Device Survival Probability (%)	Years After Implant	2 yr	99.7 +0.2/-1.0	100.0	99.2	99.8 +0.1/-0.7	99.1 +0.6/-1.5	98.1	98.7	98.7 +0.5/-0.7	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.4	99.6	99.8 +0.2/-0.5	98.8
Device	Years A	1 yr	99.7 +0.2/-1.0	100.0	99.8 +0.2/-0.6	99.9 +0.1/-0.5	99.4 +0.4/-1.4	98.1	98.9 +0.4/-0.5	99.3 +0.3/-0.6	100.0	99.1 +0.7/-2.8	99.6 +0.3/-1.1	99.8 +0.1/-0.5	99.8 +0.2/-0.5	98.9
Months o in Study			13,732	10,756	72,820	50,877	29,540	11,059	131,388	93,767	6,867	13,314	24,706	45,725	38,391	64,757
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γbut2 ni s	evitoA	speə7	509	282	250	18	31	48	339	259	72	152	455	1,280	806	405
pə	Ilorn3	reads	622	385	1,158	1,215	539	171	2,413	1,799	102	214	626	1,657	1,226	1,147
əseələ	ırket Bı	₽W SN	Aug-05	Aug-05	Aug-91	Oct-91	Not US released	Jan-97	Mar-96	Mar-96	Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	Sep-98
	þer	Сһат	Atrial	Vent	Vent	Vent	Vent	AorV	Atrial	Vent	Vent	Atrial	Vent	Atrial	Vent	Vent
	A	(lime7	SelectSecure	SelectSecure	CapSure SP	CapSure SP	CapSure Z	CapSureFix	CapSureFix	CapSureFix	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus
		apoM 9boM	3830	3830	4023	4024	4033	4067	4068	4068	4073	4074	4074	4076	4076	4092

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cing	<u> </u>	eac	15	continu	ued											
		20 yr														
		18 yr									97.3 +1.2/-2 at 201 mo					
		16 yr									97.3 +1.2/-2					
		14 yr									98.3 +0.6/-0.9	94.5 +2.2/-3.5 at 165 mo	98.8 +0.8/-1.9 at 150 mo			
		12 yr								95.9 +1.8/-3 at 141 mo	98.5	95.5	98.8 +0.8/-1.9			
		10 yr		99.0 +0.6/-1.2 at 114 mo		91.8 +4.3/-8.8 at 108 mo	93.4 +2.1/-2.9 at 102 mo		97.4 +1.5/-3.8 at 102 mo	96.7 +1.4/-2.3	98.8 +0.3/-0.6	96.0 +1.4/-2.1	98.8 +0.8/-1.9		99.5 +0.4/-1.4 at 111 mo	97.8 +1.2/-2.3 at 108 mo
		8 yr		99.0		96.5 +2.1/-5.2	93.4 +2.1/-2.9		97.4 +1.5/-3.8	97.6 +0.9/-1.6	99.0	96.9 +1.1/-1.7	98.8 +0.8/-1.9	96.6 +2.1/-5.7	99.5	97.8 +1.2/-2.3
		7 yr		99.0	97.9 +1.4/-4.2 at 78 mo	96.5 +2.1/-5.2	93.4 +2.1/-2.9		97.4 +1.5/-3.8	97.6 +0.9/-1.6	99.1 +0.3/-0.3	97.7 +0.9/-1.3	98.8 +0.8/-1.9	98.1	99.5 +0.4/-1.4	97.8 +1.2/-2.3
		6 yr		99.0	97.9	97.6	94.0 +1.8/-2.6		97.4 +1.5/-3.8	98.8 +0.5/-1.2	99.3 +0.2/-0.3	98.3 +0.7/-1.2	99.5	98.8 +0.6/-1.1	99.5	97.8
		5 yr	98.1 +1.4/-5.3 at 57 mo	99.0	97.9	99.3 +0.5/-1.4	94.0 +1.8/-2.6		97.4	99.3 +0.4/-0.9	99.3 +0.2/-0.2	98.8 +0.5/-0.9	99.5	98.8 +0.6/-1.1	99.5	99.1
lity (%)		4 yr	98.1 +1.4/-5.3	99.0	97.9	99.3 +0.5/-1.4	94.7		98.2 +1.1/-3	99.4 +0.3/-0.7	99.4 +0.2/-0.2	99.0	99.5	98.8 +0.6/-1.1	99.5	99.1
Probabi	lant	3 yr	98.1 +1.4/-5.3	99.3 +0.4/-1	98.8 +0.9/-3.6	99.3 +0.5/-1.4	95.3 +1.5/-2.2		98.2 +1.1/-3	99.5	99.5	99.1	99.5	99.1 +0.4/-1	99.5	99.4
Device Survival Probability (%)	Years After Implant	2 yr	98.1 +1.4/-5.3	99.3 +0.4/-1	99.4 +0.5/-3.5	99.3 +0.5/-1.4	96.4	100.0 at 15 mo	98.2 +1.1/-3	99.7 +0.2/-0.6	99.6 +0.1/-0.2	99.6	99.5	99.4 +0.3/-0.8	99.5	99.4
Device	Years A	1 yr	98.1	99.6 +0.3/-0.7	100.0	99.3 +0.5/-1.4	96.8 +1.2/-1.8	100.0	98.2 +1.1/-3	99.7 +0.2/-0.5	99.6	99.7 +0.2/-0.4	99.5	99.7 +0.2/-0.6	99.5	99.5
Months o in Study			7,531	40,291	11,670	22,993	31,676	2,314	14,431	82,541	441,293	98,520	43,189	44,335	31,594	37,968
su		(TilsuQ IqmoD	4	9	4	12	33	0	5	19	56	28	5	=	7	6
γbut2 ni s	evit⊃A	rspeəŢ	0	14	13	22	170	163	70	354	348	180	141	16	176	120
рә	Enroll	reads	121	911	206	539	929	200	283	1,354	8,153	1,899	386	1,209	424	296
əseələ	ket R	isM 2U	Aug-91	Oct-91	Not US released	Nov-94	Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-96	Feb-96	Feb-96	Jun-98	Jun-98
) 6 L	Chamb	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Vent	Vent	Atrial	Vent	Atrial	Vent
		Family	CapSure SP	CapSure SP	CapSure Z	Screw-In	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure Z	CapSure Z	CapSure Z	CapSure Z Novus	CapSure Z Novus
		ləboM dmuM	4523	4524	4533	4558M	4568	4574	4592	5023, 5023M	5024, 5024M	5033	5034	5034	5054	5054

9		uu		l	-u I	I	I	l	I	I	l			ı	I	
		20 yr														
		18 yr														
		16 yr								97.5 +0.8/-1.1 at 9 yr						
		14 yr								97.5 +0.8/-1.1						
		12 yr	97.6 +1.5/-4.2 at 126 mo							97.5						98.1 +0.9/-1.6
		10 yr	97.6	98.5 +1/-2.5	98.6 +1.0/-3.9	98.7 +0.6/-0.9 at 9 yr	99.0 +0.5/-0.9 at 102 mo		98.6 +0.7/-1.6 at 111 mo	97.7 +0.8/-1			97.5 +1.3/-2.8	98.9 +0.7/-1.6 at 99 mo		98.1 +0.9/-1.6
		8 yr	97.6	98.5	99.4	98.7	99.0+0.5/-0.9		98.6 +0.7/-1.6	98.4 +0.5/-0.7			97.5	98.9		98.1 +0.9/-1.6
		7 yr	99.3 +0.5/-1.2	98.5 +1/-2.5	99.4 +0.5/-1.7	99.0 +0.4/-0.6	99.0		98.6 +0.7/-1.6	98.9 +0.4/-0.5	97.1 +1.6/-3.5 at 78 mo	98.2 +1.1/-3 at 78 mo	97.5 +1.3/-2.8	98.9 +0.7/-1.6		98.1 +0.9/-1.6
		6 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	99.0	99.0		98.6 +0.7/-1.6	99.2 +0.2/-0.5	97.1	98.2 +1.1/-3	97.5 +1.3/-2.8	98.9		98.1 +0.9/-1.6
		5 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	99.1 +0.3/-0.6	99.0		99.0	99.2 +0.3/-0.4	97.1	98.2 +1.1/-3	98.5 +0.9/-1.9	98.9 +0.7/-1.6		98.1 +0.9/-1.6
ity (%)		4 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4	99.1 +0.3/-0.6	99.0		99.0 +0.5/-1.2	99.3 +0.3/-0.4	97.1	98.2 +1.1/-3	99.3 +0.4/-0.9	98.9 +0.7/-1.6		98.1 +0.9/-1.6
Probabil	ant	3 yr	99.3 +0.5/-1.2	99.5 +0.3/-1.2	99.4	99.4 +0.2/-0.5	99.3 +0.4/-0.7		99.2 +0.4/-0.9	99.5 +0.2/-0.3	97.8 +1.3/-3	98.7 +0.9/-2.6	99.3 +0.4/-0.9	99.3 +0.4/-1.3		98.3 +0.8/-1.5
Device Survival Probability (%)	Years After Implant	2 yr	99.6 +0.3/-0.9	99.7 +0.2/-0.9	99.8 +0.2/-1.4	99.6 +0.2/-0.3	99.4 +0.3/-0.6		99.4 +0.3/-0.8	99.7 +0.1/-0.2	97.8 +1.3/-3	99.2 +0.6/-2.4	99.3 +0.4/-0.9	99.3 +0.4/-1.3		99.6 +0.3/-1
Device	Years A	1 yr	99.6 +0.3/-0.9	99.9 +0.1/-0.8	99.8 +0.2/-1.4	99.7 +0.1/-0.4	99.6 +0.2/-0.5	100.0 at 0 mo	99.5 +0.3/-0.7	99.7 +0.2/-0.2	98.3 +1.1/-2.7	100.0	99.8 +0.1/-0.7	99.7 +0.2/-1.1	100.0 at 0 mo	99.7 +0.2/-0.8
Months in Study			33,537	39,849	26,824	128,187	64,412	0	46,543	252,422	12,959	15,325	39,624	30,017	1,422	43,112
su	ying icatio	PillauQ IqmoD	9	52	m	19	0	0	Q	39	9	4	=	20	0	01
in Study			42	85	83	833	326	0	159	334	9	43	146	129	12	95
pə	Ilorna	reads	296	1,362	508	2,737	1,538	0	1,172	4,497	264	344	1,053	672	21	816
əseələ	rket Ro	_B M 2U	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Feb-11	Jun-98	Mar-90	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98
) GL	Chamb	Atrial	Vent	A or V	Atrial	Vent	A or V	Vent	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
		Family	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapsureFix Novus	CapSure SP Novus	CapSure SP	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix
	ξ	laboM dmuM	5068	5068	5072	5076	5076	5086MRI	5092	5524, 5524M	5534	5554	5568	5592	5594	6940

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
3830	SelectSecure	Aug-05	20,100	16,400	2	0	7	3
4023	CapSure SP	Aug-91	41,100	8,000	14	0	4	2
4024	CapSure SP	Oct-91	221,300	45,600	29	0	147	8
4033	CapSure Z	Not US released	NA	NA	0	0	0	0
4067	CapSureFix	Jan-97	1,000	200	1	0	0	0
4068	CapSureFix	Mar-96	124,300	33,700	41	0	125	5
4073	CapSure Sense	Jun-02	700	300	0	0	0	0
4074	CapSure Sense	Jun-02	82,200	52,600	1	0	14	1
4076	CapSureFix Novus	Feb-04	349,100	271,600	17	1	14	16
4092	CapSure SP Novus	Sep-98	169,200	80,900	7	0	31	1
4523	CapSure SP	Aug-91	11,200	2,600	1	0	2	1
4524	CapSure SP	Oct-91	101,300	26,100	1	0	49	3
4533	CapSure Z	Not US released	NA	NA	0	0	0	0
4558M	Screw-in	Nov-94	19,900	4,300	1	0	18	0
4568	CapSureFix	Jan-97	69,600	24,400	3	0	49	1
4574	CapSure Sense	Jun-02	53,900	37,200	5	0	2	0
4592	CapSure SP Novus	Oct-98	82,300	41,700	6	0	11	1
5023, 5023M	CapSure SP	Nov-88	9,800	2,200	5	0	0	0
5024, 5024M	CapSure SP	Mar-90	200,700	46,400	51	1	48	9
5033	CapSure Z	Feb-96	2,300	500	1	0	0	0
5034	CapSure Z	Feb-96	56,000	13,600	12	0	12	3
5054	CapSure Z Novus	Jun-98	93,000	42,200	8	1	17	3
5068	CapSureFix	Jan-97	102,800	32,200	35	2	51	4
5072	SureFix	Jun-98	9,700	4,300	2	0	6	0
5076	CapSureFix Novus	Aug-00	1,349,300	873,500	284	0	291	86
5086MRI	CapSureFix Novus	Feb-11	17,700	17,500	0	0	0	0
5092	CapSure SP Novus	Jun-98	126,200	60,200	6	0	32	1
5524, 5524M	CapSure SP	Mar-90	59,800	17,100	11	1	11	2
5534	CapSure Z	Feb-96	26,200	7,500	3	0	5	2
5554	CapSure Z Novus	Jun-98	60,000	30,000	7	0	15	1
5568	CapSureFix	Jan-97	85,200	49,500	7	0	24	6
5592	CapSure SP Novus	Jun-98	32,400	18,500	3	0	3	0
5594	CapSure SP Novus	Jun-01	14,300	9,700	4	0	6	1

US Reports of Acute Lead Observations

3330 Selectsoure 2000 6 1 20 20 1 1 1 0 0 2 2 40234 Capsure SP 41,100 0 1 3 4 1 1 3 0 1 2 40234 Capsure Fix 22,300 0	Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
March Marc	3830	SelectSecure	20,100	6	1	26	12	1	1	1	0	0	2
4033	4023	CapSure SP	41,100	0	1	3	4	1	1	3	0	1	2
	4024	CapSure SP	221,300	12	11	50	108	0	15	1	7	2	21
Mode CapSure Fix 124,300 4 3 3 31 25 0 5 1 4 1 4 4 4 4 4 4 4	4033	CapSure Z	2,300	0	0	0	0	0	0	0	0	0	0
4073 CapSure Sense 700 1 1 1 1 1 2 0 1 0 3 0 1 1 1 0 3 0 1 1 0 1 0 1 0 0 1 0	4067	CapSure Fix	1,000	1	0	0	0	0	0	0	0	0	0
4074	4068	CapSure Fix	124,300	4	3	31	25	0	5	1	4	1	4
4076	4073	CapSure Sense	700	0	0	0	0	0	0	0	0	0	0
4992	4074	CapSure Sense	82,200	5	1	17	22	0	1	0	3	0	1
4523	4076	CapSure Fix Novus	349,100	30	4	98	53	5	15	1	6	4	8
	4092	CapSure SP Novus	169,200	2	4	18	24	0	0	1	3	0	2
4533	4523	CapSure SP	11,200	0	0	2	2	0	1	0	0	0	0
4558M Screw-in 19900 2 0 2 2 2 0 0 1 0 0 2 2 1 1 1 4568 CapSure Fix 69600 3 1 1 4 7 0 0 0 0 0 3 0 0 1 4574 CapSure Sense 53,900 0 2 199 9 1 4 4 0 0 0 0 0 2 4592 CapSure SP Novus 82,300 0 0 22 7 7 2 1 0 0 0 0 0 0 0 0 0 5024, 5024M CapSure SP 2,800 0 0 1 2 2 0 0 0 0 0 0 0 0 0 0 0 0 5024, 5024M CapSure SP 2,300 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 5034 CapSure Z 2,300 0 0 0 1 0 0 0 0 0 0 0 0 0 0 0 0 0 0	4524	CapSure SP	101,300	0	2	24	17	0	4	2	1	0	14
4568	4533	CapSure Z	NA	0	0	0	0	0	0	0	0	0	0
4574 CapSure Sense 53,900 0 2 19 9 1 4 0 0 0 2 4592 CapSure SP Novus 82,300 0 0 22 7 2 1 0 0 0 2 5023, 5023M CapSure SP 9,800 0 1 2 0 <t< td=""><td>4558M</td><td>Screw-in</td><td>19,900</td><td>2</td><td>0</td><td>2</td><td>2</td><td>0</td><td>1</td><td>0</td><td>2</td><td>1</td><td>1</td></t<>	4558M	Screw-in	19,900	2	0	2	2	0	1	0	2	1	1
4592	4568	CapSure Fix	69,600	3	1	4	7	0	0	0	3	0	1
5023, 5023M CapSure SP 9,800 0 1 2 0 <td>4574</td> <td>CapSure Sense</td> <td>53,900</td> <td>0</td> <td>2</td> <td>19</td> <td>9</td> <td>1</td> <td>4</td> <td>0</td> <td>0</td> <td>0</td> <td>3</td>	4574	CapSure Sense	53,900	0	2	19	9	1	4	0	0	0	3
5024, 5024M CapSure SP 200,700 10 9 33 49 1 9 6 3 3 14 5033 CapSure Z 2,300 0 0 1 0 </td <td>4592</td> <td>CapSure SP Novus</td> <td>82,300</td> <td>0</td> <td>0</td> <td>22</td> <td>7</td> <td>2</td> <td>1</td> <td>0</td> <td>0</td> <td>0</td> <td>2</td>	4592	CapSure SP Novus	82,300	0	0	22	7	2	1	0	0	0	2
5033 CapSure Z 2,300 0 0 1 0 12 2 12 2 0 0 0 1 0 0 0 0 8 5068 CapSure Fix 102,800 13 4 22 34 1 5 1 1 0 6 5072 Sure Fix 9,700 0 0 2 1 0 0 0 0 1 2 9 399 179 21 36 5 14 12 29 2 1 4 1 0 3 0 2 1 2 2 1 1 <td>5023, 5023M</td> <td>CapSure SP</td> <td>9,800</td> <td>0</td> <td>1</td> <td>2</td> <td>0</td> <td>0</td> <td>0</td> <td>0</td> <td>0</td> <td>0</td> <td>0</td>	5023, 5023M	CapSure SP	9,800	0	1	2	0	0	0	0	0	0	0
5034 CapSure Z 56,000 3 3 16 32 0 3 2 0 0 12 5054 CapSure Z Novus 93,000 1 2 12 20 0 0 1 0 0 8 5068 CapSure Fix 102,800 13 4 22 34 1 5 1 1 0 6 5072 SureFix 9,700 0 0 2 1 0 0 0 0 1 5076 CapSure Fix 9,700 0 0 2 1 0 0 0 0 1 5076 CapSure Fix 9,700 120 9 399 179 21 36 5 14 12 29 5086MRI CapSure Fix Novus 17,700 25 0 28 9 1 4 1 0 3 9 5524, 5524M CapSure SP	5024, 5024M	CapSure SP	200,700	10	9	33	49	1	9	6	3	3	14
5054 CapSure Z Novus 93,000 1 2 12 20 0 0 1 0 0 8 5068 CapSure Fix 102,800 13 4 22 34 1 5 1 1 0 6 5072 SureFix 9,700 0 0 2 1 0 0 0 0 0 1 5076 CapSure Fix Novus 1,349,300 120 9 399 179 21 36 5 14 12 29 5086MRI CapSure Fix Novus 17,700 25 0 28 9 1 4 1 0 3 0 5092 CapSure SP Novus 126,200 5 1 29 25 1 5 4 0 3 9 5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 1	5033	CapSure Z	2,300	0	0	1	0	0	0	0	0	0	0
5068 CapSure Fix 102,800 13 4 22 34 1 5 1 1 0 6 5072 SureFix 9,700 0 0 2 1 0 0 0 0 1 5076 CapSure Fix Novus 1,349,300 120 9 399 179 21 36 5 14 12 29 5086MRI CapSure Fix Novus 17,700 25 0 28 9 1 4 1 0 3 0 5092 CapSure SP Novus 126,200 5 1 29 25 1 5 4 0 3 9 5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 10 5534 CapSure Z 26,200 0 1 30 22 0 1 0 0 3 5568 CapS	5034	CapSure Z	56,000	3	3	16	32	0	3	2	0	0	12
5072 SureFix 9,700 0 0 2 1 0 0 0 0 1 5076 CapSure Fix Novus 1,349,300 120 9 399 179 21 36 5 14 12 29 5086MRI Capsure Fix Novus 17,700 25 0 28 9 1 4 1 0 3 0 5092 CapSure SP Novus 126,200 5 1 29 25 1 5 4 0 3 9 5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 10 5534 CapSure Z Novus 60,000 0 1 30 22 0 1 0 0 2 4 5554 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 559	5054	CapSure Z Novus	93,000	1	2	12	20	0	0	1	0	0	8
5076 CapSure Fix Novus 1,349,300 120 9 399 179 21 36 5 14 12 29 5086MRI Capsure Fix Novus 17,700 25 0 28 9 1 4 1 0 3 0 5092 CapSure SP Novus 126,200 5 1 29 25 1 5 4 0 3 9 5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 10 5534 CapSure Z 26,200 0 0 6 3 0 2 0 0 2 4 5554 CapSure Z Novus 60,000 0 1 30 22 0 1 1 3 3 1 1 0 0 0 3 3 1 1 0 0 0 3 3 1 1 1	5068	CapSure Fix	102,800	13	4	22	34	1	5	1	1	0	6
5086MRI Capsure Fix Novus 17,700 25 0 28 9 1 4 1 0 3 0 5092 CapSure SP Novus 126,200 5 1 29 25 1 5 4 0 3 9 5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 10 5534 CapSure Z 26,200 0 0 6 3 0 2 0 0 2 4 5554 CapSure Z Novus 60,000 0 1 30 22 0 1 0 0 3 5568 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594	5072	SureFix	9,700	0	0	2	1	0	0	0	0	0	1
5092 CapSure SP Novus 126,200 5 1 29 25 1 5 4 0 3 9 5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 10 5534 CapSure Z 26,200 0 0 6 3 0 2 0 0 2 4 5554 CapSure Z Novus 60,000 0 1 30 22 0 1 0 0 3 5568 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5076	CapSure Fix Novus	1,349,300	120	9	399	179	21	36	5	14	12	29
5524, 5524M CapSure SP 59,800 1 3 20 13 0 9 2 0 0 10 5534 CapSure Z 26,200 0 0 6 3 0 2 0 0 2 4 5554 CapSure Z Novus 60,000 0 1 30 22 0 1 0 0 0 3 5568 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5086MRI	CapsureFix Novus	17,700	25	0	28	9	1	4	1	0	3	0
5534 CapSure Z 26,200 0 0 6 3 0 2 0 0 2 4 5554 CapSure Z Novus 60,000 0 1 30 22 0 1 0 0 0 3 5568 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5092	CapSure SP Novus	126,200	5	1	29	25	1	5	4	0	3	9
5554 CapSure Z Novus 60,000 0 1 30 22 0 1 0 0 0 3 5568 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5524, 5524M	CapSure SP	59,800	1	3	20	13	0	9	2	0	0	10
5568 CapSure Fix 85,200 6 0 23 16 1 4 1 1 1 3 5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5534	CapSure Z	26,200	0	0	6	3	0	2	0	0	2	4
5592 CapSure SP Novus 32,400 0 0 20 4 0 1 0 0 0 2 5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5554	CapSure Z Novus	60,000	0	1	30	22	0	1	0	0	0	3
5594 CapSure SP Novus 14,300 0 1 6 0 1 0 0 0 0 2	5568	CapSure Fix	85,200	6	0	23	16	1	4	1	1	1	3
	5592	CapSure SP Novus	32,400	0	0	20	4	0	1	0	0	0	2
6940 CapSure Fix 25,300 0 1 6 1 0 0 0 1 0 0	5594	CapSure SP Novus	14,300	0	1	6	0	1	0	0	0	0	2
	6940	CapSure Fix	25,300	0	1	6	1	0	0	0	1	0	0

Report Cutoff Date: July 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5086MRI	CapsureFix Novus	Transvenous A or V Screw-in	Silicone	MP35N	Titanium nitride coated platinum alloy	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)

continued

Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5534	CapSure Z	Transvenous Atrial-J Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

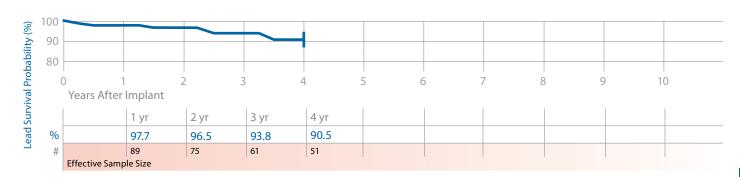
Product Characteristics

US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	US Returned Product Ana	alysis
Registered US Implants	11,700	Type and/or Fixation	Myocardial Stab-in, V or A, Peds	Conductor Fracture	36
Estimated Active US Implants	2,600	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	8
				Other	6

System Longevity Study Results

Qualifying Complications 14 Total

Number of Leads Enrolled in Study	179	Failure to Capture	7	Insulation (not further defined)	1
Cumulative Months of Follow-Up	5,924	Conductor Fracture	1	Insulation (ESC)	1
Number of Leads Active in Study	4	Failure to Sense	3	Impedance Out of Range	1



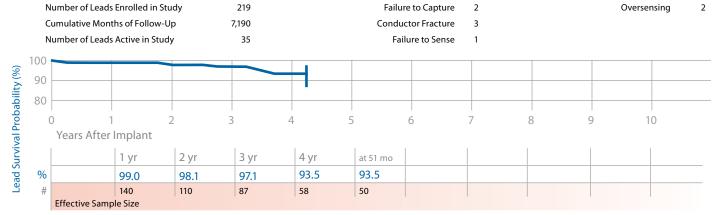
4965 CapSure Epi

Product Characteristics

US Market Release	Sep-96	Serial Number Prefix	LBT	US Returned Product Ana	alysis
Registered US Implants	19,700	Type and/or Fixation	Epicardial Suture-On V or A	Conductor Fracture	126
Estimated Active US Implants	9,300	Polarity	Unipolar	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	31
				Other	0



Qualifying Complications 8 Total



Epi/Myocardial Pacing Leads continued

4968 CapSure Epi

Product Characteristics

US Market Release	Sep-99	Serial Number Prefix	LEN	US Returned Product Analy	/sis
Registered US Implants	22,800	Type and/or Fixation	Epicardial Suture-On V or A	Conductor Fracture	19
Estimated Active US Implants	14,300	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	6
				Other	1

System Longevity Study Results

Qualifying Complications 43 Total

2	Insulation (not further defined)	18	Failure to Capture	716	Number of Leads Enrolled in Study
3	Impedance Out of Range	9	Conductor Fracture	33,110	Cumulative Months of Follow-Up
7	Oversensing	3	Failure to Sense	386	Number of Leads Active in Study
1	Other				



5071 Screw-in

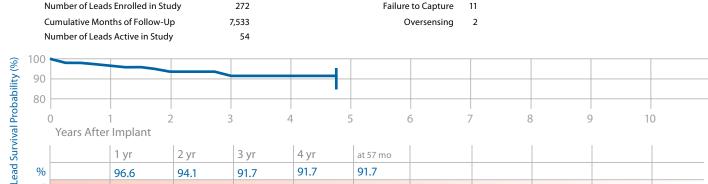
System Longevity Study Results

Product Characteristics

US Market Release	Dec-92	Serial Number Prefix	LAQ	US Returned Product Analysis
Registered US Implants	40,700	Type and/or Fixation	Myocardial Screw-in Vent.	Conductor Fracture 12
Estimated Active US Implants	14,500	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	No	Insulation Breach 2
				Other 0

Qualifying Complications

13 Total



Lead Survival Summary (95% Confidence Interval)

		16 yr					
		14 yr					
		12 yr					
		10 yr			88.2 +4.1/-6.2 at 9 yr		
		8 yr			91.8 +2.6/-3.7		
		7 yr			91.8 +2.6/-3.7		
		6 yr			92.6 +2.3/-3.3		
			5 yr		93.5 +3.5/-7.2 at 51 mo	93.1 +2.2/-3.0	91.7 +3.7/-6.5 at 57 mo
ty (%)			4 yr	90.5	93.5 +3.5/-7.2	94.3 +1.8/-2.6	91.7 +3.7/-6.5
Probabili	ant	3 yr	93.8 +3.5/-7.5	97.1 +1.9/-4.9	96.3 +1.3/-2.1	91.7	
Device Survival Probability (%)	ter Impla	Years After Implant	2 yr	96.5 +2.2/-5.8	98.1 +1.3/-4.0	97.4 +1.1/-1.7	94.1 +2.8/-5.1
Device (Years A	1 yr	97.7 +1.6/-4.8	99.0 +0.7/-3.0	99.4 +0.4/-1.0	96.6 +1.8/-3.6	
Months o in Stud			5,924	7,190	33,110	7,533	
	oitasil	JilsuQ IqmoD	4	80	43	13	
but2 ni s	vitoA	reads	4	35	386	54	
pə	ds Enrolled		179	219	716	272	
əseələ	rket R	_B M 2U	Oct-81	Sep-96	Sep-99	Dec-92	
	,	(lime	Spectraflex	CapSure Epi Sep-96	CapSure Epi	Screw -in	
		laboM dmuM	4951, 4951M	4965	4968	5071	

Epi/Myocardial Pacing Leads continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
4951, 4951M	Spectraflex	Oct-81	11,700	2,600	36	0	8	6
4965	CapSure Epi	Sep-96	19,700	9,300	126	1	31	0
4968	CapSure Epi	Sep-99	22,800	14,300	19	0	6	1
5071	Screw-in	Dec-92	40,700	14,500	12	0	2	0

Source: Returned Product Analysis Data as of July 31, 2011

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure To Sense	Impedance Abnormal	Extracardiac Stimulation
4951, 4951M	Spectraflex	11,700	0	1	0	8	0	0	0	0
4965	CapSure Epi	19,700	0	1	0	4	0	2	3	0
4968	CapSure Epi	22,800	1	0	3	9	1	0	1	0
5071	Screw-in	40,700	1	0	1	22	0	0	2	1

Model Number	Family	Estimated US Implants	Insulation Breach	Unspecified
4951, 4951M	Spectraflex	11,700	0	1
4965	CapSure Epi	19,700	0	3
4968	CapSure Epi	22,800	1	0
5071	Screw-in	40,700	0	1

Report Cutoff Date: July 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5071	Screw-in	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI

Report Cutoff Date: July 31, 2011

VDD Single Pass Pacing Leads

5032 CapSure VDD

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCL, LCN, LCM	US Returned Product Analysis
Registered US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent, Tines	Conductor Fracture 7
Estimated Active US Implants	1,300	Polarity	Quadripolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 7
				Other 0

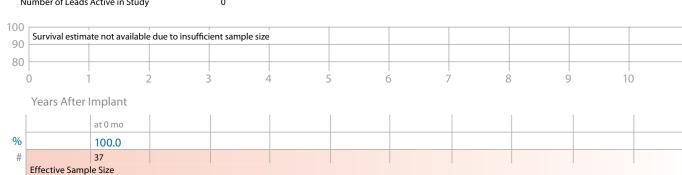
System Longevity Study Results

Lead Survival Probability (%)

Qualifying Complications 1 Total

Failure to Sense

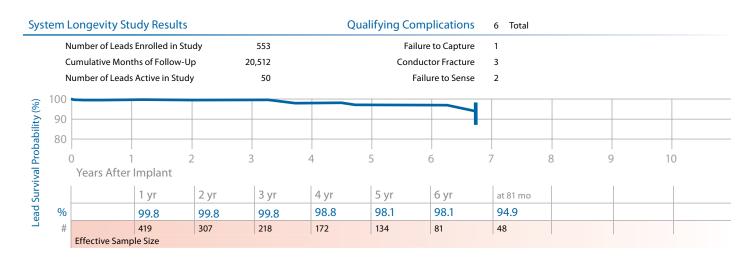
38 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 1,683 Number of Leads Active in Study 0



5038 CapSure VDD-2

Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEE, LEG, or LEF	US Returned Product Analysis
Registered US Implants	8,800	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Conductor Fracture 4
Estimated Active US Implants	3,600	Polarity	Quadripolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 1
				Other 0



VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

ā	Model Number Family US Market Release Leads Enrolled					Cumulative Months of Follow-Up in Study	Device Survival Probability (%) Years After Implant									
Model	Family	US Maı	Leads	Leads A	Qualifying Complications	Cumul	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
5032	CapSure VDD	Mar-96	38	0	1	1,683	100.0 at 0 mo									
5038	CapSure VDD-2	Sep-98	553	50	6	20,512	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.8 +0.8/-2.8	98.1 +1.2/-3.3	98.1 +1.2/-3.3	94.9 +3.1/-7.5 at 81 mo			

Source: System Longevity Study Data as of July 31, 2011

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
5032	CapSure VDD	Mar-96	5,400	1,300	7	0	7	0
5038	CapSure VDD-2	Sep-98	8,800	3,600	4	0	1	0

Source: Returned Product Analysis Data as of July 31, 2011

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Lead Dislodgement	Failure to Capture	Failure to Sense	Extracardiac Stimulation
5032	CapSure VDD	5,400	1	3	1	0
5038	CapSure VDD-2	8,800	1	1	0	1

Report Cutoff Date: July 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous V and A Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic products is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than 6-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a 6-month interval, a conservative approach has been adopted whereby only the maximum charge time in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

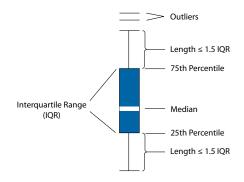
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

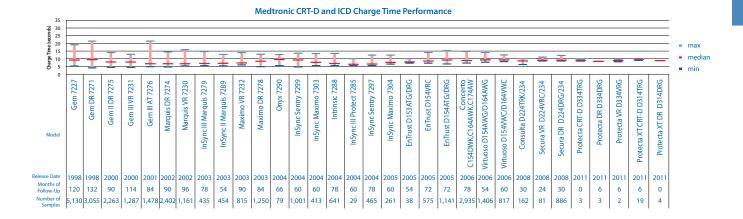
Data Presentation

Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data - the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the third quartile or the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the first quartile or the 25th percentile. Vertical lines are drawn from the quartiles to the farthest value not more than 1.5 times the interquartile range. Any values more extreme than the vertical lines are considered outliers.

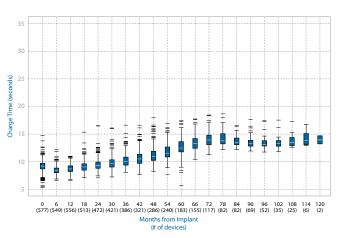
Results

The graph below shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel.

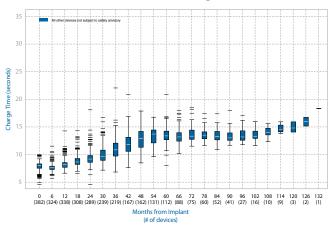




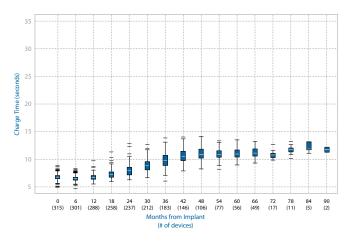
7227 **GEM** Charge Time



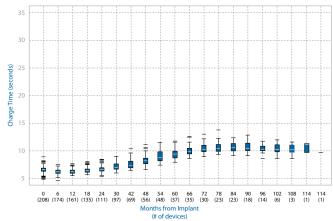
7271 GEM DR Charge Time



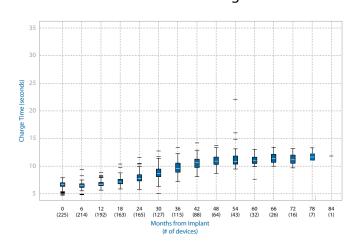
7275 GEM III DR Charge Time



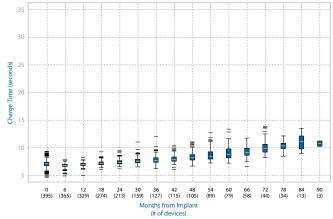
7231 GEM III VR Charge Time



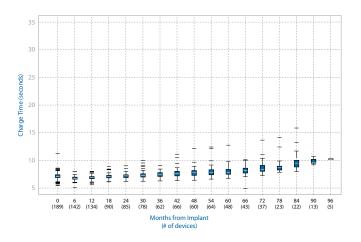
7276 GEM III AT Charge Time



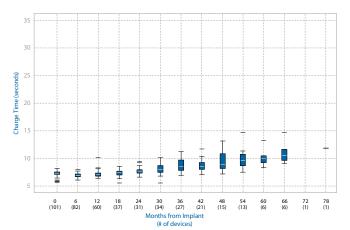
7274 Marquis DR Charge Time



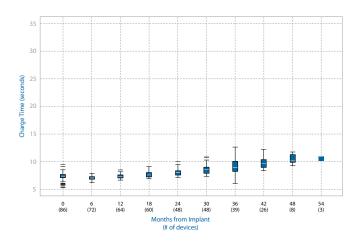
7230 Marquis VR Charge Time



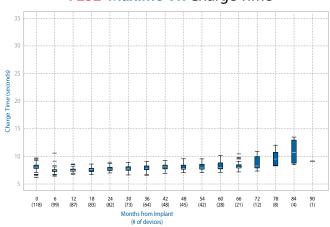
7279 InSync III Marquis Charge Time



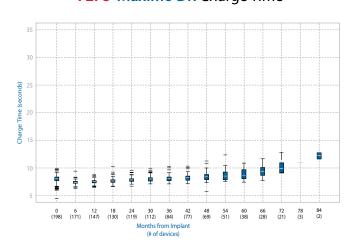
7289 InSync II Marquis Charge Time



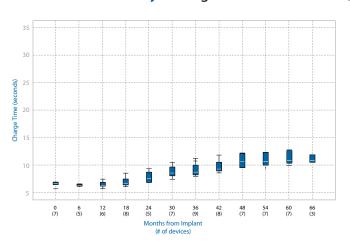
7232 Maximo VR Charge Time



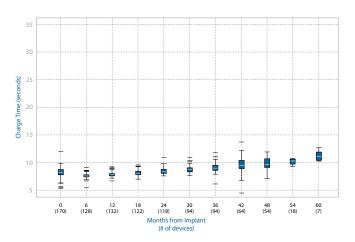
7278 Maximo DR Charge Time



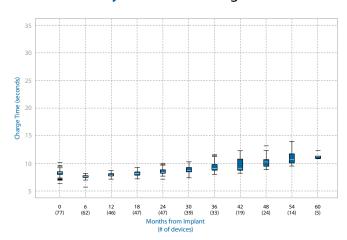
7290 Onyx Charge Time



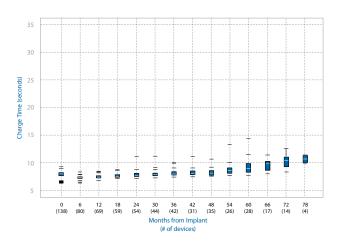
7299 InSync Sentry Charge Time



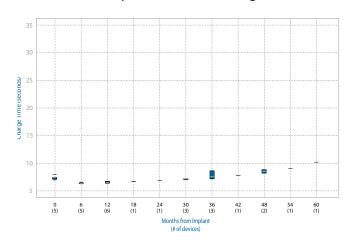
7303 InSync Maximo Charge Time



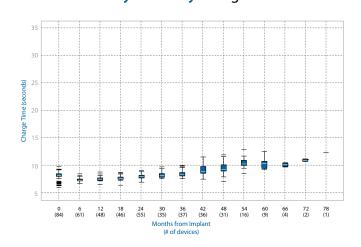
7288 Intrinsic Charge Time



7285 InSync III Protect Charge Time

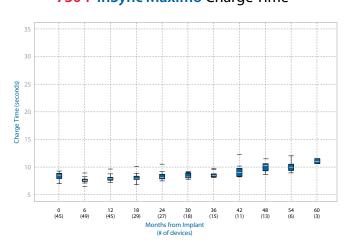


7297 InSync Sentry Charge Time

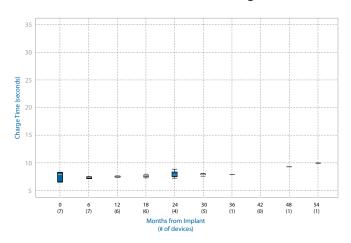


www.medtronic.com/CRDMProductPerformance

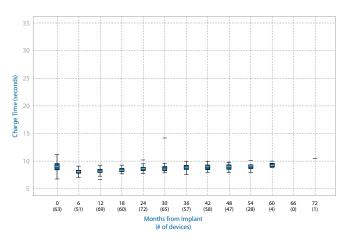
7304 InSync Maximo Charge Time



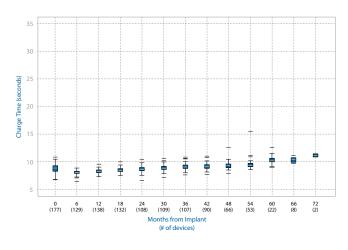
D153ATG, DRG EnTrust Charge Time



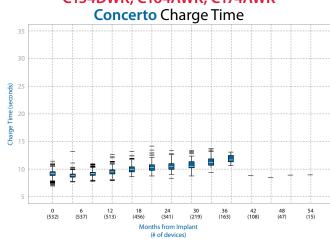
D154VRC EnTrust Charge Time



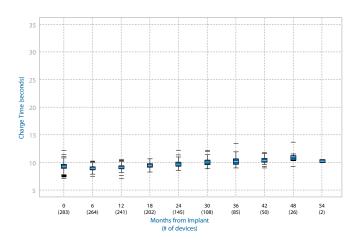
D154ATG, DRG EnTrust Charge Time



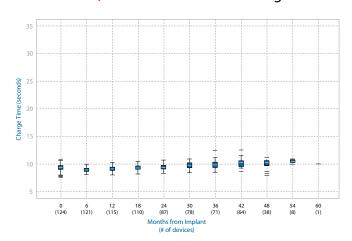
C154DWK, C164AWK, C174AWK



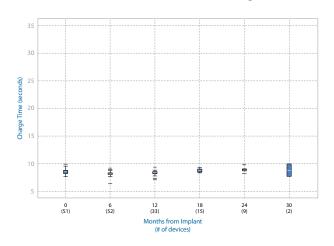
D154AWG, D164AWG Virtuoso Charge Time



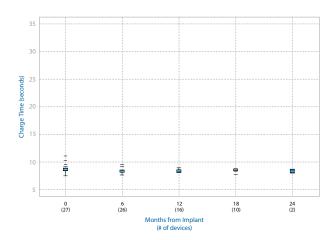
D154VWC, D164AWG Virtuoso Charge Time



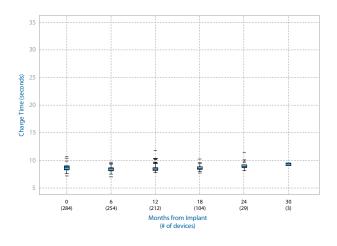
D224TRK/234 Consulta Charge Time



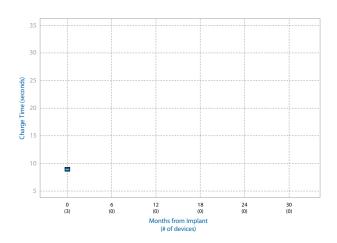
D224VRC/234 Secura VR Charge Time



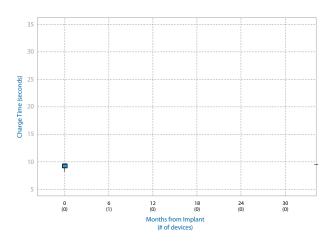
D224DRG/234 Secura DR Charge Time



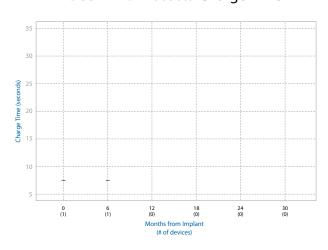
CRT-D D334TRG Protecta Charge Time



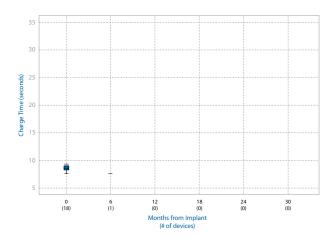
DR D334DRG Protecta Charge Time



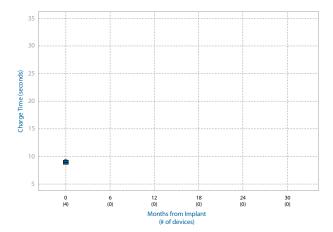
VR D334VRG Protecta Charge Time



XT CRT-D D314TRG Protecta Charge Time



XT DR D314DRG Protecta Charge Time



Advisories

EnRhythm Pacemakers

Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation

Product

All EnRhythm pacemakers.

Advisory

Two specific battery issues with EnRhythm pacemakers have been identified and both are addressed by a Medtronic software update.

First Issue

As of February 2010, Medtronic had received 62 reports (out of approximately 110,000 devices worldwide) indicating that the battery voltage at device interrogation was lower than the battery voltage that is tracked by the device to provide data for the elective replacement indicator (ERI) notification. The lower voltage measurement caused confusion and occasionally resulted in unnecessary explants.

Medtronic's investigation has shown that none of these reports resulted in loss of therapy. Importantly, the ERI notification, which uses the nightly battery measurement, is unaffected and accurate. Medtronic has identified the root cause as higher than expected battery resistance.

Medtronic's internal testing has shown that there is no current risk for compromised therapy delivery. If the software update referenced above is not implemented, there will be a potential risk of loss of device functionality in a small percent (less than 0.08% 6 years post-implant) of devices. The software update eliminates this risk.

Second Issue

Through internal accelerated testing, Medtronic has identified a second issue that projects battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion. This issue has not been clinically observed and is not expected to occur until approximately 9 years post-implant. If the software update referenced above is not implemented, there may be a potential risk for loss of therapy at or near ERI in a small number of devices. The software will eliminate this issue by changing ERI criteria.

The battery issues described above and subsequent software update are summarized in the table below. When a device receives the software update, if battery impedance is greater than the new ERI threshold ERI will be triggered shortly thereafter. Therefore, clinicians may observe an ERI/EOL indicator at the next patient follow-up. When ERI is triggered by battery impedance, additional battery capacity remains and can support device function at ERI parameters for at least one year. Medtronic is not aware of any reports of loss of therapy due to this issue.

As a reminder, when ERI is triggered, EnRhythm devices revert to VVI pacing at 65 ppm at the programmed output settings. EOL is declared 90 days after ERI or at a battery voltage of 2.69 V, whichever comes sooner.

Battery Issue	Software Update
Battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion	Changed ERI battery voltage threshold from 2.59 V to 2.81 V to ensure 90 days of therapy from ERI to EOL
Higher than expected battery impedance	Added a secondary ERI trigger based on battery impedance. This new criteria will identify devices with increased battery impedance before device performance is impacted. If triggered, displayed battery voltage is reset to 2.81 V to ensure alignment with ERI battery voltage threshold

Updated Performance Information (as of August 2011)

We now have access to battery impedance and ERI performance on more than 5,000 EnRhythm devices that have received the EnRhythm software update. Our modeling based on these data shows that approximately 6-10% of devices will reach ERI within 5 years post-implant. Consistent with our previous communications, we continue to expect average device longevity to be reduced by approximately 10-15%, with the expected average longevity remaining at 8.5 to 10.5 years, depending on device settings.1

Updated Patient Management Recommendations (as of August 2011)

After consultation with Medtronic's Independent Physician Quality Panel, we recommend:

Performing a device follow-up within 90 days after the software download to identify devices that triggered ERI shortly after the software update. Subsequent follow-up can be performed per standard practice. During programmer interrogation of a device at ERI, there is a slight possibility a transient drop in pacing amplitude could occur. If this is noted, either remove the programmer head or temporarily program to a higher output voltage.

If an unanticipated ERI/EOL is declared, it is likely due to battery impedance. In such cases, additional battery capacity remains and can support device function at ERI parameters for at least one year. However, when ERI or EOL (typically 90 days after ERI) declaration is seen, schedule device replacement.



EnRhythm Pacemakers

Original Date of Advisory: February 2010

continued

Status Update

As of August 18, 2011, 334 devices out of approximately 142,000 devices worldwide have been confirmed as having exhibited an advisory related event. Approximately 106,000 remain implanted.

 1 The 8.5 year estimate represents a high use scenario (DDD, 100% pacing in atrium and ventricle with 3.0 V output in both chambers). The 10.5 year estimate represents a typical use scenario for a sinus node dysfunction patient with the MVP function ON (AAI(R) \ll DDD(R), 50% pacing in atrium and 5% pacing in ventricle with 3.0 V output in both chambers). Projections are based on modeling and not actual field returns, due to limited availability of implant experience beyond 6 years. Field performance will continue to be monitored and modeling updated to reflect actual data.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	`	The software update eliminates any potential future risk of the two battery issues described above by changing the ERI criteria.
All EnRhythm pacemakers (142,000 Worldwide).	334 Worldwide	106,000 Worldwide	0.24%	



Concerto CRT-D and Virtuoso ICD

Original Date of Advisory: September 2009

Potential Reduced Device Longevity

Product

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity. Go to www.medtronic. <u>com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity due to gradually increasing current drain caused by low voltage capacitor degradation. This issue may present in the affected devices as reaching the Recommended Replacement Time (RRT) earlier than projected. This issue does not compromise device functionality or affect therapy delivery.

Based on information from returned devices, Medtronic expects that affected devices will continue to provide at least 3 months of normal device function between RRT and End of Service (EOS) as described in device labeling.

A total of 8,900 devices worldwide are affected by this advisory. An estimated 6,300 of these devices were active at the time of the original advisory communication.

Concerto and Virtuoso devices in the affected subset were manufactured primarily in 2006 and can be traced to a specific subset of low voltage capacitors.

Patient Management Recommendations

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients with devices in the affected subset:

Physicians should continue routine follow-up sessions at least every 3 months in accordance with product labeling.

Physicians should verify that the Low Battery Voltage RRT alert is programmed to "On-High." This provides an audible, alternating tone when the device reaches RRT. These devices are shipped with this alert programmed nominally to "On-High."

Physicians may consider monitoring patients through CareLink. The CareLink home monitor can be used to automatically notify the clinician when the device reaches RRT.

Status Update

As of August 18, 2011, 3,601 devices out of approximately 8,900 devices in this subset worldwide have been confirmed as having exhibited this capacitor degradation. Out of the initial advisory population of 8,900 worldwide, approximately 1,000 remain implanted. Approximately 800 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
8,900 Implanted Worldwide (7,000 United States)	3,601 Worldwide (3,097 United States)	1,000 Worldwide (800 United States)	40% Worldwide (44% United States)

Advisories continued

Kappa 600/700/900 Pacemakers Sigma 100/200/300 Pacemakers

Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires (2009)

Product

A specific subset of Kappa and Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory Population

Specific subsets of Kappa and Sigma series pacemakers may fail at a higher than expected rate due to separation of wires that connect the electronic circuit to other pacemaker components (e.g., battery, connector). This may present clinically as loss of rate response, premature battery depletion, loss of telemetry, or no output.

Some patients, whose devices experience a wire separation resulting in a loss of pacing output, will experience a return of bradycardia symptoms (e.g., fainting or lightheadedness). In rare cases involving pacemaker dependent patients, loss of pacing output may result in death or serious injury.

Since 1997, there have been over 1.7 million Kappa and Sigma devices implanted worldwide. At the time of the original advisory communication, an estimated 15,200 Kappa and 6,100 Sigma devices affected by the advisory remained implanted and active. These devices were manufactured primarily between November 2000 and November 2002. Most of these devices have been implanted in patients for five years or longer and may be nearing normal elective replacement time.

There is no provocative testing that can predict which specific devices may fail, and no device programming can mitigate this issue if it occurs.

Patient Management Recommendations

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Advisory Population

Patient management recommendations remain unchanged. As of August 18, 2011, Medtronic has observed $456\ \mathrm{Kappa}$ devices and $269\ \mathrm{Sigma}$ devices with this failure mechanism from the Kappa and new Sigma device subsets. This represents 0.78% (Kappa) and 1.81% (Sigma) of the original affected implant population.

Four hundred nineteen (419) of the Kappa devices (0.72%) and 206 of the Sigma devices (1.38%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 37 Kappa devices (0.06%) and 63 Sigma devices (0.42%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

As of May 2009, our modeling predicts failure rates due to this issue of 1.1% (Kappa) and 4.8% (Sigma) over the remaining lifetime of those pacemakers still in service at that time.

Out of the initial advisory population of 58,300 Kappa devices and 14,900 Sigma devices worldwide, approximately 4,100 Kappa devices and 3,000 Sigma devices remain implanted. Of these, approximately 1,200 Kappa and 800 Sigma devices are in the United States.

Continued Vigilance

Included in the advisory communication was information about an additional subset of Kappa devices where we have observed a much lower rate of occurrence of this issue. Approximately 44,000 devices of this subset remain active. We have observed a failure rate of approximately 0.082% in this subset and our May 2009 modeling predicts a failure rate of 0.12% over the remaining device life of those pacemakers still in service at that time. After review with our Independent Physician Quality Panel, we do not recommend any specific actions for this group of devices. We will continue to monitor performance and inform you if any specific patient management recommendations are warranted.

continued



Kappa 600/700/900 Pacemakers

Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires, continued

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
Kappa Pacemakers				
58,300 Implanted Worldwide (est.) (17,600 United States)	419 Worldwide (221 United States) with information indicating a clinical presentation. An additional 37 worldwide (25 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	4,100 Worldwide (1,200 United States)	0.78% Worldwide 1.40% (United States)	1.1%
Sigma Pacemakers				
14,900 Implanted Worldwide (est.) (3,700 United States)	206 Worldwide (43 United States) with information indicating a clinical presentation. An additional 63 worldwide (15 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	3,000 Worldwide (800 United States)	1.81% Worldwide 1.57% (United States)	4.8%



6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Model 6930, 6931, 6948, and 6949 implantable defibrillation leads

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for approximately 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

Patient Management Recommendations (Updated April 2011)

The Lead Integrity Alert (LIA) provides three days advance notice prior to inappropriate therapy to 76% of patients with lead fractures. As a result, we strongly recommend that all Sprint Fidelis patients who have the ability to upgrade to Lead Integrity Alert do so promptly. Also ensure that high voltage lead impedance alerts (maximum of 100 ohms) are programmed. When a lead fracture is suspected or confirmed, immediate patient attention is strongly recommended. Physicians should inform their patients to seek medical attention without delay if they experience unexpected shocks

- If a Fidelis lead fracture of any type has occurred, we recommend implanting a new high voltage lead with or without extraction of the Fidelis lead.
- In patients with normal device function and no manifestation
 of lead fracture, no action is recommended. The risk of
 prophylactic intervention appears to be greater than serious
 injury resulting from lead fracture even for pacemaker
 dependent patients, except in select individual patient
 circumstances as determined by the physician.
- In the event of a device change-out or upgrade procedure, with no manifestation of lead fracture, consider the patient age and lead model data above, as well as patient life expectancy, co-morbidities, ease of extraction related to implant time, patient preference, etc., for the following options:
 - Leave a properly performing lead intact.
 - Implant a new ICD lead without extraction of the existing lead.

- Carefully consider all factors before prophylactic placement of a pace-sense lead. Data shows an increased risk of high voltage conductor fracture if a pace-sense conductor fracture has previously occurred. This data is available at www.medtronic.com/fidelis
- Individual patient circumstances may warrant extracting and implanting a new ICD lead. If warranted, Medtronic's Independent Physician Quality Panel recommends the lead extraction procedure be performed by a physician with extensive lead extraction experience.²

Status Update

As of August 1, 2011, of the initial implant population of 205,600 in the United States, approximately 108,000 remain implanted. According to System Longevity Study results, lead survival is estimated to be 90.6% (+2.6/-3.6) at 66 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

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continued



6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture, continued

Keeping Physicians Informed

The most recent Sprint Fidelis lead performance information, including survival curves, physician letters, and subpopulation data, can be found at www.medtronic.com/fidelis and will be updated semi-annually. Medtronic's website also has a selected list of peerreviewed publications related to Fidelis lead performance and extraction. Medtronic is committed to answering your questions and keeping you informed. If you have any questions or concerns, please contact your Medtronic Representative or Medtronic Technical Services at 1 (800) 723-4636 (US).

205,600 (United States)	4,868 (United States)	108,000 (United States)	
Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Additional information about the Sprint Fidelis lead is available at: www.medtronic.com/fidelis.



Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires (2005)

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

No provocative testing can predict which devices may fail.

Patient Management Recommendations

Recommendation for the management of patients who have pacemakers affected by this advisory were changed in May 2009. Current recommendations are:

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients in the 2005 Sigma advisory:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Patient management recommendations remain unchanged. As of August 18, 2011, 694 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation.

Three hundred forty-one (341) of the Sigma devices (0.85%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 353 Sigma devices (0.88%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Our original modeling predicted a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. However, as of May 2009 updated updated modeling now predicts a failure rate of 3.9% over the remaining device life of those devices still in service at that time.

Out of the initial advisory population of 40,000 worldwide, approximately 9,000 remain implanted. Approximately 2,100 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still in Service as of May 2009
40,000 Implanted Worldwide (est.) (9,900 United States)	341 Worldwide (69 United States) with information indicating a clinical presentation.An additional 353 Worldwide (63 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	9,000 Worldwide (2,100 United States)	1.73% Worldwide 1.30% (United States)	3.9%



7274 Marquis DR 7230 Marquis VR 7278 Maximo DR 7232 Maximo VR

7277 InSync Marguis 7289 InSync II Marquis

7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

 Conduct quarterly (i.e., every 3 months) follow-up procedures

- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.
- Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of August 18, 2011, 191 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. One hundred fifteen (115) of these devices were returned from the United States.

Out of the initial advisory population of 87,000 worldwide, approximately 9,500 remain implanted. Approximately 8,300 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
87,000 Implanted Worldwide (76,000 United States)	191 Worldwide (115 United States)	9,500 Worldwide (8,300 United States)	0.22% Worldwide (0.15% United States)	Consistent with Medtronic projections, the observed rate of shorting may increase to between 0.2% and 1.5% over the second half of device life.



Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 dual chamber (D, DR, and VDD) implantable pulse generators has been identified by serial numbers. Hospitals and Physicians were notified. Go to www.medtronic.com/ <u>CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 dual chamber (D, DR, and VDD) series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free of charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status Update

Patient management recommendations remain unchanged. As of August 18, 2011, 337 out of approximately 180,000 distributed (0.18% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred seventy (170) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, less than 500 remain implanted.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
180,000 Active Worldwide at time of advisory (121,000 United States)	337 Worldwide (170 United States)	< 500 Worldwide (< 500 United States)	0.19% Worldwide (0.14% United States)	0.03%



Minix and Minix ST IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix and Minix ST families of implantable pulse generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status Update

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 3,000 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Initial Affected Population	Estimated Remaining Active Population	To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head
All Minix and Minix ST implantable pulse generators	3,000	away from the pulse generator.

Dual Chamber Pacemakers with Measurement Lock-up ERI Kappa 600, 700, 800, 900, EnPulse, Adapta, Versa, Sensia, Relia, and Vitatron Models E50A1, E60A1, and G70A1

Purpose of this Information

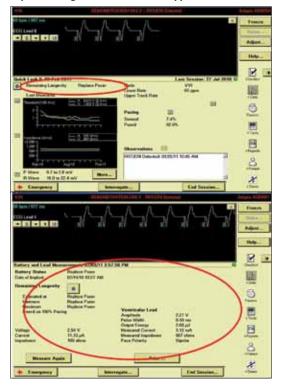
This Performance Note describes a rare measurement lock-up issue that impacts the Medtronic Dual Chamber pacemakers listed above. If this measurement lock-up occurs, the device will trigger a false Elective Replacement Indicator (ERI). A reset is available to clear this condition and there is no need to explant the device. This issue does not impact battery longevity.

Background

If this rare measurement lock-up occurs in the pacemaker, it causes the device to read a value of zero for battery voltage. After four measurements of zero, the device will trigger ERI and revert to a VVI pacing mode at 65 bpm. There is no loss of ventricular pacing and the output voltage will remain the

The issue can be uniquely identified using the programmer or via CareLink transmission; the battery voltage measurements and remaining longevity will appear as blank values. Medtronic has developed a method for clearing the ERI condition through the use of a specially configured programmer. There is no impact to the device functionality or longevity after this reset is complete.

Example 1 - Programmer Screen for Typical Pacemaker at ERI



Example

Two examples of images from the Medtronic 2090 Programmer are shown below. Example 1 shows what a normal ERI condition looks like. Example 2 shows what will be displayed if the ERI is triggered due to the measurement lock-up condition.

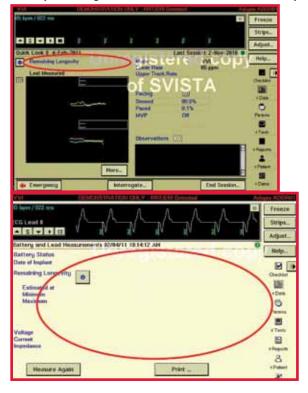
A device that has experienced a measurement lock-up ERI will present ALL of the following symptoms:

- Device declaring ERI/RRT
- Remaining Longevity = <Blank> on the programmer (and CareLink where available)
- Battery Voltage = <Blank> on the programmer (and CareLink where available)
- If the user attempts to take a Battery and Lead Measurement, a pop-up window will indicate that it cannot estimate remaining battery life.

Recommendation

This condition can be reset and does not require device explant. If this measurement lock-up occurs, obtain a saveto-disk file and contact Medtronic Brady Technical Services at 1 (800) 505-4636 for assistance. Reset devices are no more likely to experience a recurrence of this issue.

Example 2 - Programmer Screen for Measurement Lock-up ERI



Helix Retraction of the Sprint Quattro Secure S 6935 and **Sprint Quattro Secure 6947**

Purpose of this Information

This performance note is intended to provide guidance regarding retraction of the helix of Sprint Quattro Model 6935 or 6947 leads.

Background

In certain cases, over-retraction of the helix, during initial implant or subsequent repositioning, may result in the inability to extend the helix. This does not impact acute or chronic performance of successfully implanted leads.

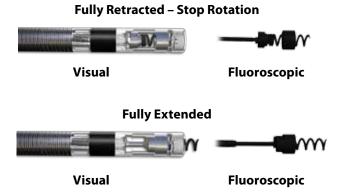
The root cause is over-retraction of the helix mechanism beyond the retraction stop, resulting in the inability to extend the helix in a subsequent attempt.

Recommendations

Consistent with the Technical Manual, the following steps can be used to mitigate this issue.

- Fluoroscopy should be used to confirm when the helix is fully retracted.
- Rotation of fixation tool should be stopped once full helix retraction is visually verified.
- If helix is unable to extend, replace with a new lead and report the issue to Medtronic.

Retraction Stop



Potential Malfunction of CRT, ICD, and IPG Products due to Anomalies in MOSFET Integrated Circuit Technology

Medtronic has detected a specific pattern of MOSFET IC malfunctions in its Concerto, Virtuoso and EnRhythm family of devices. As of July 2009, Medtronic has confirmed twenty-eight (28) malfunctions related to this pattern out of 115,000 EnRhythm and 233,000 Concerto/Virtuoso products distributed worldwide. Reliability analysis of this pattern shows the probability of occurrence decreases with time and over 90% of the malfunctions related to the pattern had occurred within the first twelve months after implant. With process improvements in place, Medtronic expects few additional malfunctions related to this pattern.

The pattern involves metal-oxide-semiconductor field-effect transistors (MOSFET). A MOSFET is an electronic circuit used to amplify or switch electronic signals. MOSFETs have been used in the electronics industries for decades and MOSFET technology is the most widely used type of integrated circuit. Medtronic uses this technology in the circuitry of its CRT, ICD, and IPG products. Each product contains thousands of MOSFETs in its electronic circuitry.

Each MOSFET depends on a layer of insulating material to electrically isolate its components. The integrity of this insulating layer is important to the operation of the MOSFET. Variation in the thickness of the insulating layer can cause the MOSFET to operate in an undesirable manner. Process variations for electronic circuits can affect the integrity of the insulating material, and can lead to MOSFET malfunction. Medtronic's quality system strives to control process variation and detect undesired anomalies that are characteristic of all MOSFET manufacturing. In addition, Medtronic's post-market vigilance activities monitor malfunctions and may implement screening and testing improvements when a pattern of related malfunctions is identified.

The pattern with the Concerto, Virtuoso and EnRhythm models has presented clinically as high lead impedance, sensing difficulty, loss of pacing therapy and/or early battery depletion due to higher than normal battery drain. The degree of battery drain varies case by case, such that the time from the onset to battery depletion has ranged from several days to several months. If not detected by normal patient follow-up procedures, the use of patient alerts or CareLink remote monitoring, the battery will fully deplete, leaving the patient without therapy.

As of March 2009, Medtronic has implemented additional electrical screening and stress tests to address this specific pattern for products being sold.

Since these rates of malfunction are low and the probability of occurrence decreases with time, Medtronic recommends physicians continue following patients in accordance with standard practice.

Clinical Management of VCM near Elective Replacement

Background

Medtronic Technical Services has received reports of devices going to ERI or end of life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately. When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage ≤ 2.15 V).

Please note that the following parameter changes occur when the device goes to ERI:

Table: IPG Therapy Parameter Changes at ERI

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-Up Considerations" may also be used on these devices.

Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
 - Program the ventricular channel to 5 V, 1 ms
 - Navigate to Data/Battery and Lead Measurements
 - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
 - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
 - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

¹ Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- The amount of electrical energy expended in providing therapy to the patient
- The amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- The energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

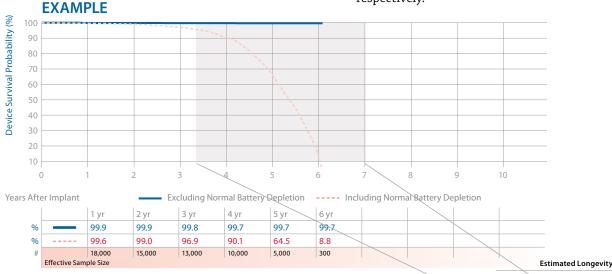
Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



This figure shows the range of the estimated longevity values given in the reference chart in relation to the survival curve. The range of longevity is representative of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at approximately the mid-point of the range of longevity values.

Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation

Purpose of this Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients.1 Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.²⁻⁴ Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.5 Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats.⁶ In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

Clinical Trial Observations

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate, and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)⁷⁻⁹ or VVI 40 pacing modes, ¹⁰ the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1,000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1,000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/ VF across pacing modes.¹¹

Pacemaker Patients

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization. 12,13 MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block.9 However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate.

DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing, $^{13,14}\,\mathrm{may}$ lead to endless loop tachycardia, $^{14,15}\,$ and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pauses. Therefore, careful consideration should be given to pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications that prolong QT.

Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony versus ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

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AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below end of life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform transtelephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level

occurs. The measured battery voltage will also appear on the programmer display and on printouts.

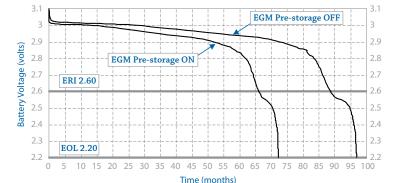
Battery depletion curves are shown in Figure 1, with special focus on device longevity when programming EGM prestorage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately
 9 days for each month pre-storage is ON
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/replacement occurs prior to end of life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary.



AT500 Battery Depletion Curve

Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial – 2 V, 0.4 ms, 600 ohms, Ventricle – 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least one lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards, the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the performance note, "Clinical Management of High Voltage Lead System Oversensing."

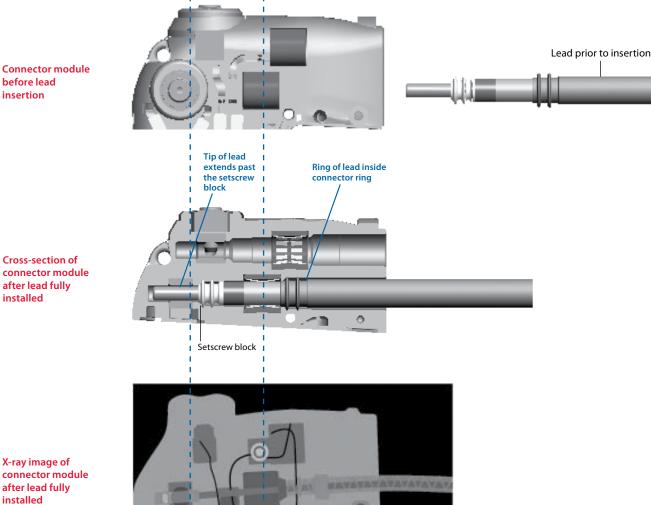
Performing the following steps can be used for each lead connection during the implant procedure:

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- 3 Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- **5** Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.



X-ray image of after lead fully

GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactured and utilized a unique lithium/silver vanadium oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching middle of life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

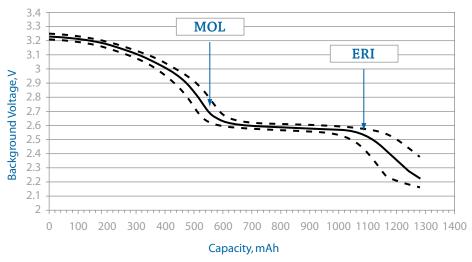
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

GEM II/III Battery Discharge Curve



General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the nonsustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture
- Elicit and investigate any patient complaints/symptoms that may be suggestive of potential lead failure

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed helow.

Factors that should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads. 1-3 Ultimately, the decision to replace an implanted lead involves medical judgment.
- ¹ Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. PACE. June 2002;25(6):879-882.
- ² Ellenbogen KA, Wood MA, Shepard RK, et al. Detection and management of an implantable cardioverter defibrillator lead failure: incidence and clinical implications. J Am Coll Cardiol. January 1, 2003;41(1):73-80.
- ³ Hauser RG, Kallinen LM, Almquist AK, Gornick CC, Katsiyiannis WT. Early failure of a small-diameter high-voltage implantable cardioverter-defibrillator lead. Heart Rhythm. July 2007;4(7):892-896.

Clinical Management of High-Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T and far-field P waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high-voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding

it. Thus, an ICD system that is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/farfield sensing, electromagnetic interference, T wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far-field sensing	Diaphragmatic muscle potentials in breathing, wide tip-to-ring (coil on integrated bipolar leads) spacing	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks	Check R waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-to-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave sensing	Drugs, ischemic tissue, exercise, Long QT syndrome, electrolyte imbalance	Sense markers seen on EGM related to T wave. False positive detection.	Check for R wave deterioration and characteristics. If R wave > 3.0 mV, reprogram sensitivity. If R wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header	This is an acute phenomenon seen within 6 months of implant (usually sooner)	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete conductor fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit	Characterized by chaotic oversensing related to motion of the fracture site	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead insulation breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement Perforation Electrolyte Imbalance Improper IPG/Lead Connection	Increase or Decrease Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase, Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	Increase Increase Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P and/or R Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P and/or R Waves	Dislodgement	Decrease Decrease .Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset, Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/ Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory

Phone: 1 (800) 328-2518, ext. 44800 Email: crdm.returnedproduct@medtronic.com



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